# RENESAS

# RL78/G12

RENESAS MCU

True Low Power Platform (as low as 63 µA/MHz), 1.8V to 5.5V operation, 2 to 16 Kbyte Flash, 31 DMIPS at 24MHz, for General Purpose Applications

# 1. OUTLINE

#### <R> 1.1 Features

#### Ultra-Low Power Technology

- 1.8 V to 5.5 V operation from a single supply
- Stop (RAM retained): 0.23 μA, (LVD enabled): 0.31 μA
- Snooze: 0.7 mA (UART), 1.20 mA (ADC)
- Operating: 63 µA /MHz

#### 16-bit RL78 CPU Core

- Delivers 31 DMIPS at maximum operating frequency of 24 MHz
- Instruction Execution: 86 % of instructions can be executed in 1 to 2 clock cycles
- CISC Architecture (Harvard) with 3-stage pipeline
- Multiply Signed & Unsigned: 16 x 16 to 32-bit result in 1 clock cycle
- MAC: 16 x 16 to 32-bit result in 2 clock cycles
- 16-bit barrel shifter for shift & rotate in 1 clock cycle
- 1-wire on-chip debug function

#### Main Flash Memory

- Density: 2 KB to 16 KB
- Block size: 1 KB
- On-chip single voltage flash memory with protection from block erase/writing

#### **Data Flash Memory**

- Data Flash with background operation
- Data flash size: 2 KB size options
- Erase Cycles: 1 Million (typ.)
- Erase/programming voltage: 1.8 V to 5.5 V

#### RAM

- 256 B to 1.5 KB size options
- Supports operands or instructions
- Back-up retention in all modes

#### **High-speed Oscillator Oscillator**

- 24MHz with +/- 1% accuracy over voltage (1.8 V to 5.5 V) and temperature (-20 °C to 85 °C)
- Pre-configured settings: 24 MHz, 16 MHz, 12 MHz, 8 MHz, 6 MHz, 4 MHz, 3 MHz, 2 MHz, and 1 MHz

#### Reset and Supply Management

- Power-on reset (POR) monitor/generator
- Low voltage detection (LVD) with 12 setting options (Interrupt and/or reset function)

#### Data Memory Access (DMA) Controller

- Up to 2 fully programmable channels
- Transfer unit: 8- or 16-bit

#### **Multiple Communication Interfaces**

- Up to 3 x  $I^2C$  master
- Up to 1 x I<sup>2</sup>C multi-master
- Up to 3 x CSI/SPI (7-, 8-bit)
- Up to 3 x UART (7-, 8-, 9-bit)

#### **Extended-Function Timers**

- Multi-function 16-bit timers: Up to 8 channels
- Interval Timer: 12-bit, 1 channel
- 15 kHz watchdog timer : 1 channel (window function)

#### **Rich Analog**

- ADC: Up to 11 channels, 10-bit resolution, 2.1 µs conversion time
- Supports 1.8 V to 5.5 V
- Internal voltage reference (1.45 V)
- On-chip temperature sensor

#### Safety Features (IEC or UL 60730 compliance)

- Flash memory CRC calculation
- RAM parity error check
- RAM write protection
- SFR write protection
- · Illegal memory access detection
- Clock stop/ frequency detection
- ADC self-test

#### **General Purpose I/O**

- 5 V tolerant, high-current (up to 20 mA per pin)
- Open-Drain, Internal Pull-up support

#### **Operating Ambient Temperature**

- Standard: -40 °C to +85 °C
- Extended: -40 °C to +105 °C

#### Package Type and Pin Count

- QFN: 24
- SSOP: 20, 30

#### \* There is difference in specifications between every product. Please refer to specification for details.

# Datasheet

R01DS0193EJ0200 Rev.2.00 Sep 06, 2013

Code flash	Data flash	RAM	20 pins	24 pins	30 pins
16 KB	2 KB	2 KB	_	—	R5F102AA
	_		_	—	R5F103AA
	2 KB	1.5 KB	R5F1026A Note 1	R5F1027A <sup>Note 1</sup>	—
	_		R5F1036A Note 1	R5F1037A Note 1	_
12 KB	2KB	1 KB	R5F10269 Note 1	R5F10279 Note 1	R5F102A9
	_		R5F10369 Note 1	R5F10379 Note 1	R5F103A9
8 KB	2 KB	768 B	R5F10268 Note 1	R5F10278 Note 1	R5F102A8
	_		R5F10368 Note 1	R5F10378 Note 1	R5F103A8
4 KB	2KB	512 B	R5F10267	R5F10277	R5F102A7
	_		R5F10367	R5F10377	R5F103A7
2 KB	2 KB	256 B	R5F10266 Note 2		
	_		R5F10366 Note 2		

O ROM, RAM capacities

Notes 1. This is 640 bytes when the self-programming function or data flash function is used. (For details, see CHAPTER 3 CPU ARCHITECTURE in the RL78/G12 User's Manual Hardware.)

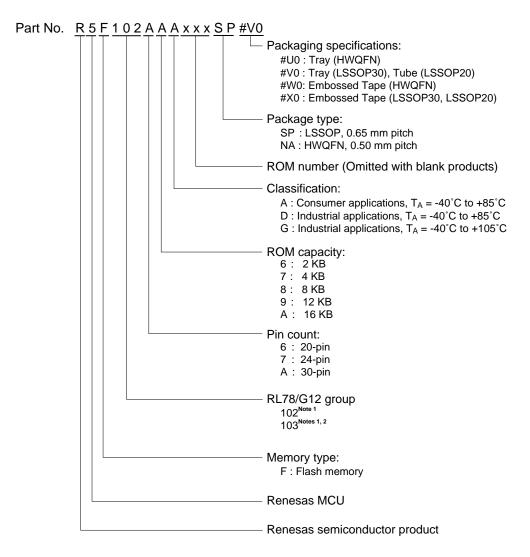
**2.** The self-programming function cannot be used for R5F10266 and R5F10366.

Caution When the flash memory is rewritten via a user program, the code flash area and RAM area are used because each library is used. When using the library, refer to RL78 Family Flash Self Programming Library Type01 User's Manual and RL78 Family Data Flash Library Type04 User's Manual.



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# 1.2 List of Part Numbers



#### Figure 1-1. Part Number, Memory Size, and Package of RL78/G12

- Notes 1. For details about the differences between the R5F102 products and the R5F103 products of RL78/G12, see 1.3 Differences between the R5F102 Products and the R5F103 Products.
  - 2. Products only for "A: Consumer applications (T<sub>A</sub> = -40 to +85°C)" and "D: Industrial applications (T<sub>A</sub> = -40 to +85°C)"



Table 1-1.	List of	Ordering	Part	Numbers
------------	---------	----------	------	---------

· ·	in Package unt	Data flash	Fields of Application	Part Number			
20 pin	20-pin plastic LSSOP (4.4 × 6.5 mm, 0.65 mm pitch)	Mounted	A	R5F1026AASP#V0, R5F10269ASP#V0, R5F10268ASP#V0, R5F10267ASP#V0, R5F10266ASP#V0 R5F1026AASP#X0, R5F10269ASP#X0, R5F10268ASP#X0, R5F10267ASP#X0, R5F10266ASP#X0			
			D	R5F1026ADSP#V0, R5F10269DSP#V0, R5F10268DSP#V0, R5F10267DSP#V0, R5F10266DSP#V0 R5F1026ADSP#X0, R5F10269DSP#X0, R5F10268DSP#X0, R5F10267DSP#X0, R5F10266DSP#X0			
			G	R5F1026AGSP#V0, R5F10269GSP#V0, R5F10268GSP#V0, R5F10267GSP#V0, R5F10266GSP#V0 R5F1026AGSP#X0, R5F10269GSP#X0, R5F10268GSP#X0, R5F10267GSP#X0, R5F10266GSP#X0			
		Not mounted	A	R5F1036AASP#V0, R5F10369ASP#V0, R5F10368ASP#V0, R5F10367ASP#V0, R5F10366ASP#V0 R5F1036AASP#X0, R5F10369ASP#X0, R5F10368ASP#X0, R5F10367ASP#X0, R5F10366ASP#X0			
				D	R5F1036ADSP#V0, R5F10369DSP#V0, R5F10368DSP#V0, R5F10367DSP#V0, R5F10366DSP#V0 R5F1036ADSP#X0, R5F10369DSP#X0, R5F10368DSP#X0, R5F10367DSP#X0, R5F10366DSP#X0		
24 pin	$(4 \times 4 \text{ mm}, 0.5)$	Mounted	A	R5F1027AANA#U0, R5F10279ANA#U0, R5F10278ANA#U0, R5F10277ANA#U0 R5F1027AANA#W0, R5F10279ANA#W0, R5F10278ANA#W0, R5F10277ANA#W0			
	mm pitch)	n pitch)	h)			D	R5F1027ADNA#U0, R5F10279DNA#U0, R5F10278DNA#U0, R5F10277DNA#U0 R5F1027ADNA#W0, R5F10279DNA#W0, R5F10278DNA#W0, R5F10277DNA#W0
			G	R5F1027AGNA#U0, R5F10279GNA#U0, R5F10278GNA#U0, R5F10277GNA#U0 R5F1027AGNA#W0, R5F10279GNA#W0, R5F10278GNA#W0, R5F10277GNA#W0			
		Not mounted	А	R5F1037AANA#V0, R5F10379ANA#V0, R5F10378ANA#V0, R5F10377ANA#V0 R5F1037AANA#X0, R5F10379ANA#X0, R5F10378ANA#X0, R5F10377ANA#X0			
			D	R5F1037ADNA#V0, R5F10379DNA#V0, R5F10378DNA#V0, R5F10377DNA#V0 R5F1037ADNA#X0, R5F10379DNA#X0, R5F10378DNA#X0, R5F10377DNA#X0			
30 pin		Mounted	A	R5F102AAASP#V0, R5F102A9ASP#V0, R5F102A8ASP#V0, R5F102A7ASP#V0 R5F102AAASP#X0, R5F102A9ASP#X0, R5F102A8ASP#X0, R5F102A7ASP#X0			
	(7.62 mm (300), 0.65 mm pitch )		D	R5F102AADSP#V0, R5F102A9DSP#V0, R5F102A8DSP#V0, R5F102A7DSP#V0 R5F102AADSP#X0, R5F102A9DSP#X0, R5F102A8DSP#X0, R5F102A7DSP#X0			
			G	R5F102AAGSP#V0, R5F102A9GSP#V0, R5F102A8GSP#V0, R5F102A7GSP#V0 R5F102AAGSP#X0, R5F102A9GSP#X0, R5F102A8GSP#X0, R5F102A7GSP#X0			
		Not mounted	A	R5F103AAASP#V0, R5F103A9ASP#V0, R5F103A8ASP#V0, R5F103A7ASP#V0 R5F103AAASP#X0, R5F103A9ASP#X0, R5F103A8ASP#X0, R5F103A7ASP#X0			
			D	R5F103AADSP#V0, R5F103A9DSP#V0, R5F103A8DSP#V0, R5F103A7DSP#V0 R5F103AADSP#X0, R5F103A9DSP#X0, R5F103A8DSP#X0, R5F103A7DSP#X0			

Note For fields of application, see Figure 1-1. Part Number, Memory Size, and Package of RL78/G12.

<R> Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.



# 1.3 Differences between the R5F102 Products and the R5F103 Products

The following are differences between the R5F102 products and the R5F103 products.

- O Whether the data flash memory is mounted or not
- O High-speed on-chip oscillator oscillation frequency accuracy
- O Number of channels in serial interface
- O Whether the DMA function is mounted or not
- O Whether a part of the safety functions are mounted or not

### 1.3.1 Data Flash

The data flash memory of 2 KB is mounted on the R5F102 products, but not on the R5F103 products.

Product	Data Flash
R5F102 products	2КВ
R5F1026A, R5F1027A, R5F102AA,	
R5F10269, R5F10279, R5F102A9,	
R5F10268, R5F10278, R5F102A8,	
R5F10267, R5F10277, R5F102A7,	
R5F10266 Note	
R5F103 products	Not mounted
R5F1036A, R5F1037A, R5F103AA,	
R5F10369, R5F10379, R5F103A9,	
R5F10368, R5F10378 R5F103A8,	
R5F10367, R5F10377, R5F103A7,	
R5F10366	

- **Note** The RAM in the R5F10266 has capacity as small as 256 bytes. Depending on the customer's program specification, the stack area to execute the data flash library may not be kept and data may not be written to or erased from the data flash memory.
- Caution When the flash memory is rewritten via a user program, the code flash area and RAM area are used because each library is used. When using the library, refer to RL78 Family Flash Self Programming Library Type01 User's Manual and RL78 Family Data Flash Library Type04 User's Manual.



# 1.3.2 On-chip oscillator characteristics

(1) High-speed on-chip oscillator oscillation frequency of the R5F102 products

Oscillator	Condition	MIN	MAX	Unit
High-speed on-chip	T <sub>A</sub> = -20 to +85 °C	-1.0	+1.0	%
oscillator oscillation	T <sub>A</sub> = -40 to -20 °C	-1.5	+1.5	
frequency accuracy	T <sub>A</sub> = +85 to +105 °C	-2.0	+2.0	

(2) High-speed on-chip oscillator oscillation frequency of the R5F103 products

Oscillator	Condition	MIN	MAX	Unit
High-speed on-chip	T <sub>A</sub> = -40 to + 85 °C	-5.0	+5.0	%
oscillator oscillation				
frequency accuracy				

## 1.3.3 Peripheral Functions

The following are differences in peripheral functions between the R5F102 products and the R5F103 products.

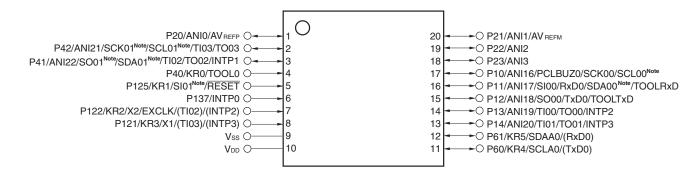
	R5F102	product	R5F103 product		
RL78/G12		20, 24 pin product	30 pin product	20, 24 pin product	30 pin product
Serial interface	UART	1 channel	3 channels	1 channel	
	CSI	2 channels	3 channels	1 channel	
Simplified I <sup>2</sup> C		2 channels	3 channels	None	
DMA function		2 channels		None	
Safety function	CRC operation	Yes		None	
	RAM guard	Yes		None	
	SFR guard	Yes		None	



# 1.4 Pin Configuration (Top View)

### 1.4.1 20-pin products

<R> • 20-pin plastic LSSOP (4.4 × 6.5 mm, 0.65 mm pitch)



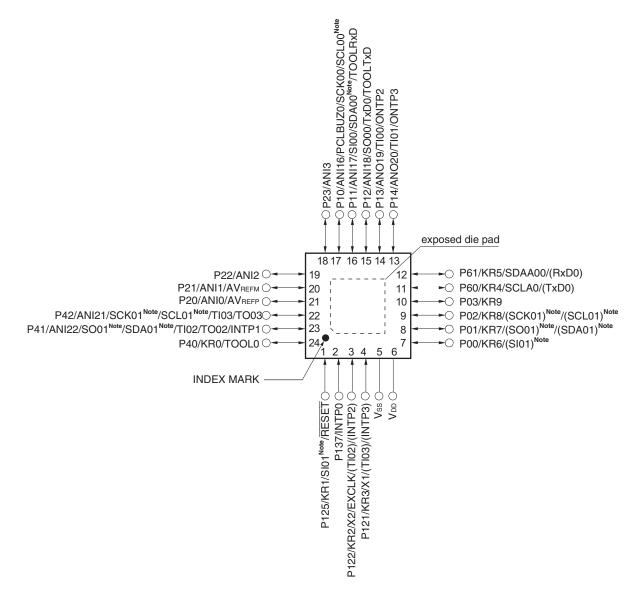
Note Provided only in the R5F102 products.

- Remarks 1. For pin identification, see 1.5 Pin Identification.
  - 2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G12 User's Manual Hardware.



# 1.4.2 24-pin products

<R> • 24-pin plastic HWQFN (4 × 4 mm, 0.5 mm pitch)



Note Provided only in the R5F102 products.

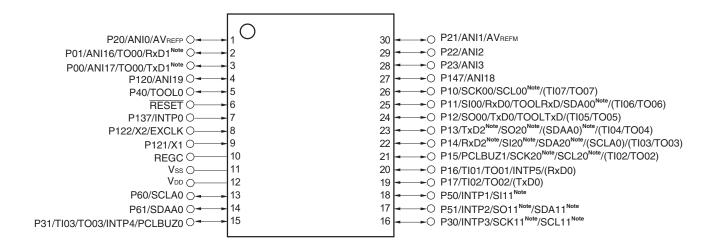
- Remarks 1. For pin identification, see 1.5 Pin Identification.
  - Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G12 User's Manual Hardware.
  - 3. It is recommended to connect an exposed die pad to Vss.

<R>



# 1.4.3 30-pin products

<R> • 30-pin plastic LSSOP (7.62 mm (300), 0.65 mm pitch)



Note Provided only in the R5F102 products.

#### Caution Connect the REGC pin to Vss via capacitor (0.47 to 1 $\mu$ F).

Remarks 1. For pin identification, see 1.5 Pin Identification.

 Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G12 User's Manual Hardware.



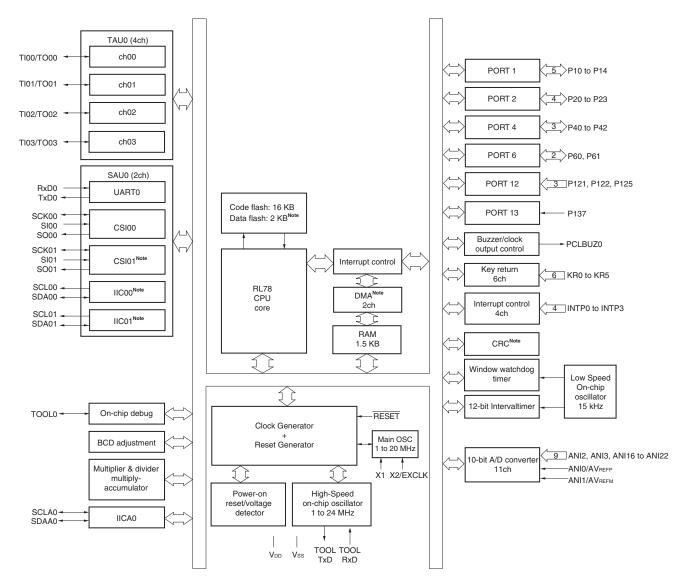
# 1.5 Pin Identification

ANI0 to ANI3,		REGC:	Regulator Capacitance
ANI16 to ANI22:	Analog input	RESET:	Reset
AVREFM:	Analog Reference Voltage Minus	RxD0 to RxD2:	Receive Data
AVREFP:	Analog reference voltage plus	SCK00, SCK01, SCK11,	
EXCLK:	External Clock Input	SCK20:	Serial Clock Input/Output
	(Main System Clock)	SCL00, SCL01,	
INTP0 to INTP5	Interrupt Request From Peripheral	SCL11, SCL20, SCLA0:	Serial Clock Input/Output
KR0 to KR9:	Key Return	SDA00, SDA01, SDA11,	
P00 to P03:	Port 0	SDA20, SDAA0:	Serial Data Input/Output
P10 to P17:	Port 1	SI00, SI01, SI11, SI20:	Serial Data Input
P20 to P23:	Port 2	SO00, SO01, SO11,	
P30 to P31:	Port 3	SO20:	Serial Data Output
P40 to P42:	Port 4	TI00 to TI07:	Timer Input
P50, P51:	Port 5	TO00 to TO07:	Timer Output
P60, P61:	Port 6	TOOL0:	Data Input/Output for Tool
P120 to P122, P125:	Port 12	TOOLRxD, TOOLTxD:	Data Input/Output for External
P137:	Port 13		Device
P147:	Port 14	TxD0 to TxD2:	Transmit Data
PCLBUZ0, PCLBUZ1:	Programmable Clock Output/	VDD:	Power supply
	Buzzer Output	Vss:	Ground
		X1, X2:	Crystal Oscillator (Main System
			Clock)



# 1.6 Block Diagram

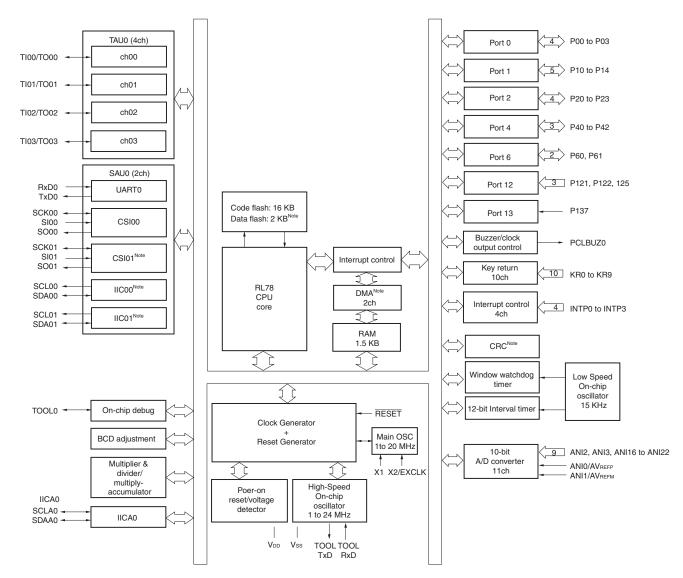
# 1.6.1 20-pin products



Note Provided only in the R5F102 products.



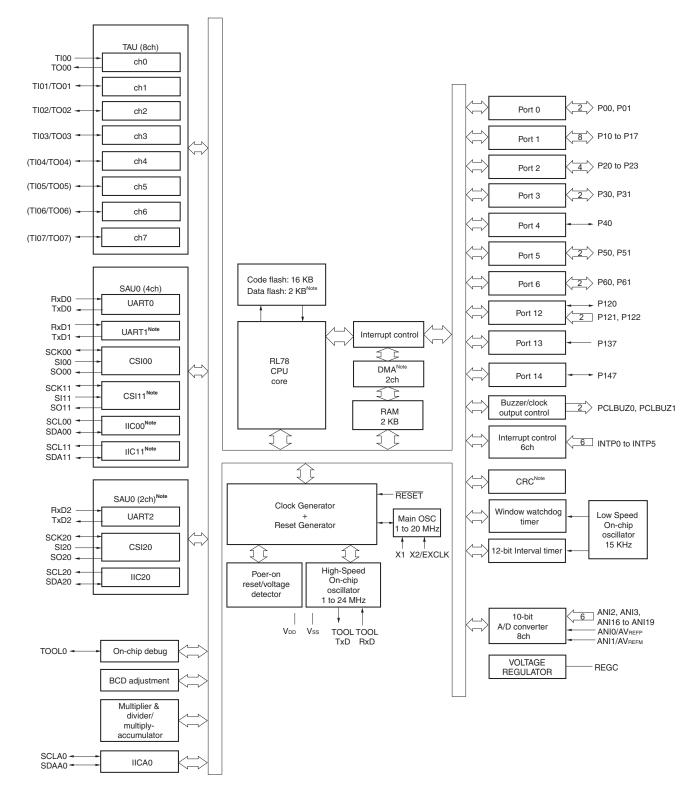
# 1.6.2 24-pin products



Note Provided only in the R5F102 products.



# 1.6.3 30-pin products



**Note** Provided only in the R5F102 products.

Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G12 User's Manual Hardware.



<R>

# 1.7 Outline of Functions

This outline describes the function at the time when Peripheral I/O redirection register (PIOR) is set to 00H.

		[		1			(1	
	Item	20-pin		24-pin		30-pin		
		R5F1026x	R5F1036x	R5F1027x	R5F1037x	R5F102Ax	R5F103Ax	
Code flas	h memory	2 to 16	KB Note 1		4 to 2	16 KB		
Data flasi	n memory	2 KB	-	2 KB	-	2 KB	-	
RAM		256 B to	o 1.5 KB	512 B to	o 1.5 KB	512 B	to 2KB	
Address	space			11	MB			
Main system	High-speed system clock			ation, external m /, 1 to 8 MHz: Vi	•	• • •		
clock	High-speed on-chip oscillator clock			to 24 MHz (V <sub>DD</sub> = to 8 MHz (V <sub>DD</sub> =		to 16 MHz (V <sub>DD</sub> =	2.4 to 5.5 V),	
Low-spee	ed on-chip oscillator clock 15 kHz (TYP)							
General-p	ourpose register	(8-bit register $\times$ 8) $\times$ 4 banks						
Minimum	instruction execution time	0.04167 $\mu$ s (High-speed on-chip oscillator clock: fi $\mu$ = 24 MHz operation)						
		0.05 $\mu$ s (High-speed system clock: f <sub>MX</sub> = 20 MHz operation)						
Instructio	n set	Data transfer (8/16 bits)						
		Adder and subtractor/logical operation (8/16 bits)						
		Multiplication (8 bits × 8 bits)						
	1	Rotate, barre	el shift, and bit n	nanipulation (set	, reset, test, and	Boolean operat	ion), etc.	
I/O port	Total	1	8	2	2	2	26	
	CMOS I/O	(N-ch C	2 ).D. I/O d voltage]: 4)	(N-ch C	6 D.D. I/O id voltage]: 5)	(N-ch 0	1 D.D. I/O id voltage]: 9)	
	CMOS input	2	1		4	;	3	
	N-ch open-drain I/O (6 V tolerance)	2						
Timer	16-bit timer	4 channels 8 channels					innels	
	Watchdog timer	1 channel						
	12-bit Interval timer			1 cha	annel			
	Timer output		4 cha (PWM outp	nnels outs: 3 <sup>Note 3</sup> )		8 cha (PWM output	nnels s: 7 <sup>Note 3</sup> ) <sup>Note 2</sup>	

**Notes 1.** The self-programming function cannot be used in the R5F10266 and R5F10366.

2. The maximum number of channels when PIOR0 is set to 1.

The number of PWM outputs varies depending on the setting of channels in use (the number of masters and slaves). (See 6.9.3 Operation as multiple PWM output function in the RL78/G12 User's Manual Hardware.)

Caution When the flash memory is rewritten via a user program, the code flash area and RAM area are used because each library is used. When using the library, refer to RL78 Family Flash Self Programming Library Type01 User's Manual and RL78 Family Data Flash Library Type04 User's Manual.



Item		20-	pin	24-	pin	30-	pin		
		R5F1026x	R5F1036x	R5F1027x	R5F1037x	R5F102Ax	R5F103Ax		
Clock output/buzzer ou	Itput	I		1		2	1		
·		2.44 kHz to 10	MHz: (Peripher	al hardware cloo	:k: fмаіn = 20 MH	z operation)			
8/10-bit resolution A/D	converter			annels		8 cha	nnels		
Serial interface		[R5F1026x (20	-pin), R5F1027;	x (24-pin)]					
				C: 2 channels/U	ART: 1 channel				
		[R5F102Ax (30	-pin)]						
				C: 1 channel/UAF	RT: 1 channel				
		CSI: 1 chann	el/Simplified I <sup>2</sup> C	C: 1 channel/UAF	RT: 1 channel				
		CSI: 1 chann	el/Simplified I <sup>2</sup> C	C: 1 channel/UAF	RT: 1 channel				
		[R5F1036x (20	-pin), R5F1037	x (24-pin)]					
		CSI: 1 chann	CSI: 1 channel/Simplified I <sup>2</sup> C: 0 channel/UART: 1 channel						
		[R5F103Ax (30-pin)]							
		CSI: 1 channel/Simplified I <sup>2</sup> C: 0 channel/UART: 1 channel							
	I <sup>2</sup> C bus			1 cha	annel				
Multiplier and divider/m	nultiply-	• 16 bits $\times$ 16 bits = 32 bits (unsigned or signed)							
accumulator		• 32 bits × 32 bits = 32 bits (unsigned)							
		• 16 bits × 16 b	oits + 32 bits = 3	2 bits (unsigned	or signed)				
DMA controller	1	2 channels	_	2 channels	_	2 channels	—		
Vectored interrupt	Internal	18	16	18	16	26	19		
sources	External		:	5		6	;		
Key interrupt		6	6	1	0	_	_		
Reset		Reset by RES							
		Internal reset							
		Internal reset							
			<ul> <li>Internal reset by voltage detector</li> <li>Internal reset by illegal instruction execution <sup>Note</sup></li> </ul>						
		Internal reset by RAM parity error							
		Internal reset by illegal-memory access							
Power-on-reset circuit		Power-on-res	Power-on-reset: 1.51 V (TYP)						
		Power-down-reset: 1.50 V (TYP)							
Voltage detector		Rising edge :	1.88 to 4.06 V	(12 stages)					
		Falling edge :	: 1.84 to 3.98 V	(12 stages)					
On-chip debug function	ı	Provided							
Power supply voltage		V <sub>DD</sub> = 1.8 to 5.5	5 V						
Operating ambient terr	perature	$T_A = -40$ to +85	5°C (A: Consum	er applications,	D: Industrial app	lications), T <sub>A</sub> = -	40 to +105°C		
		(G: Industrial a	pplications)						

**Note** The illegal instruction is generated when instruction code FFH is executed.

Reset by the illegal instruction execution not issued by emulation with the in-circuit emulator or on-chip debug emulator.



# 2. ELECTRICAL SPECIFICATIONS (A, D: $T_A = -40$ to +85°C)

This chapter describes the electrical specifications for the products "A: Consumer applications ( $T_A = -40$  to  $+85^{\circ}$ C)" and "D: Industrial applications ( $T_A = -40$  to  $+85^{\circ}$ C)".

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
  - 2. The pins mounted depend on the product. Refer to 2.1 Port Functions to 2.2.1 Functions for each product in the RL78/G12 User's Manual Hardware.



# 2.1 Absolute Maximum Ratings

# Absolute Maximum Ratings (T<sub>A</sub> = 25°C)

Parameter	Symbols		Conditions	Ratings	U
Supply Voltage	VDD			-0.5 to + 6.5	Ņ
REGC terminal input voltage <sup>Note1</sup>	VIREGC	REGC	REGC		Ň
Input Voltage	VII	Other than P60, F	261	Note 2 -0.3 to V <sub>DD</sub> + 0.3 <sup>Note 3</sup>	\ \
input voltage	VII VI2	P60, P61 (N-ch o		-0.3 to 6.5	
Output Voltage	Vo			$-0.3$ to V <sub>DD</sub> + $0.3^{Note 3}$	\
Analog input voltage	VAI	20-, 24-pin produ	cts: ANI0 to ANI3, ANI16 to ANI22	-0.3 to V <sub>DD</sub> + 0.3	١
		30-pin products: /	ANI0 to ANI3, ANI16 to ANI19	and -0.3 to AV <sub>REF(+)</sub> +0.3 <sup>Notes 3, 4</sup>	
Output current, high	Іон1	Per pin	Other than P20 to P23	-40	m
		Total of all pins	All the terminals other than P20 to P23	-170	m
			20-, 24-pin products: P40 to P42	-70	m
			30-pin products: P00, P01, P40, P120		
			20-, 24-pin products: P00 to P03 <sup>Note 5</sup> , P10 to P14 30-pin products: P10 to P17, P30, P31, P50, P51, P147	-100	m
	Іон2	Per pin	P20 to P23	-0.5	m
		Total of all pins		-2	m
Output current, low	IOL1	Per pin	Other than P20 to P23	40	m
		Total of all pins	All the terminals other than P20 to P23	170	m
			20-, 24-pin products: P40 to P42 30-pin products: P00, P01, P40, P120	70	m
			20-, 24-pin products: P00 to P03 <sup>Note 5</sup> , P10 to P14, P60, P61 30-pin products: P10 to P17, P30, P31, P50, P51, P60, P61, P147	100	rr
	IOL2	Per pin	P20 to P23	1	m
		Total of all pins		5	m
Operating ambient temperature	TA			-40 to +85	0
Storage temperature	Tstg			-65 to +150	0

Notes 1. 30-pin product only.

- **2.** Connect the REGC pin to Vss via a capacitor (0.47 to 1 μF). This value determines the absolute maximum rating of the REGC pin. Do not use it with voltage applied.
- **3.** Must be 6.5 V or lower.
- 4. Do not exceed AVREF (+) + 0.3 V in case of A/D conversion target pin.
- **5.** 24-pin products only.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
  - 2. AVREF (+): + side reference voltage of the A/D converter.
  - 3. Vss: Reference voltage



# 2.2 Oscillator Characteristics

2.2.1 X1 oscillator characteristics

<r></r>	Parameter Resonator		Conditions	MIN.	TYP.	MAX.	Unit	
	X1 clock oscillation Ceramic resonator /		$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	1.0		20.0	MHz	
frequency (fx) <sup>N</sup>	frequency (fx) <sup>Note</sup>	crystal oscillator	$1.8~V \leq V_{\text{DD}} < 2.7~V$	1.0		8.0		

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

<R> Note Indicates only permissible oscillator frequency ranges. Refer to AC Characteristics for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

- <R> Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.
  - Remark When using the X1 oscillator, refer to 5.4 System Clock Oscillator in the RL78/G12 User's Manual Hardware.

### 2.2.2 On-chip oscillator characteristics

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

<r></r>	Oscillators	Parameters	Conditions		MIN.	TYP.	MAX.	Unit
	High-speed on-chip oscillator clock frequency <sup>Notes 1, 2</sup>	fін					24	MHz
	High-speed on-chip oscillator		R5F102 products	$T_A = -20 \text{ to } +85^{\circ}\text{C}$	-1.0		+1.0	%
	clock frequency accuracy			$T_A$ = -40 to -20°C	-1.5		+1.5	%
			R5F103 products		-5.0		+5.0	%
	Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
	Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

**Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H) and bits 0 to 2 of HOCODIV register.

2. This only indicates the oscillator characteristics. Refer to AC Characteristics for instruction execution time.



<R>

# 2.3 DC Characteristics

### 2.3.1 Pin characteristics

TA = -40 to +85°C, ^	I.8 V ≤ V	$V_{DD} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V}$		-			(1/4)
Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, high <sup>Note 1</sup>	Іон1	20-, 24-pin products: Per pin for P00 to P03 <sup>Note 4</sup> , P10 to P14, P40 to P42 30-pin products: Per pin for P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147				-10.0 Note 2	mA
		20-, 24-pin products:	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$			-30.0	mA
		Total of P40 to P42	$2.7~V \leq V_{\text{DD}} < 4.0~V$			-6.0	mA
		30-pin products: Total of P00, P01, P40, P120 (When duty ≤ 70% <sup>Note 3</sup> )	$1.8 \text{ V} \leq V_{\text{DD}} < 2.7 \text{ V}$			-4.5	mA
		20-, 24-pin products:	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$			-80.0	mA
		Total of P00 to P03 <sup>Note 4</sup> , P10 to P14	$2.7~V \leq V_{\text{DD}} < 4.0~V$			-18.0	mA
		30-pin products: Total of P10 to P17, P30, P31, P50, P51, P147 (When duty $\leq$ 70% <sup>Note 3</sup> )	$1.8 \text{ V} \leq V_{\text{DD}} < 2.7 \text{ V}$			-10.0	mA
		Total of all pins (When duty $\leq 70\%^{Note 3}$ )				-100	mA
	Іон2	Per pin for P20 to P23				-0.1	mA
		Total of all pins				-0.4	mA

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V})$

Notes 1. value of current at which the device operation is guaranteed even if the current flows from the VDD pin to an output pin.

- 2. However, do not exceed the total current value.
- 3. The output current value under conditions where the duty factor  $\leq 70\%$ . If duty factor > 70%: The output current value can be calculated with the following expression (where n represents the duty factor as a percentage).
  - Total output current of pins =  $(I_{OH} \times 0.7)/(n \times 0.01)$ <Example> Where n = 80% and IoH = -10.0 mA

Total output current of pins =  $(-10.0 \times 0.7)/(80 \times 0.01) \approx -8.7$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

4. 24-pin products only.

Caution P10 to P12 and P41 for 20-pin products, P01, P10 to P12, and P41 for 24-pin products, and P00, P10 to P15, P17, and P50 for 30-pin products do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



<R>

$I_A = -40 \text{ to } +85^{\circ}\text{C},$	1.8 V ≤ V	$V_{DD} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V}$			1	-	(2/4
Parameter	Symbol IoL1	Conditions			TYP.	MAX.	Unit
Output current, Iow <sup>Note 1</sup>		20-, 24-pin products: Per pin for P00 to P03 <sup>Note 4</sup> , P10 to P14, P40 to P42				20.0 Note 2	mA
		30-pin products: Per pin for P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147					
		Per pin for P60, P61				15.0 Note 2	mA
		20-, 24-pin products:	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$			60.0	mA
		Total of P40 to P42	$2.7~V \leq V_{\text{DD}} < 4.0~V$			9.0	mA
		30-pin products: Total of P00, P01, P40, P120 (When duty $\leq$ 70% <sup>Note 3</sup> )	$1.8 \text{ V} \leq \text{V}_{\text{DD}} < 2.7 \text{ V}$			1.8	mA
		20-, 24-pin products:	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$			80.0	mA
		Total of P00 to P03 <sup>Note 4</sup> ,	$2.7~V \leq V_{\text{DD}} < 4.0~V$			27.0	mA
		P10 to P14, P60, P61 30-pin products: Total of P10 to P17, P30, P31, P50, P51, P60, P61, P147 (When duty $\leq$ 70% <sup>Note 3</sup> )	$1.8 \text{ V} \le \text{V}_{\text{DD}} < 2.7 \text{ V}$			5.4	mA
		Total of all pins (When duty $\leq 70\%^{Note 3}$ )				140	mA
	Iol2	Per pin for P20 to P23				0.4	mA
		Total of all pins				1.6	mA

#### **•** • • •

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the Vss pin.

2. However, do not exceed the total current value.

**3.** The output current value under conditions where the duty factor  $\leq$  70%.

If duty factor > 70%: The output current value can be calculated with the following expression (where n represents the duty factor as a percentage).

• Total output current of pins =  $(I_{OL} \times 0.7)/(n \times 0.01)$ 

<Example> Where n = 80% and IoL = 10.0 mA

Total output current of pins =  $(10.0 \times 0.7)/(80 \times 0.01) \cong 8.7$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

- 4. 24-pin products only.
- Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

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Parameter	Symbol	Condition	S	MIN.	TYP.	MAX.	Unit
Input voltage, high	VIH1	Normal input buffer 20-, 24-pin products: P00 to P0 P40 to P42	)3 <sup>Note 2</sup> , P10 to P14,	0.8Vdd		Vdd	V
		30-pin products: P00, P01, P1 P40, P50, P51, P120, P147					
	VIH2	TTL input buffer	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	2.2		VDD	V
		20-, 24-pin products: P10, P11	$3.3~V \leq V_{\text{DD}} < 4.0~V$	2.0		VDD	V
		30-pin products: P01, P10, P11, P13 to P17	$1.8 \text{ V} \leq \text{V}_{\text{DD}} < 3.3 \text{ V}$	1.5		Vdd	V
	VIH3	P20 to P23		0.7Vdd		VDD	V
	VIH4	P60, P61		0.7Vdd		6.0	V
	VIH5	P121, P122, P125 <sup>Note 1</sup> , P137,	EXCLK, RESET	0.8Vdd		VDD	V
Input voltage, low	VIL1	Normal input buffer		0		0.2V <sub>DD</sub>	V
		20-, 24-pin products: P00 to P0 P40 to P42	03 <sup>Note 2</sup> , P10 to P14,				
		30-pin products: P00, P01, P10 P40, P50, P51, P120, P147					
	VIL2	TTL input buffer	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	0		0.8	V
		20-, 24-pin products: P10, P11	$3.3~V \leq V_{\text{DD}} < 4.0~V$	0		0.5	V
		30-pin products: P01, P10, P11, P13 to P17	$1.8 \text{ V} \leq \text{V}_{\text{DD}} < 3.3 \text{ V}$	0		0.32	V
	VIL3	P20 to P23		0		0.3Vdd	V
	VIL4	P60, P61		0		0.3V <sub>DD</sub>	V
	VIL5	P121, P122, P125 <sup>Note 1</sup> , P137,	EXCLK, RESET	0		0.2V <sub>DD</sub>	V
Output voltage, high	Vон1	20-, 24-pin products: P00 to P03 <sup>Note 2</sup> , P10 to P14,	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -10.0 \ \text{mA} \end{array}$	VDD-1.5			V
		P40 to P42 30-pin products:	$4.0 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V},$ IOH1 = -3.0 mA	VDD-0.7			V
		P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147	$2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V},$ IOH1 = -2.0 mA	V <sub>DD</sub> -0.6			V
			$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V},$ IOH1 = -1.5 mA	VDD-0.5			V
	Vон2	P20 to P23	Іон2 <b>=</b> –100 <i>µ</i> А	VDD-0.5			V

**Notes 1.** 20, 24-pin products only.

2. 24-pin products only.

Caution The maximum value of V<sub>IH</sub> of pins P10 to P12 and P41 for 20-pin products, P01, P10 to P12, and P41 for 24-pin products, and P00, P10 to P15, P17, and P50 for 30-pin products is V<sub>DD</sub> even in N-ch opendrain mode.

High level is not output in the N-ch open-drain mode.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



$T_A = -40$ to +85°C, 1.8 V $\leq$ VDD $\leq$ 5.5 V, Vss = 0	V)
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(4/4)

Parameter	Symbol		Conditio	ons	TYP.	MAX.	Unit	
Output voltage, low	Vol1	20-, 24-pin product P00 to P03 <sup>Note</sup> , P1		$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 20.0 \ mA \end{array} \end{array} \label{eq:eq:optimal_states}$			1.3	V
		P40 to P42 30-pin products: P0		$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 8.5 \ mA \end{array} \end{array} \label{eq:eq:electropy}$			0.7	V
		P10 to P17, P30, P31, P40, P50, P51, P120, P147		$\begin{array}{l} 2.7 \ \text{V} \leq \text{V}_{\text{DD}} \leq 5.5 \ \text{V}, \\ I_{\text{OL1}} = 3.0 \ \text{mA} \end{array}$			0.6	V
				$\begin{array}{l} 2.7 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 1.5 \ \text{mA} \end{array} \end{array} \label{eq:VDD}$			0.4	V
				$\begin{array}{l} 1.8 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 0.6 \ mA \end{array} \end{array} \label{eq:DD}$			0.4	V
	Vol2	P20 to P23		Iol2 = 400 μA			0.4	V
	Vol3			$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 15.0 \ mA \end{array} \end{array} \label{eq:VDD}$			2.0	V
			4				0.4	V
				$\begin{array}{l} 2.7 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 3.0 \ \text{mA} \end{array} \end{array} \label{eq:VDD}$			0.4	V
							0.4	V
Input leakage current, high	Ішні	Other than P121, $V_1 = V_{DD}$ P122					1	μA
	Ілна	P121, P122 (X1, X2/EXCLK)	$V_1 = V_{DD}$	Input port or external clock input			1	μA
				When resonator connected			10	μA
Input leakage current, low	ILIL1	Other than P121, P122	VI = VSS				-1	μA
	Ilil2	P121, P122 (X1, X2/EXCLK)	VI = VSS	Input port or external clock input			-1	μA
				When resonator connected			-10	μA
On-chip pull-up resistance	Ru	20-, 24-pin product P00 to P03 <sup>Note</sup> , P1 P40 to P42, P125,	0 to P14,	VI = Vss, input port	10	20	100	kΩ
		30-pin products: P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147						

Note 24-pin products only.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(1/2)

# 2.3.2 Supply current characteristics

### (1) 20-, 24-pin products

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	Idd1	Operating	HS(High-speed	$f_{H} = 24 \text{ MHz}^{\text{Note 3}}$	Basic	V <sub>DD</sub> = 5.0 V		1.5		mA
current <sup>Note 1</sup>		mode	main) mode <sup>Note 4</sup>		operation	V <sub>DD</sub> = 3.0 V		1.5		
					Normal	V <sub>DD</sub> = 5.0 V		3.3	5.0	mA
					operation	V <sub>DD</sub> = 3.0 V		3.3	5.0	
				f⊩ = 16 MHz <sup>Note 3</sup>		V <sub>DD</sub> = 5.0 V		2.5	3.7	mA
						V <sub>DD</sub> = 3.0 V		2.5	3.7	
			LS(Low-speed main) mode <sup>Note 4</sup>	$f_{IH} = 8 \text{ MHz}^{Note 3}$		V <sub>DD</sub> = 3.0 V		1.2	1.8	mA
						V <sub>DD</sub> = 2.0 V		1.2	1.8	
			HS(High-speed	$f_{MX} = 20 \text{ MHz}^{Note 2},$		Square wave input		2.8	4.4	mA
			main) mode <sup>Note4</sup>	V <sub>DD</sub> = 5.0 V		Resonator connection		3.0	4.6	
	f <sub>MX</sub> = 20 MHz <sup>Note 2</sup> ,		Square wave input		2.8	4.4	mA			
				V <sub>DD</sub> = 3.0 V		Resonator connection		3.0	4.6	
				$f_{MX} = 10 \text{ MHz}^{Note 2},$		Square wave input		1.8	2.6	mA
				V <sub>DD</sub> = 5.0 V		Resonator connection		1.8	2.6	
				$f_{MX} = 10 \text{ MHz}^{Note 2},$	Square	Square wave input		1.8	2.6	mA
				V <sub>DD</sub> = 3.0 V		Resonator connection		1.8	2.6	
			LS(Low-speed	$f_{MX} = 8 \text{ MHz}^{\text{Note 2}},$ $V_{DD} = 3.0 \text{ V}$		Square wave input		1.1	1.7	mA
		r				Resonator connection		1.1	1.7	
				$f_{MX} = 8 \text{ MHz}^{\text{Note 2}},$	1	Square wave input		1.1	1.7	mA
				V <sub>DD</sub> = 2.0 V		Resonator connection		1.1	1.7	

<R> Notes 1. Total current flowing into V<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub> or V<sub>SS</sub>. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

- <R>
- 2. When high-speed on-chip oscillator clock is stopped.
- 3. When high-speed system clock is stopped
- 4. Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS(High speed main) mode:  $V_{DD} = 2.7 \text{ V}$  to 5.5 V @1 MHz to 24 MHz  $V_{DD} = 2.4 \text{ V}$  to 5.5 V @1 MHz to 16 MHz

- LS(Low speed main) mode:  $V_{DD}$  = 1.8 V to 5.5 V @1 MHz to 8 MHz
- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fil: high-speed on-chip oscillator clock frequency
  - **3.** Temperature condition of the TYP. value is  $T_A = 25^{\circ}C$ .



(0/0)

### (1) 20-, 24-pin products

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$ 

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	IDD2 Note 2	HALT	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		440	1210	μA
current Note 1		mode	main) mode Note 6		V <sub>DD</sub> = 3.0 V		440	1210	
				f <sub>IH</sub> = 16 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		400	950	μA
					V <sub>DD</sub> = 3.0 V		400	950	
			LS (Low-speed	f <sub>IH</sub> = 8 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 3.0 V		270	542	μA
			main) mode <sup>Note 6</sup>		V <sub>DD</sub> = 2.0 V		270	542	,
			HS (High-speed	f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1000	μA
			main) mode <sup>Note 6</sup>	V <sub>DD</sub> = 5.0 V	Resonator connection		450	1170	
				$f_{MX} = 20 \text{ MHz}^{\text{Note 3}},$	Square wave input		280	1000	μA
				V <sub>DD</sub> = 3.0 V	Resonator connection		450	1170	
				$f_{MX}$ = 10 MHz <sup>Note 3</sup> ,	Square wave input		190	590	μA
				V <sub>DD</sub> = 5.0 V	Resonator connection		260	660	
				$f_{MX} = 10 \text{ MHz}^{\text{Note 3}},$ $V_{\text{DD}} = 3.0 \text{ V}$	Square wave input		190	590	μA
					Resonator connection		260	660	
			LS (Low-speed	f <sub>MX</sub> = 8 MHz <sup>Note 3</sup> ,	Square wave input		110	360	μA
			main) mode <sup>Note 6</sup>	V <sub>DD</sub> = 3.0 V	Resonator connection		150	416	
				f <sub>MX</sub> = 8 MHz <sup>Note 3</sup> ,	Square wave input		110	360	μA
				V <sub>DD</sub> = 2.0 V	Resonator connection		150	416	
	IDD3 Note 5	STOP	T <sub>A</sub> = -40°C				0.19	0.50	μA
		mode	T <sub>A</sub> = +25°C				0.24	0.50	
			T <sub>A</sub> = +50°C				0.32	0.80	
			T <sub>A</sub> = +70°C				0.48	1.20	
			T <sub>A</sub> = +85°C				0.74	2.20	

<R> Notes 1. Total current flowing into V<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub> or V<sub>SS</sub>. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

- 2. During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator clock is stopped.
- **4.** When high-speed system clock is stopped.
- 5. Not including the current flowing into the 12-bit interval timer and watchdog timer.
- **6.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS(High speed main) mode:  $V_{DD}$  = 2.7 V to 5.5 V @1 MHz to 24 MHz

V<sub>DD</sub> = 2.4 V to 5.5 V @1 MHz to 16 MHz

LS(Low speed main) mode: VDD = 1.8 V to 5.5 V @1 MHz to 8 MHz

- **Remarks 1.** f<sub>MX</sub>: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Except temperature condition of the TYP. value is T<sub>A</sub> = 25°C, other than STOP mode

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#### (2) 30-pin products

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$ 

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	IDD1	Operating	HS (High-speed	f⊪ = 24 MHz <sup>Note 3</sup>	Basic	V <sub>DD</sub> = 5.0 V		1.5		mA
current Note 1		mode	main) mode <sup>Note 4</sup>		operation	V <sub>DD</sub> = 3.0 V		1.5		
					Normal	V <sub>DD</sub> = 5.0 V		3.7	5.5	mA
					operation	V <sub>DD</sub> = 3.0 V		3.7	5.5	
				$f_{IH} = 16 \text{ MHz}^{\text{Note 3}}$ $f_{IH} = 8 \text{ MHz}^{\text{Note 3}}$		V <sub>DD</sub> = 5.0 V		2.7	4.0	mA mA
						V <sub>DD</sub> = 3.0 V		2.7	4.0	
			LS (Low-speed			V <sub>DD</sub> = 3.0 V		1.2	1.8	
			main) mode <sup>Note 4</sup>			V <sub>DD</sub> = 2.0 V		1.2	1.8	
			HS (High-speed	$f_{MX}$ = 20 MHz <sup>Note 2</sup> ,		Square wave input		3.0	4.6	mA
			main) mode <sup>Note 4</sup>	main) mode Note 4 $V_{DD} = 5.0 V$		Resonator connection		3.2	4.8	
				$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$		Square wave input		3.0	4.6	mA
				V <sub>DD</sub> = 3.0 V	ote 2	Resonator connection		3.2	4.8	
				$f_{MX}$ = 10 MHz <sup>Note 2</sup> ,		Square wave input		1.9	2.7	mA
				V <sub>DD</sub> = 5.0 V		Resonator connection		1.9	2.7	
				$f_{MX}$ = 10 MHz <sup>Note 2</sup> ,		Square wave input		1.9	2.7	mA
				V <sub>DD</sub> = 3.0 V		Resonator connection		1.9	2.7	
			LS (Low-speed	$f_{MX} = 8 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.1	1.7	mA
				V <sub>DD</sub> = 3.0 V		Resonator connection		1.1	1.7	
				$f_{MX} = 8 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.1	1.7	mA
				V <sub>DD</sub> = 2.0 V		Resonator connection		1.1	1.7	

#### <R> Notes 1. Total current flowing into VDD, including the input leakage current flowing when the level of the input pin is fixed to VDD or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

- 2. When high-speed on-chip oscillator clock is stopped.
- 3. When high-speed system clock is stopped
- 4. Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS(High speed main) mode: VDD = 2.7 V to 5.5 V @1 MHz to 24 MHz VDD = 2.4 V to 5.5 V @1 MHz to 16 MHz

LS(Low speed main) mode: V<sub>DD</sub> = 1.8 V to 5.5 V @1 MHz to 8 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - **3.** Temperature condition of the TYP. value is  $T_A = 25^{\circ}C$ .



(0/0)

#### (2) 30-pin products

(T <sub>4</sub> = _40 to ±85°C	$1.8 V \le V_{DD} \le 5.5 V, V_{SS} = 0 V$
(1A = -40 10 + 65 C)	$1.0 V \le V D U \le 0.0 V, V S = 0 V$

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	IDD2 Note 2	HALT	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		440	1280	μA
current Note 1		mode	main) mode Note 6		V <sub>DD</sub> = 3.0 V		440	1280	
				f <sub>IH</sub> = 16 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		400	1000	μA
					V <sub>DD</sub> = 3.0 V		400	1000	
			LS (Low-speed	fiH = 8 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 3.0 V		260	530	μA
			main) mode Note 6		V <sub>DD</sub> = 2.0 V		260	530	
			HS (High-speed	f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1000	μA
			main) mode <sup>Note 6</sup>	V <sub>DD</sub> = 5.0 V	Resonator connection		450	1170	
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1000	μA
				V <sub>DD</sub> = 3.0 V	Resonator connection		450	1170	
				f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		190	600	μA
				V <sub>DD</sub> = 5.0 V	Resonator connection		260	670	
				f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		190	600	μA
				V <sub>DD</sub> = 3.0 V	Resonator connection		260	670	
			LS (Low-speed	f <sub>MX</sub> = 8 MHz <sup>Note 3</sup> ,	Square wave input		95	330	μA
			main) mode <sup>Note 6</sup>	V <sub>DD</sub> = 3.0 V	Resonator connection		145	380	
				f <sub>MX</sub> = 8 MHz <sup>Note 3</sup>	Square wave input		95	330	μA
				V <sub>DD</sub> = 2.0 V	Resonator connection		145	380	
	IDD3 <sup>Note 5</sup>	STOP	T <sub>A</sub> = −40°C				0.18	0.50	μA
		mode	T <sub>A</sub> = +25°C				0.23	0.50	
			T <sub>A</sub> = +50°C				0.30	1.10	
			T <sub>A</sub> = +70°C				0.46	1.90	
			T <sub>A</sub> = +85°C				0.75	3.30	

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**Notes 1.** Total current flowing into V<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub> or V<sub>SS</sub>. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

- 2. During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator clock is stopped.
- **4.** When high-speed system clock is stopped.
- 5. Not including the current flowing into the 12-bit interval timer and watchdog timer.
- 6. Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS (High speed main) mode: VDD = 2.7 V to 5.5 V @1 MHz to 24 MHz

V<sub>DD</sub> = 2.4 V to 5.5 V @1 MHz to 16 MHz

LS (Low speed main) mode: VDD = 1.8 V to 5.5 V @1 MHz to 8 MHz

- **Remarks 1.** f<sub>MX</sub>: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Except STOP mode, temperature condition of the TYP. value is  $T_A = 25^{\circ}C$ .



#### <R> (3) Peripheral functions (Common to all products)

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Low-speed onchip oscillator operating current	Note 1				0.20		μA
12-bit interval timer operating current	ITMKA Notes 1, 2, 3				0.02		μA
Watchdog timer operating current	WDT Notes 1, 2, 4	fı∟ = 15 kHz			0.22		μA
A/D converter	ADC Notes 1, 5	When conversion at	Normal mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 5.0 V		1.30	1.70	mA
operating current		maximum speed	Low voltage mode, $AV_{REFP} = V_{DD} = 3.0 V$		0.50	0.70	mA
A/D converter reference voltage operating current	ADREF Note 1				75.0		μA
Temperature sensor operating current	ITMPS Note 1				75.0		μA
LVD operating current	Notes 1, 6				0.08		μA
Self- programming operating current	IFSP Notes 1, 8				2.00	12.20	mA
BGO operating current	BGO Notes 1, 7				2.00	12.20	mA
SNOOZE	ISNOZ Note 1	ADC operation	The mode is performed Note 9		0.50	0.60	mA
operating current			The A/D conversion operations are performed, Low voltage mode, $AV_{REFP} = V_{DD} = 3.0 V$		1.20	1.44	mA
		CSI/UART operation			0.70	0.84	mA

Notes 1. Current flowing to the VDD.

- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3, and IFIL and ITMKA when the 12-bit interval timer operates.
- 4. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer operates.
- **5.** Current flowing only to the A/D converter. The current value of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- 6. Current flowing only to the LVD circuit. The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit operates.
- 7. Current flowing only during data flash rewrite.
- 8. Current flowing only during self programming.
- 9. For shift time to the SNOOZE mode, see 17.3.3 SNOOZE mode in the RL78/G12 User's Manual Hardware.

Remarks 1. fil: Low-speed on-chip oscillator clock frequency

**2.** Temperature condition of the TYP. value is  $T_A = 25^{\circ}C$ 



# 2.4 AC Characteristics

# $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

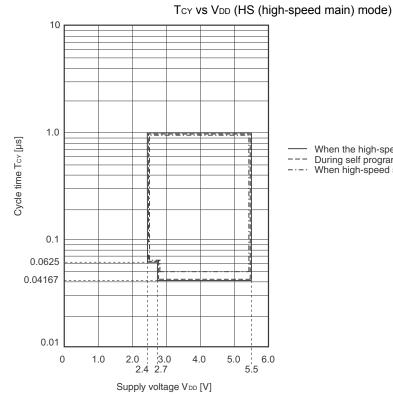
Items	Symbol		Condition	S	MIN.	TYP.	MAX.	l
Instruction cycle (minimum instruction execution time)	Тсү	Main system clock (fMAIN)	HS (High- speed main)	$2.7~V \le V_{DD} \le 5.5~V$	0.04167		1	
		operation	mode	$2.4 \text{ V} \leq V_{\text{DD}} < 2.7 \text{ V}$	0.0625		1	
			LS (Low- speed main) mode	$1.8~V \le V_{\text{DD}} \le 5.5~V$	0.125		1	
		During self	HS (High-	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	0.04167		1	
		programming	speed main) mode	$2.4~V \leq V_{\text{DD}} < 2.7~V$	0.0625		1	
			LS (Low- speed main) mode	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$	0.125		1	
External main system clock	f <sub>EX</sub>	$2.7 \text{ V} \le V_{\text{DD}} \le 5.5 \text{ V}$					20.0	Ν
frequency		$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2.7 \text{ V}$			1.0		16.0	ľ
		$1.8 \text{ V} \leq \text{V}_{\text{DD}} < 2$	1.0		8.0	ľ		
External main system clock	texh, texl	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$			24			
input high-level width, low-		$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2.7 \text{ V}$			30			
level width		$1.8 \text{ V} \leq V_{\text{DD}} < 2.4 \text{ V}$			60			
TI00 to TI07 input high-level width, low-level width	t⊤⊩, t⊤∟							
TO00 to TO07 output	fто	$4.0 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$					12	Ν
frequency		$2.7 \text{ V} \le V_{DD} < 4.0 \text{ V}$					8	Ν
		$1.8 \text{ V} \leq \text{V}_{\text{DD}} < 2$	.7 V				4	Ν
PCLBUZ0, or PCLBUZ1	<b>f</b> PCL	$4.0 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$					16	Ν
output frequency		$2.7 \text{ V} \le V_{DD} < 4.0 \text{ V}$					8	ľ
		$1.8 \text{ V} \le \text{V}_{\text{DD}} < 2.7 \text{ V}$					4	Ν
INTP0 to INTP5 input high- level width, low-level width	tinth, tintl				1			
KR0 to KR9 input available width	tkr				250			
RESET low-level width	trsL				10			

Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the timer clock select register 0 (TPS0) and the CKS0n bit of timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

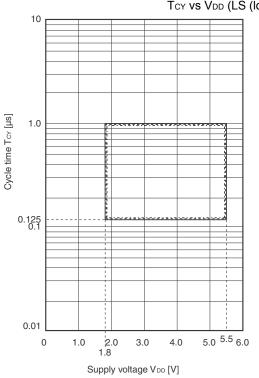


#### <R> Minimum Instruction Execution Time during Main System Clock Operation



When the high-speed on-chip oscillator clock is selected During self programming When high-speed system clock is selected \_ \_ \_

\_ . \_ .



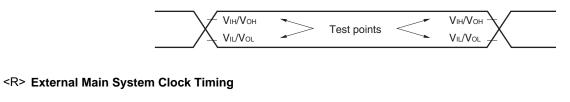
TCY VS VDD (LS (low-speed main) mode)

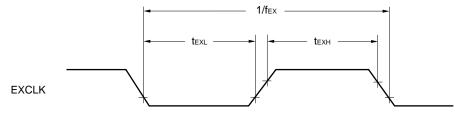
When the high-speed on-chip oscillator clock is selected

--- During self programming ---. When high-speed system clock is selected

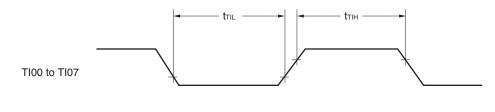


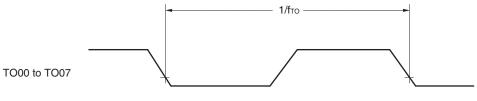
#### <R> AC Timing Test Point



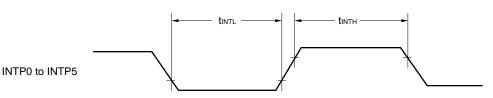


#### **TI/TO Timing**

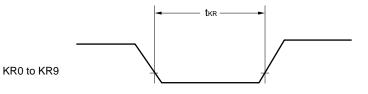




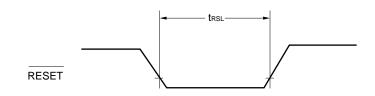
#### **Interrupt Request Input Timing**



**Key Interrupt Input Timing** 



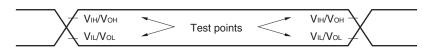
**RESET** Input Timing





# 2.5 Peripheral Functions Characteristics

#### <R> AC Timing Test Point



2.5.1 Serial array unit

#### <R> (1) During communication at same potential (UART mode) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	、 <b>U</b>	h-speed Mode	`	v-speed Mode	Unit
			MIN.	MAX.	MIN.	MAX.	
Transfer rate				fмск/6		fмск/6	bps
Note 1		Theoretical value of the maximum transfer rate $f_{CLK} = f_{MCK}^{Note2}$		4.0		1.3	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

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2. The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are:

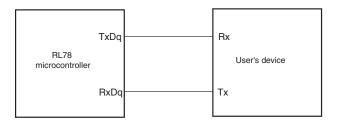
HS (high-speed main) mode: 24 MHz (2.7 V  $\leq$  VDD  $\leq$  5.5 V)

16 MHz (2.4 V 
$$\leq$$
 VDD  $\leq$  5.5 V)

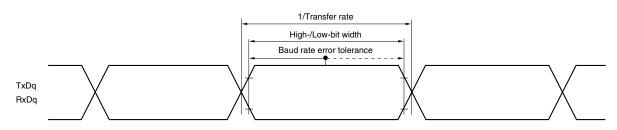
LS (low-speed main) mode: 8 MHz (1.8 V 
$$\leq$$
 VDD  $\leq$  5.5 V)

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

#### UART mode connection diagram (during communication at same potential)



#### UART mode bit width (during communication at same potential) (reference)



**Remarks 1.** q: UART number (q = 0 to 2), g: PIM, POM number (g = 0, 1)

2. fMCK: Serial array unit operation clock frequency

(Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))



# <R> (2) During communication at same potential (CSI mode) (master mode, SCK00... internal clock output, corresponding CSI00 only)

Parameter	Symbol	Conditions	HS (high-spe Mod	,	LS (low-spe Mod	Unit	
			MIN.	MAX.	MIN.	MAX.	
SCK00 cycle time	tkcy1	<b>t</b> ксү1 ≥ <b>2/f</b> с∟к	83.3		250		ns
SCK00 high-/low-	<b>t</b> кн1,	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	tксү1/2–7		tксү1/2–50		ns
level width	<b>t</b> ĸ∟1	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	tксү1/2–10		tксү1/2–50		ns
SI00 setup time	tsik1	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	23		110		ns
(to SCK00↑) <sup>Note 1</sup>		$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	33		110		ns
SI00 hold time (from SCK00↑) <sup>Note2</sup>	tksi1		10		10		ns
Delay time from SCK00↓ to SO00 output <sup>Note 3</sup>	tkso1	C = 20 pF <sup>Note 4</sup>		10		10	ns

# $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$

- **Notes 1.** When DAP00 = 0 and CKP00 = 0, or DAP00 = 1 and CKP00 = 1. The SI00 setup time becomes "to SCK00 $\downarrow$ " when DAP00 = 0 and CKP00 = 1, or DAP00 = 1 and CKP00 = 0.
  - 2. When DAP00 = 0 and CKP00 = 0, or DAP00 = 1 and CKP00 = 1. The SI00 hold time becomes "from SCK00↓" when DAP00 = 0 and CKP00 = 1, or DAP00 = 1 and CKP00 = 0.
  - **3.** When DAP00 = 0 and CKP00 = 0, or DAP00 = 1 and CKP00 = 1. The delay time to SO00 output becomes "from SCK00∱" when DAP00 = 0 and CKP00 = 1, or DAP00 = 1 and CKP00 = 0.
  - 4. C is the load capacitance of the SCK00 and SO00 output lines.

# Caution Select the normal input buffer for the SI00 pin and the normal output mode for the SO00 and SCK00 pins by using port input mode register 1 (PIM1) and port output mode register 1 (POM1).

- **Remarks 1.** This specification is valid only when CSI00's peripheral I/O redirect function is not used.
  - 2. fMCK: Serial array unit operation clock frequency
    - (Operation clock to be set by the serial clock select register 0 (SPS0) and the CKS00 bit of serial mode register 00 (SMR00).)



# <R> (3) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output) $(T_A = -40 \text{ to } +85^{\circ}\text{C}. 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}. \text{ V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit	
				MIN.	MAX.	MIN.	MAX.		
SCKp cycle time	tkcy1	tксү1 ≥ 4/fcLк	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	167		500		ns	
			$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	250		500		ns	
			$1.8~V \le V_{\text{DD}} \le 5.5~V$	-		500		ns	
SCKp high-/low-level width	tкнı,	$4.0~V \leq V_{\text{DD}} \leq$	5.5 V	tксү1/2–12		tксү1/2–50		ns	
	tĸ∟1	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$		tксү1/2–18		tксү1/2–50		ns	
		$2.4~V \leq V_{\text{DD}} \leq 5.5~V$		tксү1/2-38		tксү1/2–50		ns	
		$1.8~V \leq V_{\text{DD}} \leq 5.5~V$		-		tксү1/2–50		ns	
SIp setup time (to SCKp↑)	tsıĸı	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$		44		110		ns	
Note 1		$2.7~V \leq V_{\text{DD}} \leq 5.5~V$		44		110		ns	
		$2.4~V \leq V_{\text{DD}} \leq 5.5~V$		75		110		ns	
		$1.8~V \leq V_{\text{DD}} \leq$	5.5 V	-		110		ns	
SIp hold time (from SCKp↑) <sup>Note 2</sup>	tksi1			19		19		ns	
Delay time from SCKp↓ to SOp output <sup>Note 3</sup>	tkso1	C = 30 pF <sup>Note</sup>	C = 30 pF <sup>Note4</sup>		25		25	ns	

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **4.** C is the load capacitance of the SCKp and SOp output lines.

# Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp and SCKp pins by using port input mode register 1 (PIM1) and port output mode registers 0, 1, 4 (POM0, POM1, POM4).

- **Remarks 1.** p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3: "1, 3" is only for the R5F102 products)
  - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3: "1, 3" is only for the R5F102 products.))



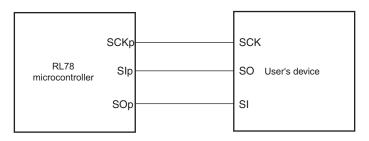
Parameter	Symbol	Conditions		HS (high main)	•	LS (low-speed main) Mode		Unit	
				MIN.	MAX.	MIN.	MAX.		
SCKp cycle time Note4	tkCY2	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	20 MHz < fмск	8/fмск		_		ns	
			fмск ≤ 20 MHz	6/fмск		6/fмск		ns	
		$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	16 MHz < fмск	8/fмск		_		ns	
			fмск ≤ 16 MHz	6/fмск		6/fмск		ns	
		$2.4~V \leq V_{\text{DD}} \leq 5.5~V$		6/fмск		6/fмск		ns	
				and 500		and 500			
		$1.8~V \le V_{\text{DD}} \le 5.5~V$		-		6/ <b>f</b> мск		ns	
						and 750			
SCKp high-/low-level	tкн2,	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$		tксү2/2-7		tксү2/2-7		ns	
width	tĸ∟2	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$		tксү2/2–8		tксү2/2-8		ns	
		$2.4~V \leq V_{\text{DD}} \leq 5.5~V$		tксү2/2–18		tксү2/2-18		ns	
		$1.8~V \leq V_{\text{DD}} \leq 5.5~V$		_		tксү2/2-18		ns	
SIp setup time	tsik2	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$		1/fмск +		1/fмск +		ns	
(to SCKp↑) <sup>Note 1</sup>				20		30			
		$2.4~V \leq V_{\text{DD}} \leq 5.5~V$		1/fмск +		1/fмск +		ns	
				30		30			
		$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$		-		1/fмск + 30		ns	
SIp hold time	tksi2			1/f <sub>мск</sub> +		1/f <sub>мск</sub> +		ns	
(from SCKp↑) Note 2				31		31			
Delay time from	tkso2	C = 30 pF <sup>Note4</sup>	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$		2/fмск +		2/fмск +	ns	
SCKp↓ to SOp output <sup>Note 3</sup>					44		110		
SOp output			$2.4~V \le V_{\text{DD}} \le 5.5~V$		2/fмск + 75		2/fмск + 110	ns	
			$1.8 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$		_		2/fмск + 110	ns	

# <R> (4) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

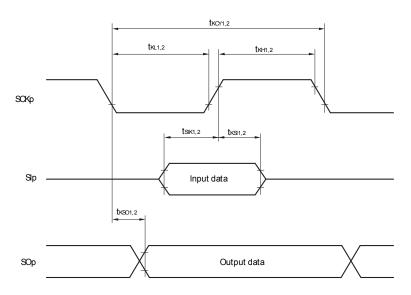
- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp<sup>↑</sup>" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SOp output lines.
  - 5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
- Caution Select the normal input buffer for the SIp and SCKp pins and the normal output mode for the SOp pin by using port input mode register 1 (PIM1) and port output mode registers 0, 1, 4 (POM0, POM1, POM4).



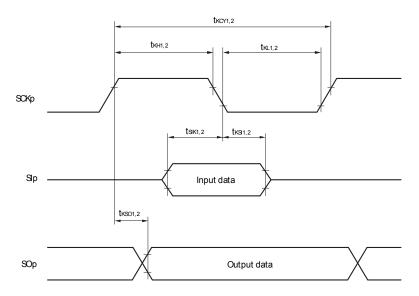




CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



(Remarks are listed on the next page.)



- **Remarks 1.** p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3: "1, 3" is only for the R5F102 products.)
  - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3: "1, 3" is only for the R5F102 products.))

# <R> (5) During communication at same potential (simplified $I^2C$ mode)

Parameter	Symbol	Conditions	HS (high-speed	HS (high-speed main) Mode LS (low-speed main) Mode		
			LS (low-speed			
			MIN.	MAX.		
SCLr clock frequency	fsc∟	$1.8~V \leq V_{\text{DD}} \leq 5.5~V,$		400 Note 1	kHz	
		$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$				
		$1.8 \text{ V} \le \text{V}_{\text{DD}} < 2.7 \text{ V},$		300 Note 1	kHz	
		$C_b$ = 100 pF, $R_b$ = 5 k $\Omega$				
Hold time when SCLr = "L"	tLow	$1.8~V \leq V_{\text{DD}} \leq 5.5~V,$	1150		ns	
		$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$				
		$1.8~V \leq V_{\text{DD}} < 2.7~V,$	1550		ns	
		$C_b$ = 100 pF, $R_b$ = 5 k $\Omega$				
Hold time when SCLr = "H"	tнigн	$1.8~V \leq V_{\text{DD}} \leq 5.5~V,$	1150		ns	
		$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$				
		$1.8~V \leq V_{\text{DD}} < 2.7~V,$	1550		ns	
		$C_b$ = 100 pF, $R_b$ = 5 k $\Omega$				
Data setup time (reception)	tsu:dat	$1.8~V \leq V_{\text{DD}} \leq 5.5~V,$	1/fмск + 145 <sup>Note</sup>		ns	
		$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$	2			
		$1.8~V \leq V_{\text{DD}} < 2.7~V,$	1/fмск + 230 <sup>Note</sup>		ns	
		$C_b$ = 100 pF, $R_b$ = 5 k $\Omega$	2			
Data hold time (transmission)	thd:dat	$1.8~V \leq V_{\text{DD}} \leq 5.5~V,$	0	355	ns	
		$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$				
		$1.8~V \leq V_{\text{DD}} < 2.7~V,$	0	405	ns	
		$C_b$ = 100 pF, $R_b$ = 5 k $\Omega$				

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$ 

Notes 1. The value must also be equal to or less than  $f_{MCK}/4$ .

<R>

Set tsu:DAT so that it will not exceed the hold time when SCLr = "L" or SCLr = "H".

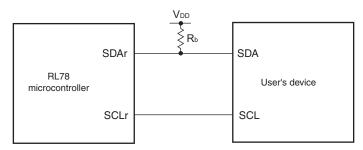
Caution Select the N-ch open drain output (VDD tolerance) mode for SDAr by using port output mode register h (POMh).

(Remarks are listed on the next page.)

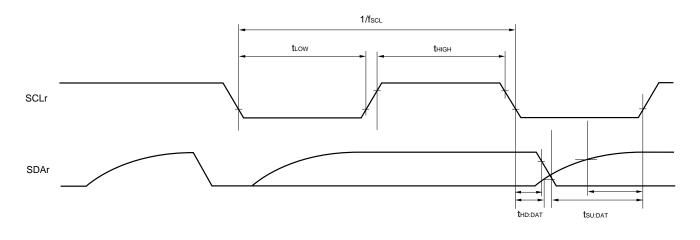
2.



### Simplified I<sup>2</sup>C mode connection diagram (during communication at same potential)



### Simplified I<sup>2</sup>C mode serial transfer timing (during communication at same potential)



- **2.** r: IIC number (r = 00, 01, 11, 20), h: = POM number (h = 0, 1, 4, 5)
- fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (0, 1, 3))
- **4.** Simplified  $I^2C$  mode is supported only by the R5F102 products.



Parameter	Symbol		С	onditions		igh-speed n) Mode		ow-speed n) Mode	Unit
					MIN.	MAX.	MIN.	MAX.	
Transfer		Reception	$4.0 V \le V_{DD} \le$	5.5 V,		fмск/6		fмск/6	bps
rate Note4			$2.7~V \leq V_b \leq 4$	4.0 V		Note1		Note1	
				Theoretical value of the maximum transfer rate fmck = fclk		4.0		1.3	Mbps
				$\begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V \end{array}$		fмск/6 Note1		fмск/6 Note1	bps
				Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note3}$		4.0		1.3	Mbps
			$1.8 V \le V_{DD} <$ $1.6 V \le V_b \le 2$	3.3 V,		fмск/6 Notes1, 2		fмск/6 Notes1, 2	bps
				Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note3}$		4.0		1.3	Mbp
		Transmission	$4.0 V \le V_{DD} \le$	5.5 V,		Note4		Note4	bps
			$2.7~V \leq V_b \leq 4.0~V$						
				Theoretical value of the maximum transfer rate $C_b$ = 50 pF, $R_b$ = 1.4 k $\Omega$ , $V_b$ = 2.7 V		2.8 Note5		2.8 Note5	Mbp
			$2.7 V \le V_{DD} <$	4.0 V,		Note6		Note6	bps
			$2.3~V \leq V_b \leq 2$	2.7 V,					
				Theoretical value of the maximum transfer rate $C_b$ = 50 pF, $R_b$ = 2.7 k $\Omega$ , $V_b$ = 2.3 V		1.2 Note7		1.2 Note7	Mbp
			$1.8 V \le V_{DD} <$	$1.8 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V},$		Notes		Notes	bps
			$1.6~V \leq V_b \leq 2$	2.0 V		2, 8		2, 8	
				Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega, V_b = 1.6 \text{ V}$		0.43 Note9		0.43 Note9	Mbp

### <R> (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$ 

<R> Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

< R> **2.** Use it with  $V_{DD} \ge V_b$ .

 The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are: HS (high-speed main) mode: 24 MHz (2.7 V ≤ V<sub>DD</sub> ≤ 5.5 V)

16 MHz (2.4 V  $\leq$  V\_DD  $\leq$  5.5 V)

LS (low-speed main) mode: 8 MHz (1.8 V  $\leq$  V\_{DD}  $\leq$  5.5 V)

<R>

<R>

**4.** The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V  $\leq$  V\_{DD}  $\leq$  5.5 V and 2.7 V  $\leq$  V\_b  $\leq$  4.0 V

Maximum transfer rate =

$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3}$$
 [bps]

 $\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\}$   $(\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits} \times 100 [\%]$ 

Baud rate error (theoretical value) =

\* This value is the theoretical value of the relative difference between the transmission and reception sides.



- 5. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to **Note 4** above to calculate the maximum transfer rate under conditions of the customer.
- <R>

<R>

<R>

<R>

**6.** The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V  $\leq$  V\_DD < 4.0 V and 2.3 V  $\leq$  V\_b  $\leq$  2.7 V

Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =

$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\}}{(\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 [\%]$$

\* This value is the theoretical value of the relative difference between the transmission and reception sides.

- 7. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 6 above to calculate the maximum transfer rate under conditions of the customer.
- **8.** The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.8 V  $\leq$  V\_DD < 3.3 V, 1.6 V  $\leq$  V\_b  $\leq$  2.0 V

Maximum transfer rate =

$$(-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})) \times 3$$

Baud rate error (theoretical value) =

(Transfer rate) × Number of transferred bits
 \* This value is the theoretical value of the relative difference between the transmission and reception sides.

 $\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\}$  × 100 [%]

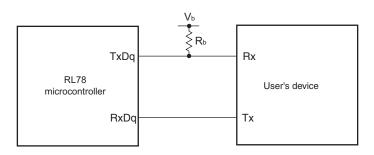
**9.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to **Note 8** above to calculate the maximum transfer rate under conditions of the customer.

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.

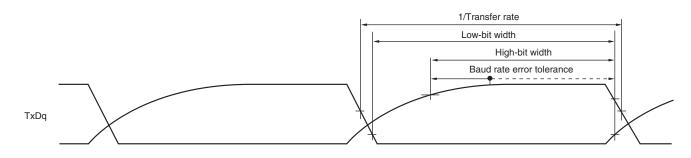


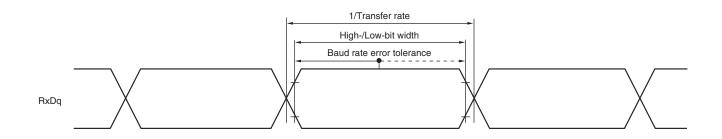
<R>

### UART mode connection diagram (during communication at different potential)



### UART mode bit width (during communication at different potential) (reference)





<r></r>	<b>Remarks 1.</b> R <sub>b</sub> [Ω]: Communication line (TxDq) pull-up resistance, C <sub>b</sub> [F]: Communication line (TxDq) load capacitance,
	Vb[V]: Communication line voltage
<r></r>	<b>2.</b> q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)

- Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
  - m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))
  - **4.** UART0 of the 20- and 24-pin products supports communication at different potential only when the peripheral I/O redirection function is not used.



# <R> (7) Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCK00... internal clock output, corresponding CSI00 only)

Parameter	Symbol		Conditions	HS (higl main)		LS (low main)		Unit
				MIN.	MAX.	MIN.	MAX.	1
SCK00 cycle time	tксү1	tĸcv1≥2/fcLĸ		200		1150		ns
			$\begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 20 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	300		1150		ns
SCK00 high-level width	tкнı	$4.0 V \le V_{DD} \le 5.5$ $C_b = 20 \text{ pF}, R_b =$	5 V, 2.7 V ≤ Vb ≤ 4.0 V, 1.4 kΩ	tксү1/2 – 50		tксү1/2– 50		ns
		$2.7 V \le V_{DD} < 4.0$ $C_b = 20 \text{ pF}, R_b =$	) V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, 2.7 kΩ	tксү1/2 – 120		tксү1/2 – 120		ns
SCK00 low-level width	tĸ∟ı		4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V, 2.7 V ≤ V <sub>b</sub> ≤ 4.0 V, C <sub>b</sub> = 20 pF, R <sub>b</sub> = 1.4 kΩ			tксү1/2 – 50		ns
		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.0$ $C_{\text{b}} = 20 \text{ pF}, \text{R}_{\text{b}} =$	) V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, 2.7 kΩ	tксү1/2 – 10		tксү1/2 – 50		ns
SI00 setup time (to SCK00↑) <sup>Note 1</sup>	tsik1	$\label{eq:VDD} \begin{array}{l} 4.0 \ V \leq V_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ \\ C_b = 20 \ pF, \ R_b = 1.4 \ k\Omega \end{array}$		58		479		ns
		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.0 \text{ C}_{\text{b}} = 20 \text{ pF}, \text{R}_{\text{b}} = 10 \text{ c}_{\text{b}}$	) V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, 2.7 kΩ	121		479		ns
SI00 hold time (from SCK00↑) <sup>Note 1</sup>	tksi1	$\begin{array}{l} \label{eq:VDD} 4.0 \; V \leq V_{DD} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 20 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$		10		10		ns
		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.0 \text{ C}_{\text{b}} = 20 \text{ pF}, \text{R}_{\text{b}} = 10 \text{ c}_{\text{b}}$	) V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, 2.7 kΩ	10		10		ns
Delay time from SCK00↓ to SO00 output <sup>Note 1</sup>	tkso1	$4.0 V \le V_{DD} \le 5.5$ C <sub>b</sub> = 20 pF, R <sub>b</sub> =	$5 V$ , 2.7 V $\le V_b \le 4.0 V$ , 1.4 kΩ		60		60	ns
		$2.7 V \le V_{DD} < 4.0$ $C_b = 20 \text{ pF}, R_b =$	) V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, 2.7 kΩ		130		130	ns
SI00 setup time (to SCK00↓) <sup>Note 2</sup>	tsik1	$4.0 V \le V_{DD} \le 5.5$ C <sub>b</sub> = 20 pF, R <sub>b</sub> =	$5 V, 2.7 V \le V_b \le 4.0 V,$ 1.4 kΩ	23		110		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0$ $C_b = 20 \text{ pF}, \text{ R}_b =$	) V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, 2.7 kΩ	33		110		ns
SI00 hold time (from SCK00↓) <sup>Note 2</sup>	tksi1	$4.0 V \le V_{DD} \le 5.5$ $C_b = 20 \text{ pF}, R_b =$	$5 V, 2.7 V \le V_b \le 4.0 V,$ 1.4 kΩ	10		10		ns
		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.0$ $C_{\text{b}} = 20 \text{ pF}, \text{R}_{\text{b}} =$	) V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, 2.7 kΩ	10		10		ns
Delay time from SCK00↑ to SO00 output <sup>Note 2</sup>	t <sub>KSO1</sub>	$4.0 V \le V_{DD} \le 5.5$ $C_b = 20 \text{ pF}, R_b =$	5 V, 2.7 V ≤ V <sub>b</sub> ≤ 4.0 V, 1.4 kΩ		10		10	ns
		$2.7 V \le V_{DD} < 4.0$ $C_b = 20 \text{ pF}, R_b =$	) V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, 2.7 kΩ		10		10	ns

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

(Notes, Caution, and Remarks are listed on the next page.)



- **Notes 1.** When DAP00 = 0 and CKP00 = 0, or DAP00 = 1 and CKP00 = 1
  - **2.** When DAP00 = 0 and CKP00 = 1, or DAP00 = 1 and CKP00 = 0.
- <R> Caution Select the TTL input buffer for the SI00 pin and the N-ch open drain output (VDD tolerance) mode for the SO00 pin and SCK00 pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VH and VL, see the DC characteristics with TTL input buffer selected.
  - **Remarks 1.** R<sub>b</sub> [Ω]:Communication line (SCK00, SO00) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCK00, SO00) load capacitance, V<sub>b</sub> [V]: Communication line voltage
    - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register 0 (SPS0) and the CKS00 bit of serial mode register 00 (SMR00).)



# <R> (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (1/3)

Parameter	Symbol		Conditions	HS (high-spe Mode	,	LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkCY1	$t_{\text{KCY1}} \ge 4/f_{\text{CLK}}$	$4.0~V \leq V_{\text{DD}} \leq 5.5~V,$	300		1150		ns
			$2.7~V \leq V_b \leq 4.0~V,$					
			$C_b$ = 30 pF, $R_b$ = 1.4 k $\Omega$					
			$2.7 \text{ V} \leq \text{V}_{\text{DD}} < 4.0 \text{ V},$	500		1150		ns
			$2.3~V \leq V_b \leq 2.7~V,$					
			$C_b$ = 30 pF, $R_b$ = 2.7 k $\Omega$					
			$1.8 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V},$	1150		1150		ns
			$1.6~V \leq V_{b} \leq 2.0~V$ $^{\text{Note}}\text{,}$					
			$C_b$ = 30 pF, $R_b$ = 5.5 k $\Omega$					
SCKp high-level width	<b>t</b> кн1	$4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \ 2.7 \ V \leq V_{\text{b}} \leq 4.0 \ V,$		tксү1/2-75		tксү1/2–75		ns
		$C_b$ = 30 pF, $R_b$ = 1.4 k $\Omega$						
		$2.7 \text{ V} \leq V_{\text{DD}} <$	$4.0 \ V, \ 2.3 \ V \leq V_{b} \leq 2.7 \ V,$	tксү1/2 –170		tксү1/2–170		ns
		$C_b$ = 30 pF, $R_b$ = 2.7 k $\Omega$						
		$1.8 V \le V_{DD} <$	3.3 V, 1.6 V $\leq$ V_b $\leq$ 2.0 V $^{\text{Note}},$	tксү1/2 –458		tксү1/2–458		ns
		C <sub>b</sub> = 30 pF, R	b = 5.5 kΩ					
SCKp low-level width	<b>t</b> ĸ∟1	$4.0~V \leq V_{\text{DD}} \leq$	5.5 V, 2.7 V $\leq$ V <sub>b</sub> $\leq$ 4.0 V,	tксү1/2-12		tксү1/2–50		ns
		C <sub>b</sub> = 30 pF, R	<sub>b</sub> = 1.4 kΩ					
		$2.7 \text{ V} \leq \text{V}_{\text{DD}}$ <	4.0 V, 2.3 V $\leq$ V_b $\leq$ 2.7 V,	tксү1/2-18		tксү1/2–50		ns
		C <sub>b</sub> = 30 pF, R	<sub>b</sub> = 2.7 kΩ					
		$1.8 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V \ ^{\text{Note}},$		tксү1/2 –50		tксү1/2–50		ns
		C <sub>b</sub> = 30 pF, R	<sub>b</sub> = 5.5 kΩ					

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.8 \text{ V} \le \text{V}_{DD} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$ 

Note Use it with  $V_{DD} \ge V_b$ .

- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SOp pin and SCKp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.
- Remarks 1. R<sub>b</sub> [Ω]: Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - **2.** p: CSI number (p = 00, 20)



# <R> (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (2/3)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↑) <sup>Note 1</sup>	tsik1	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	81		479		ns
		$\begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	177		479		ns
			479		479		ns
SIp hold time (from SCKp↑) <sup>Note 1</sup>	tksi1	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	19		19		ns
		$\begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	19		19		ns
		$\label{eq:VDD} \left\{ \begin{array}{l} 1.8 \; V \leq V_{DD} < 3.3 \; V, \; 1.6 \; V \leq V_b \leq 2.0 \; V^{\mbox{ Note } 2}, \\ C_b = 30 \; pF, \; R_b = 5.5 \; k\Omega \end{array} \right.$	19		19		ns
Delay time from SCKp↓ to	tkso1	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$		100		100	ns
SOp output Note 1		$\label{eq:VD} \begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$		195		195	ns
		$\label{eq:VDD} \begin{split} 1.8 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V^{\mbox{Note $2$}}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$		483		483	ns

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

<R> Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

<R>

**2.** Use it with  $V_{DD} \ge V_b$ .

(Cautions and Remarks are listed on the next page.)



<R> (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (3/3)

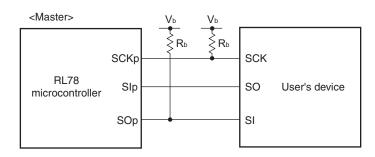
Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↓) <sup>Note 1</sup>	tsik1	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	44		110		ns
		$\begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	44		110		ns
		$\label{eq:VDD} \begin{split} 1.8 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V^{\text{Note 2}}, \\ C_{\text{b}} = 30 \ p\text{F}, \ R_{\text{b}} = 5.5 \ k\Omega \end{split}$	110		110		ns
SIp hold time (from SCKp↓) <sup>Note 1</sup>	tksi1	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	19		19		ns
		$\begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	19		19		ns
		$\label{eq:VDD} \begin{split} 1.8 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V^{\text{Note 2}}, \\ C_{\text{b}} = 30 \ p\text{F}, \ R_{\text{b}} = 5.5 \ k\Omega \end{split}$	19		19		ns
Delay time from SCKp↑ to	tkso1	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$		25		25	ns
SOp output Note 1		$\label{eq:VDD} \begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$		25		25	ns
		$\label{eq:VDD} \begin{split} 1.8 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V^{\text{Note 2}}, \\ C_{\text{b}} = 30 \ p\text{F}, \ R_{\text{b}} = 5.5 \ k\Omega \end{split}$		25		25	ns

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$ 

- <R> Notes 1. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.2. Use it with  $V_{DD} \ge V_b$ .
- <R> Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SOp pin and SCKp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.
   2. CSI01 and CSI11 cannot communicate at different potential.
  - 2. Color and Corrication communicate at unreferit potential.

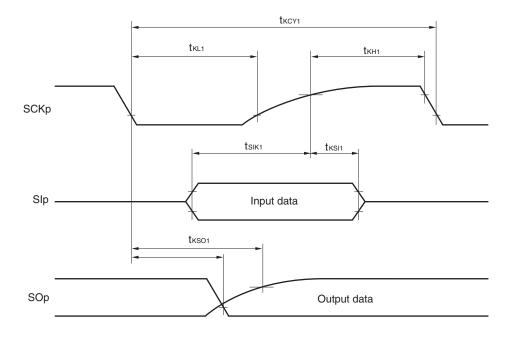
**2.** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)

### CSI mode connection diagram (during communication at different potential)

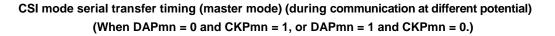


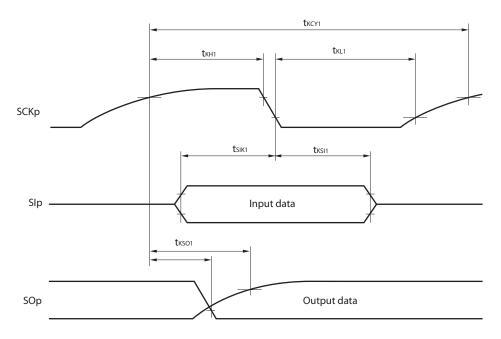


**Remarks 1.** R<sub>b</sub> [Ω]: Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage



### CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1)







### <R> (9) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (slave mode, SCKp... external clock input) $(T_A = -40 \text{ to } \pm 85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{ Vss} = 0.\text{ V})$

Parameter	Symbol	C	onditions	HS (high-spo Mod		LS (low-spe Moc	,	Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time Note 1	tkCY2	$4.0~V \leq V_{\text{DD}} \leq 5.5~V,$	20 MHz < $f_{MCK} \le$ 24 MHz	12/fмск		_		ns
		$2.7~V \leq V_b \leq 4.0~V$	8 MHz < $f_{MCK} \le$ 20 MHz	10/ <b>f</b> мск		_		ns
			$4 \text{ MHz} < f_{\text{MCK}} \le 8 \text{ MHz}$	8/fмск		16/fмск		ns
			fмск ≤4 MHz	6/fмск		10/fмск		ns
		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.0 \text{ V},$	20 MHz < $f_{MCK} \le$ 24 MHz	16/ <b>f</b> мск		_		ns
		$2.3 \ V \le V_b \le 2.7 \ V$	16 MHz < fмск ≤ 20 MHz	14/fмск		-		ns
			8 MHz < fмск ≤ 16 MHz	12/fмск		_		ns
			$4 \text{ MHz} < f_{MCK} \le 8 \text{ MHz}$	8/fмск		16/fмск		ns
			fмск ≤4 MHz	6/fмск		10/fмск		ns
		$1.8 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V},$	20 MHz < fмск ≤ 24 MHz	36/fмск		-		ns
		$1.6 \ V \le V_b \le 2.0 \ V$	16 MHz < fмск ≤ 20 MHz	<b>32/f</b> мск		-		ns
		Note 2	8 MHz < fмск ≤ 16 MHz	26/fмск		-		ns
			4 MHz < fмск ≤ 8 MHz	16/fмск		16/ <b>f</b> мск		ns
			fмск ≤4 MHz	<b>10/f</b> мск		10/fмск		ns
SCKp high-/low-level	<b>t</b> кн2,	$4.0 \ V \le V_{\text{DD}} \le 5.5 \ V, \ 2.7 \ V \le V_b \le 4.0 \ V$		tkcy2/2 - 12		tксү2/2 – 50		ns
width	tĸ∟2	$2.7 \text{ V} \le V_{\text{DD}} < 4.0 \text{ V},$	$2.3~V \leq V_{b} \leq 2.7~V$	tkcy2/2 - 18		tксү2/2 – 50		ns
		$1.8 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V},$	$1.6~V \leq V_b \leq 2.0~V^{\text{Note 2}}$	tkcy2/2-50		tксү2/2 – 50		ns
SIp setup time	tsik2	$4.0~V \leq V_{\text{DD}} \leq 5.5~V,$	$2.7~V \leq V_{\text{DD}} \leq 4.0~V$	1/fмск + 20		1/fмск + 30		ns
(to SCKp↑) Note 3		$2.7 \text{ V} \le V_{\text{DD}} < 4.0 \text{ V},$	$2.3~V \leq V_{b} \leq 2.7~V$	1/fмск + 20		1/fмск + 30		ns
		$1.8 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V},$	$1.6~V \leq V_{\text{DD}} \leq 2.0~V$ $^{Note~2}$	1/fмск + 30		1/fмск + 30		ns
SIp hold time (from SCKp↑) <sup>Note 4</sup>	tksi2			1/fмск + 31		1/fмск + 31		ns
Delay time from	tkso2	$4.0~V \leq V_{\text{DD}} \leq 5.5~V,$	$2.7 V \le V_b \le 4.0 V$ ,		2/fмск +		2/fмск +	ns
SCKp↓ to SOp		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 1.4	kΩ		120		573	
output Note 5		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.0 \text{ V},$	$2.3~V \leq V_b \leq 2.7~V,$		2/fмск +		2/fмск +	ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 2.7	'kΩ		214		573	
		$1.8 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V},$	$1.6~V \leq V_{b} \leq 2.0~V^{\text{Note 2}},$		2/fмск +		2/fмск +	ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 5.5	kΩ		573		573	

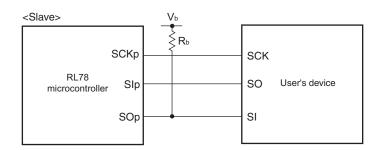
Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

**2.** Use it with  $V_{DD} \ge V_b$ .

- **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp<sup>↑</sup>" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Cautions 1. Select the TTL input buffer for the SIp and SCKp pins and the N-ch open drain output (VDD tolerance) mode for the SOp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.



### CSI mode connection diagram (during communication at different potential)

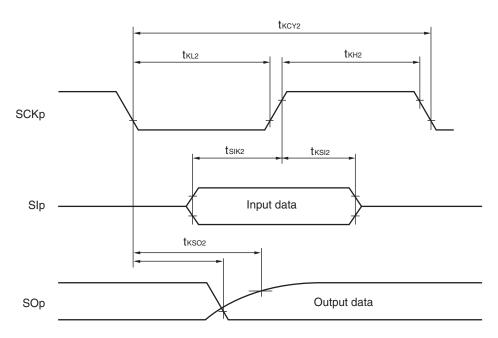


- Remarks 1.
   Rb [Ω]: Communication line (SOp) pull-up resistance, Cb [F]: Communication line (SOp) load capacitance,

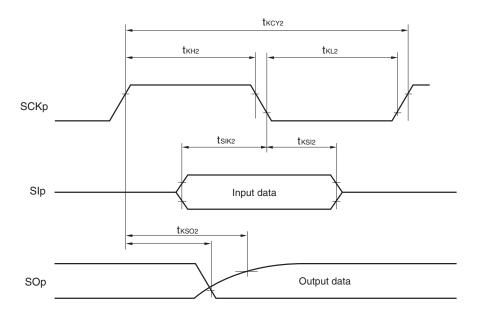
   Vb [V]: Communication line voltage
  - **2.** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)

 fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 10))

CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)







### CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)

**Remark** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)



### <R> (10) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I<sup>2</sup>C mode)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$ 

Parameter	Symbol	Conditions		h-speed Mode	•	v-speed Mode	Unit
			MIN.	MAX.	MIN.	MAX.	
SCLr clock frequency	fscL	$\begin{array}{l} 4.0 \; V \leq V_{\text{DD}} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 100 \; p\text{F}, \; R_b = 2.8 \; k\Omega \end{array}$		400 <sup>Note1</sup>		300 <sup>Note1</sup>	kHz
		$\begin{array}{l} 2.7 \; V \leq V_{\text{DD}} < 4.0 \; V,  2.3 \; V \leq V_{b} \leq 2.7 \; V, \\ C_{b} = 100 \; p\text{F}, \; R_{b} = 2.7 \; k\Omega \end{array}$		400 <sup>Note1</sup>		300 <sup>Note1</sup>	kHz
		$\label{eq:VDD} \begin{split} 1.8 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_{b} \leq 2.0 \ V, \\ \text{C}_{b} = 100 \ \text{pF}, \ \text{R}_{b} = 5.5 \ \text{k}\Omega \end{split}$		300 <sup>Note1</sup>		300 <sup>Note1</sup>	kHz
Hold time when SCLr = "L"	tLow	$\begin{array}{l} 4.0 \ V \leq V_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 100 \ pF, \ R_b = 2.8 \ k\Omega \end{array}$	1150		1550		ns
		$\label{eq:VDD} \begin{array}{l} 2.7 \ V \leq V_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{b} \leq 2.7 \ V, \\ C_{b} = 100 \ pF, \ R_{b} = 2.7 \ k\Omega \end{array}$	1150		1550		ns
		$\begin{split} 1.8 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ \text{C}_b = 100 \ \text{pF}, \ R_b = 5.5 \ \text{k}\Omega \end{split}$	1550		1550		ns
Hold time when SCLr = "H"	tніgн	$\begin{array}{l} 4.0 \; V \leq V_{\text{DD}} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 100 \; p\text{F}, \; R_b = 2.8 \; k\Omega \end{array}$	675		610		ns
		$\label{eq:VDD} \begin{array}{l} 2.7 \ V \leq V_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{b} \leq 2.7 \ V, \\ C_{b} = 100 \ p\text{F}, \ R_{b} = 2.7 \ k\Omega \end{array}$	600		610		ns
		$\begin{split} 1.8 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ \text{$^{Note2}$} \\ C_b = 100 \ \text{pF}, \ R_b = 5.5 \ \text{k}\Omega \end{split}$	610		610		ns
Data setup time (reception)	tsu:dat	$\begin{array}{l} 4.0 \; V \leq V_{\text{DD}} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 100 \; pF, \; R_b = 2.8 \; k\Omega \end{array}$	1/fмск + 190 Note3		1/fмск + 190 Note3		ns
		$\begin{array}{l} 2.7 \; V \leq V_{\text{DD}} < 4.0 \; V,  2.3 \; V \leq V_{b} \leq 2.7 \; V, \\ C_{b} = 100 \; pF, \; R_{b} = 2.7 \; k\Omega \end{array}$	1/fмск + 190 Note3		1/fмск + 190 Note3		ns
		$\label{eq:VDD} \begin{array}{l} 1.8 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_{b} \leq 2.0 \ V, \\ \\ C_{b} = 100 \ pF, \ R_{b} = 5.5 \ k\Omega \end{array}$	1/fмск + 190 Note3		1/fмск + 190 Note3		ns
Data hold time (transmission)	thd:dat	$\begin{array}{l} 4.0 \; V \leq V_{\text{DD}} \leq 5.5 \; \text{V},  2.7 \; \text{V} \leq V_{b} \leq 4.0 \; \text{V}, \\ C_{b} = 100 \; \text{pF}, \; \text{R}_{b} = 2.8 \; \text{k}\Omega \end{array}$	0	355	0	355	ns
		$\label{eq:VDD} \begin{array}{l} 2.7 \ V \leq V_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{b} \leq 2.7 \ V, \\ C_{b} = 100 \ pF, \ R_{b} = 2.7 \ k\Omega \end{array}$	0	355	0	355	ns
		$\label{eq:VDD} \begin{array}{l} 1.8 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_{b} \leq 2.0 \ V, \\ \\ C_{b} = 100 \ p\text{F}, \ R_{b} = 5.5 \ k\Omega \end{array}$	0	405	0	405	ns

<R> Notes 1. The value must also be equal to or less than fmck/4.

**2.** Use it with  $V_{DD} \ge V_b$ .

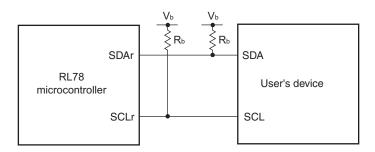
3. Set tsu:DAT so that it will not exceed the hold time when SCLr = "L" or SCLr = "H".

- <R> Cautions 1. Select the TTL input buffer and the N-ch open drain output (VDD tolerance) mode for the SDAr pin and the N-ch open drain output (VDD tolerance) mode for the SCLr pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
  - 2. IIC01 and IIC11 cannot communicate at different potential.

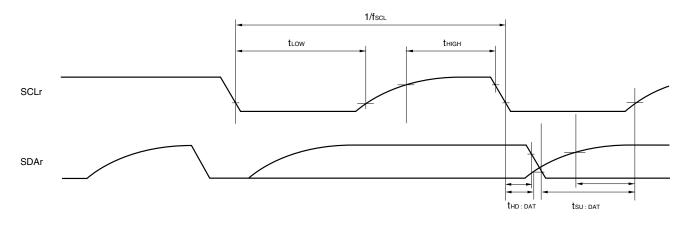
(Remarks are listed on the next page.)



### Simplified I<sup>2</sup>C mode connection diagram (during communication at different potential)



### Simplified I<sup>2</sup>C mode serial transfer timing (during communication at different potential)



- **Remarks 1.** R<sub>b</sub> [Ω]: Communication line (SDAr, SCLr) pull-up resistance, C<sub>b</sub> [F]: Communication line (SDAr, SCLr) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - **2.** r: IIC Number (r = 00, 20)
  - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
     m: Unit number (m = 0,1), n: Channel number (n = 0))
  - 4. Simplified  $I^2$ C mode is supported only by the R5F102 products.



### 2.5.2 Serial interface IICA

Parameter	Symbol	Conditions	HS	(high-spee	ed main) m	node	Unit
			LS	(low-spee	d main) m	ode	
			Standa	rd Mode	Fast Mode		
			MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fsc∟	Fast mode: fcLK≥ 3.5 MHz			0	400	kHz
		Normal mode: fc∟κ≥ 1 MHz	0	100			kHz
Setup time of restart condition	tsu:sta		4.7		0.6		μs
Hold time <sup>Note 1</sup>	thd:sta		4.0		0.6		μs
Hold time when SCLA0 = "L"	<b>t</b> LOW		4.7		1.3		μs
Hold time when SCLA0 = "H"	<b>t</b> HIGH		4.0		0.6		μs
Data setup time (reception)	tsu:dat		250		100		ns
Data hold time (transmission) <sup>Note 2</sup>	thd:dat		0	3.45	0	0.9	μs
Setup time of stop condition	tsu:sto		4.0		0.6		μs
Bus-free time	<b>t</b> BUF		4.7		1.3		μs

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

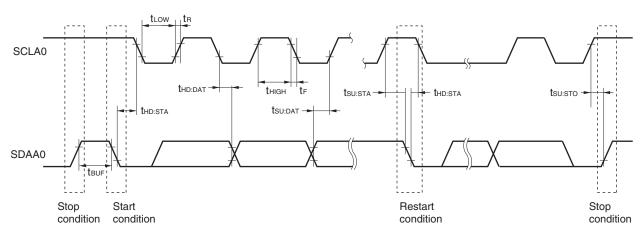
Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of the during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

- Caution Only in the 30-pin products, the values in the above table are applied even when bit 2 (PIOR2) in the peripheral I/O redirection register (PIOR) is 1. At this time, the pin characteristics (IoH1, IoL1, VOH1, VOL1) must satisfy the values in the redirect destination.
- **Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

	Normal mode:	$C_b$ = 400 pF, Rb = 2.7 k $\Omega$
>	Fast mode:	$C_b$ = 320 pF, Rb = 1.1 k $\Omega$

<R>



#### IICA serial transfer timing



### 2.6 Analog Characteristics

### <R> 2.6.1 A/D converter characteristics

Classification of A/D converter characteristics

Input channel		Reference Voltage	
	Reference voltage (+) = AVREFP Reference voltage (-) = AVREFM	Reference voltage (+) = VDD Reference voltage (-) = Vss	Reference voltage (+) = VBGR Reference voltage (-) = AVREFM
ANI0 to ANI3	Refer to 2.6.1 (1).	Refer to 2.6.1 (3).	Refer to 2.6.1 (4).
ANI16 to ANI22	Refer to <b>2.6.1 (2)</b> .		
Internal reference voltage	Refer to 2.6.1 (1).		-
Temperature sensor output voltage			

<R> (1) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI2, ANI3, internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{AV}_{REFP} \le \text{VDD} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{AV}_{REFP}, \text{ Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$ 

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall errorNote 1	AINL	10-bit resolution			1.2	±3.5	LSB
		AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>			1.2	$\pm 7.0^{\text{Note 4}}$	LSB
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V\text{DD} \leq 5.5~V$	2.125		39	μs
		Target pin: ANI2, ANI3	$2.7~V \leq V\text{DD} \leq 5.5~V$	3.1875		39	μs
			$1.8~V \leq V\text{DD} \leq 5.5~V$	17		39	μs
				57		95	μs
		10-bit resolution	$3.6~V \leq V\text{DD} \leq 5.5~V$	2.375		39	μs
		Target pin: Internal	$2.7~V \leq V\text{DD} \leq 5.5~V$	3.5625		39	μs
		reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±0.25 ±0.50 <sup>Note 4</sup>	%FSR %FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±0.25 ±0.50 <sup>Note 4</sup>	%FSR %FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution				±2.5	LSB
		AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				$\pm 5.0^{\text{ Note 4}}$	LSB
Differential linearity error	DLE	10-bit resolution				±1.5	LSB
Note 1		AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				$\pm 2.0^{\text{ Note 4}}$	LSB
Analog input voltage	VAIN	ANI2, ANI3		0		AVREFP	V
		Internal reference voltage (2.4 V $\leq$ VDD $\leq$ 5.5 V, HS	V <sub>BGR</sub> Note 5			V	
		Temperature sensor outp (2.4 V $\leq$ VDD $\leq$ 5.5 V, HS	Ň	V <sub>TMPS25</sub> Note 5			

(Notes are listed on the next page.)



Notes	<b>1.</b> Excludes quantization error (±1/2 LSB).
	2. This value is indicated as a ratio (%FSR) to the full-scale value.
<r></r>	<b>3.</b> When $AV_{REFP} < V_{DD}$ , the MAX. values are as follows.
	Overall error: Add $\pm 1.0$ LSB to the MAX. value when AV <sub>REFP</sub> = V <sub>DD</sub> .
	Zero-scale error/Full-scale error: Add $\pm 0.05\%$ FSR to the MAX. value when AV <sub>REFP</sub> = V <sub>DD</sub> .
	Integral linearity error/ Differential linearity error: Add $\pm 0.5$ LSB to the MAX. value when AV <sub>REFP</sub> = V <sub>DD</sub> .
<r></r>	<b>4.</b> Values when the conversion time is set to 57 $\mu$ s (min.) and 95 $\mu$ s (max.).
<r></r>	5. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

<R> (2) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI16 to ANI22

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{AV}_{REFP} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{AV}_{REFP}, \text{ Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$ 

Res						
	a		8		10	bit
	10-bit resolution			1.2	±5.0	LSB
	AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>	V <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>		1.2	$\pm 8.5^{\text{Note}4}$	LSB
CONV	10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.125		39	μs
	Target ANI pin: ANI16 to ANI22	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.1875		39	μs
		$1.8~V \leq V \text{DD} \leq 5.5~V$	17		39	μs
			57		95	μs
ZS	10-bit resolution				±0.35	%FSR
	AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±0.60 <sup>Note 4</sup>	%FSR
EFS	10-bit resolution				±0.35	%FSR
	AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±0.60 <sup>Note 4</sup>	%FSR
LE	10-bit resolution				±3.5	LSB
	AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				$\pm 6.0^{\text{Note 4}}$	LSB
DLE	10-bit resolution				±2.0	LSB
	AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±2.5 Note 4	LSB
/ain	ANI16 to ANI22		0			V
	ZS =S E LE	DNV10-bit resolution Target ANI pin: ANI16 to ANI22ZS10-bit resolution AVREFP = VDD Note 3ES10-bit resolution AVREFP = VDD Note 3E10-bit resolution AVREFP = VDD Note 3LE10-bit resolution AVREFP = VDD Note 3	DNV10-bit resolution Target ANI pin: ANI16 to ANI22 $3.6 V \le V_{DD} \le 5.5 V$ $2.7 V \le V_{DD} \le 5.5 V$ $1.8 V \le V_{DD} \le 5.5 V$ ZS10-bit resolution AVREFP = V_{DD} Note 3 $10$ -bit resolution AVREFP = V_{DD} Note 3E10-bit resolution AVREFP = V_{DD} Note 3LE10-bit resolution AVREFP = V_{DD} Note 3	$\begin{array}{c c} 10-bit \ resolution \\ Target \ ANI \ pin: \ ANI16 \ to \ ANI22 \\ \hline 2.7 \ V \leq V_{DD} \leq 5.5 \ V \\ \hline 2.7 \ V \leq V_{DD} \leq 5.5 \ V \\ \hline 1.8 \ V \leq V_{DD} \leq 5.5 \ V \\ \hline 1.8 \ V \leq V_{DD} \leq 5.5 \ V \\ \hline 17 \\ \hline 57 \\ \hline 27 \\ \hline \\ $	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

<R> <R> 2. This value is indicated as a ratio (%FSR) to the full-scale value.

**3.** When AV<sub>REFP</sub>  $\leq$  V<sub>DD</sub>, the MAX. values are as follows. Overall error: Add ±4.0 LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>. Zero-scale error/Full-scale error: Add ±0.20%FSR to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>. Integral linearity error/ Differential linearity error: Add ±2.0 LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

<R> 4. When the conversion time is set to 57  $\mu$ s (min.) and 95  $\mu$ s (max.).



# <R> (3) When reference voltage (+) = V<sub>DD</sub> (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V<sub>ss</sub> (ADREFM = 0), target pin: ANI0 to ANI3, ANI16 to ANI22, internal reference voltage, and temperature sensor output voltage

Parameter	Symbol	Condition	าร	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution			1.2	±7.0	LSB
					1.2	±10.5 <sup>Note 3</sup>	LSB
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.125		39	μs
		Target pin: ANI0 to ANI3,	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.1875		39	μs
		ANI16 to ANI22	$1.8~V \le V_{DD} \le 5.5~V$	17		39	μs
				57		95	μs
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.375		39	μs
		Target pin: internal reference	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.5625		39	μs
		voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4~\text{V} \leq \text{VDD} \leq 5.5~\text{V}$	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution				±0.60	%FSR
						±0.85 Note 3	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution				±0.60	%FSR
						±0.85 Note 3	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution				±4.0	LSB
						$\pm 6.5$ Note 3	LSB
Differential linearity error Note 1	DLE	10-bit resolution				±2.0	LSB
						±2.5 Note 3	LSB
Analog input voltage	VAIN	ANI0 to ANI3, ANI16 to ANI2	2	0		VDD	V
		Internal reference voltage (2.4 V $\leq$ VDD $\leq$ 5.5 V, HS (high	n-speed main) mode)		VBGR Note 4		V
		Temperature sensor output v (2.4 V $\leq$ VDD $\leq$ 5.5 V, HS (high	•	,	VTMPS25 Note	4	V

(T <sub>A</sub> = -40 to +85°C, '	$1.8 V \le V DD \le 5.5 V, V ss$	= 0 V, Reference voltage	ge(+) = Vdd, F	Reference voltage (–) = Vss)

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

**3.** When the conversion time is set to 57  $\mu$ s (min.) and 95  $\mu$ s (max.).

<R> 4. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

<R>



### <R> (4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM (ADREFM = 1), target pin: ANI0, ANI2, ANI3, and ANI16 to ANI22

(T<sub>A</sub> = -40 to +85°C, 2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = 0 V, Reference voltage (+) = V<sub>BGR</sub><sup>Note 3</sup>, Reference voltage (-) = AV<sub>REFM</sub><sup>Note 4</sup> = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		bit
Conversion time	<b>t</b> CONV	8-bit resolution	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	8-bit resolution			±0.60	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	8-bit resolution			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution			±1.0	LSB
Analog input voltage	VAIN		0		$V_{\text{BGR}}^{\text{ Note 3}}$	V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

#### 3. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

<R> <R>

**4.** When reference voltage (-) = Vss, the MAX. values are as follows.

Zero-scale error: Add  $\pm 0.35\%$ FSR to the MAX. value when reference voltage (–) = AV<sub>REFM</sub>. Integral linearity error: Add  $\pm 0.5$  LSB to the MAX. value when reference voltage (–) = AV<sub>REFM</sub>. Differential linearity error: Add  $\pm 0.2$  LSB to the MAX. value when reference voltage (–) = AV<sub>REFM</sub>.



### 2.6.2 Temperature sensor/internal reference voltage characteristics

>	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
	Temperature sensor output voltage	VTMPS25	Setting ADS register = 80H, TA = +25°C		1.05		V
	Internal reference voltage	VBGR	Setting ADS register = 81H	1.38	1.45	1.50	V
	Temperature coefficient	Fvtmps	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
ſ	Operation stabilization wait time	tamp		5			μs

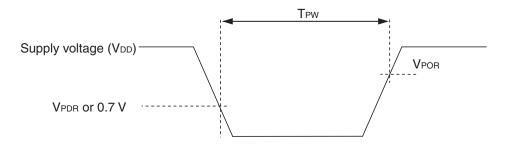
### (T<sub>A</sub> = -40 to +85°C, 2.4 V $\leq$ V<sub>DD</sub> $\leq$ 5.5 V, V<sub>SS</sub> = 0 V, HS (high-speed main) mode

### 2.6.3 POR circuit characteristics

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

<r></r>	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
	Detection voltage	VPOR	Power supply rise time	1.47	1.51	1.55	V
		VPDR	Power supply fall time	1.46	1.50	1.54	V
	Minimum pulse width Note	Tpw		300			μs

<R> Note Minimum time required for a POR reset when V<sub>DD</sub> exceeds below V<sub>PDR</sub>. This is also the minimum time required for a POR reset from when V<sub>DD</sub> exceeds below 0.7 V to when V<sub>DD</sub> exceeds V<sub>POR</sub> while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).





### 2.6.4 LVD circuit characteristics

# LVD Detection Voltage of Reset Mode and Interrupt Mode (TA = -40 to +85°C, VPDR $\leq$ VDD $\leq$ 5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Uı
Detection supply voltage	VLVD0	Power supply rise time	3.98	4.06	4.14	Ņ
		Power supply fall time	3.90	3.98	4.06	,
	VLVD1	Power supply rise time	3.68	3.75	3.82	``
		Power supply fall time	3.60	3.67	3.74	,
	VLVD2	Power supply rise time	3.07	3.13	3.19	,
		Power supply fall time	3.00	3.06	3.12	,
	VLVD3	Power supply rise time	2.96	3.02	3.08	
		Power supply fall time	2.90	2.96	3.02	,
	VLVD4	Power supply rise time	2.86	2.92	2.97	
		Power supply fall time	2.80	2.86	2.91	
	VLVD5	Power supply rise time	2.76	2.81	2.87	
		Power supply fall time	2.70	2.75	2.81	
	VLVD6	Power supply rise time	2.66	2.71	2.76	
		Power supply fall time	2.60	2.65	2.70	
	VLVD7	Power supply rise time	2.56	2.61	2.66	
		Power supply fall time	2.50	2.55	2.60	
	VLVD8	Power supply rise time	2.45	2.50	2.55	
		Power supply fall time	2.40	2.45	2.50	
	VLVD9	Power supply rise time	2.05	2.09	2.13	
		Power supply fall time	2.00	2.04	2.08	
	VLVD10	Power supply rise time	1.94	1.98	2.02	
		Power supply fall time	1.90	1.94	1.98	
	VLVD11	Power supply rise time	1.84	1.88	1.91	,
		Power supply fall time	1.80	1.84	1.87	
Minimum pulse width	t∟w		300			Ļ
Detection delay time					300	μ



### <R> LVD detection voltage of interrupt & reset mode $(T_{4} = -40 \text{ to } \pm 85^{\circ}\text{C}, \text{ Varge } \le V_{20} \le 5.5 \text{ V}, \text{ Varge } = 0. \text{ V})$

Parameter	Symbol		Con	ditions	MIN.	TYP.	MAX.	Unit
Interrupt and reset	VLVDB0	VPOC2, VPOC1, VPOC0 = 0, 0, 1, falling reset voltage				1.84	1.87	V
mode	VLVDB1		LVIS1, LVIS0 = 1, 0	Rising reset release voltage	1.94	1.98	2.02	V
				Falling interrupt voltage	1.90	1.94	1.98	V
	VLVDB2		LVIS1, LVIS0 = 0, 1	Rising reset release voltage	2.05	2.09	2.13	V
				Falling interrupt voltage	2.00	2.04	2.08	V
	VLVDB3		LVIS1, LVIS0 = 0, 0	Rising reset release voltage	3.07	3.13	3.19	V
				Falling interrupt voltage	3.00	3.06	3.12	V
	VLVDC0	Vpoc2,	VPOC1, VPOC0 = 0, 1, 0, fal	ling reset voltage	2.40	2.45	2.50	V
	VLVDC1		LVIS1, LVIS0 = 1, 0	Rising reset release voltage	2.56	2.61	2.66	V
				Falling interrupt voltage	2.50	2.55	2.60	V
	VLVDC2		LVIS1, LVIS0 = 0, 1	Rising reset release voltage	2.66	2.71	2.76	V
				Falling interrupt voltage	2.60	2.65	2.70	V
	VLVDC3		LVIS1, LVIS0 = 0, 0	Rising reset release voltage	3.68	3.75	3.82	V
				Falling interrupt voltage	3.60	3.67	3.74	V
	VLVDD0	Vpoc2,	VPOC1, VPOC1 = 0, 1, 1, fal	ling reset voltage	2.70	2.75	2.81	V
	VLVDD1		LVIS1, LVIS0 = 1, 0	Rising reset release voltage	2.86	2.92	2.97	V
				Falling interrupt voltage	2.80	2.86	2.91	V
	VLVDD2		LVIS1, LVIS0 = 0, 1	Rising reset release voltage	2.96	3.02	3.08	V
				Falling interrupt voltage	2.90	2.96	3.02	V
	VLVDD3		LVIS1, LVIS0 = 0, 0	Rising reset release voltage	3.98	4.06	4.14	V
				Falling interrupt voltage	3.90	3.98	4.06	V

### <R> 2.6.5 Power supply voltage rising slope characteristics

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{ Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

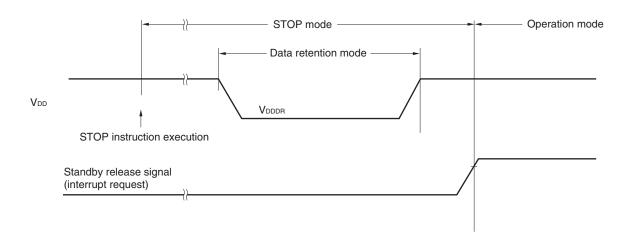
Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V<sub>DD</sub> reaches the operating voltage range shown in 2.4 AC Characteristics.



### 2.7 Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 <sup>Note</sup>		5.5	V

**Note** The value depends on the POR detection voltage. When the voltage drops, the data is retained before a POR reset is affected, but data is not retained when a POR reset is affected.



### 2.8 Flash Memory Programming Characteristics

(	$T_{A} = -40 \text{ to}$	+85°C. 1.	8 V ≤ V	$DD \le 5.5 V.$	Vss = 0 V)

· · · · · ·		· · ·					
Parameter	Symbol	Condi	Conditions		TYP.	MAX.	Unit
System clock frequency	fclк			1		24	MHz
Code flash memory rewritable times Notes 1, 2, 3	Cerwr	Retained for 20 years	T <sub>A</sub> = 85°C	1,000			Times
Data flash memory rewritable times		Retained for 1 year	T <sub>A</sub> = 25°C		1,000,000		
Notes 1, 2, 3		Retained for 5 years	T <sub>A</sub> = 85°C	100,000			
		Retained for 20 years	T <sub>A</sub> = 85°C	10,000			

**Notes 1.** 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library
- **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.



### 2.9 Dedicated Flash Memory Programmer Communication (UART)

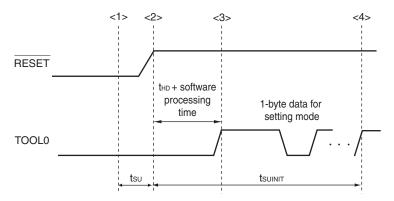
	0.0	•, • 33 = • • •				
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

### 2.10 Timing of Entry to Flash Memory Programming Modes

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

R>	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
	Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset are released before external reset release			100	ms
	Time to release the external reset after the TOOL0 pin is set to the low level	tsu	POR and LVD reset are released before external reset release	10			μs
	Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	tнo	POR and LVD reset are released before external reset release	1			ms



<R>

- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.

<R>

- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.
- **Remark** tsuinit: Communication for the initial setting must be completed within 100 ms after the external reset is released during this period.
  - $t_{\text{SU:}}$  Time to release the external reset after the TOOL0 pin is set to the low level
- <R> thD: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)



### <R> 3. ELECTRICAL SPECIFICATIONS (G: $T_A = -40$ to +105°C)

This chapter describes the electrical specifications for the products "G: Industrial applications (T<sub>A</sub> = -40 to +105°C)".

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
  - 2. The pins mounted depend on the product. Refer to 2.1 Port Functions to 2.2.1 Functions for each product in the RL78/G12 User's Manual Hardware.
  - Please contact Renesas Electronics sales office for derating of operation under T<sub>A</sub> = +85°C to +105°C.
     Derating is the systematic reduction of load for the sake of improved reliability.

There are following differences between the products "G: Industrial applications ( $T_A = -40$  to  $+105^{\circ}$ C)" and the products "A: Consumer applications, and D: Industrial applications".

Parameter	Apr	lication
	G: Industrial applications	
Operating ambient temperature	T <sub>A</sub> = -40 to +85°C	T <sub>A</sub> = -40 to +105°C
Operating mode	HS (high-speed main) mode:	HS (high-speed main) mode only:
Operating voltage range	2.7 V $\leq$ V_{DD} $\leq$ 5.5 V@1 MHz to 24 MHz	$2.7~V \leq V_{\text{DD}} \leq 5.5~V@1~\text{MHz}$ to 24 MHz
	2.4 V $\leq$ V_{DD} $\leq$ 5.5 V@1 MHz to 16 MHz	2.4 V $\leq$ V_{DD} $\leq$ 5.5 V@1 MHz to 16 MHz
	LS (low-speed main) mode:	
	1.8 V $\leq$ V_{DD} $\leq$ 5.5 V@1 MHz to 8 MHz	
High-speed on-chip oscillator clock	R5F102 products, 1.8 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V:	R5F102 products, 2.4 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V:
accuracy	±1.0%@ T <sub>A</sub> = -20 to +85°C	±2.0%@ T <sub>A</sub> = +85 to +105°C
	±1.5%@ T <sub>A</sub> = -40 to -20°C	±1.0%@ T <sub>A</sub> = -20 to +85°C
	R5F103 products, 1.8 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V:	±1.5%@ T <sub>A</sub> = -40 to -20°C
	±5.0%@ T <sub>A</sub> = -40 to +85°C	
Serial array unit	UART	UART
	CSI: fcLk/2 (supporting 12 Mbps), fcLk/4	CSI: fclk/4
	Simplified I <sup>2</sup> C communication	Simplified I <sup>2</sup> C communication
Voltage detector	Rise detection voltage: 1.88 V to 4.06 V	Rise detection voltage: 2.61 V to 4.06 V
	(12 levels)	(8 levels)
	Fall detection voltage: 1.84 V to 3.98 V	Fall detection voltage: 2.55 V to 3.98 V
	(12 levels)	(8 levels)

Remark The electrical characteristics of the products G: Industrial applications (T<sub>A</sub> = -40 to +105°C) are different from those of the products "A: Consumer applications, and D: Industrial applications". For details, refer to **3.1** to **3.10**.



### 3.1 Absolute Maximum Ratings

### Absolute Maximum Ratings (T<sub>A</sub> = 25°C)

Parameter	Symbols		Conditions	Ratings	Unit
Supply Voltage	VDD			-0.5 to + 6.5	V
REGC terminal input voltage <sup>Note1</sup>	VIREGC	REGC		-0.3 to +2.8 and -0.3 to V <sub>DD</sub> + 0.3 <sub>Note 2</sub>	V
Input Voltage	VI1	Other than P60, F	261	-0.3 to V <sub>DD</sub> + 0.3 <sup>Note 3</sup>	V
	V <sub>I2</sub>	P60, P61 (N-ch o	pen drain)	-0.3 to 6.5	V
Output Voltage	Vo			-0.3 to V <sub>DD</sub> + 0.3 <sup>Note 3</sup>	V
Analog input voltage	VAI	20, 24-pin produc	pin products: ANI0 to ANI3, ANI16 to ANI22 products: ANI0 to ANI3, ANI16 to ANI19 AVREF(+)+0 0 Other than P20 to P23 f all pins All the terminals other than P20 to P23 -1		V
		30-pin products: A	ANIO to ANI3, ANI16 to ANI19	and -0.3 to AVREF(+)+0.3 <sup>Notes 3, 4</sup>	
Output current, high	Іон1	Per pin	Other than P20 to P23	-40	mA
		Total of all pins	All the terminals other than P20 to P23	-170	mA
			20-, 24-pin products: P40 to P42	-70	mA
			30-pin products: P00, P01, P40, P120		
			20-, 24-pin products: P00 to P03 <sup>Note 5</sup> , P10 to P14 30-pin products: P10 to P17, P30, P31, P50, P51, P147	-100	mA
	Іон2	Per pin	P20 to P23	-0.5	mA
		Total of all pins		-2	mA
Output current, low	Iol1	Per pin	Other than P20 to P23	40	mA
		Total of all pins	All the terminals other than P20 to P23	170	mA
			20-, 24-pin products: P40 to P42 30-pin products: P00, P01, P40, P120	70	mA
			20-, 24-pin products: P00 to P03 <sup>Note 5</sup> , P10 to P14, P60, P61 30-pin products: P10 to P17, P30, P31, P50, P51, P60, P61, P147	100	mA
	IOL2	Per pin	P20 to P23	1	mA
		Total of all pins		5	mA
Operating ambient temperature	TA			-40 to +105	°C
Storage temperature	Tstg			-65 to +150	°C

Notes 1. 30-pin product only.

- 2. Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F). This value determines the absolute maximum rating of the REGC pin. Do not use it with voltage applied.
- 3. Must be 6.5 V or lower.
- 4. Do not exceed AVREF (+) + 0.3 V in case of A/D conversion target pin.
- **5.** 24-pin products only.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
  - **2.** AVREF (+): + side reference voltage of the A/D converter.
  - 3. Vss: Reference voltage



### 3.2 Oscillator Characteristics

3.2.1 X1 oscillator characteristics

### $(T_A = -40 \text{ to } +105^{\circ}C, 2.4 \text{ V} \le \text{V}_{DD} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	Ceramic resonator /	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	1.0		20.0	MHz
frequency (fx) <sup>Note</sup>	crystal oscillator	$2.4~V \leq V_{\text{DD}} < 2.7~V$	1.0		8.0	

**Note** Indicates only permissible oscillator frequency ranges. Refer to AC Characteristics for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

- Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.
- Remark When using the X1 oscillator, refer to 5.4 System Clock Oscillator in the RL78/G12 User's Manual Hardware.

### 3.2.2 On-chip oscillator characteristics

#### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Oscillators	Parameters	Con	ditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency <sup>Notes 1, 2</sup>	fін			1		24	MHz
High-speed on-chip oscillator		R5F102 products	$T_A = -20 \text{ to } +85^{\circ}\text{C}$	-1.0		+1.0	%
clock frequency accuracy			$T_A$ = -40 to -20°C	-1.5		+1.5	%
			T <sub>A</sub> = +85 to +105°C	-2.0		+2.0	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

**Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H) and bits 0 to 2 of HOCODIV register.

2. This only indicates the oscillator characteristics. Refer to AC Characteristics for instruction execution time.



### 3.3 DC Characteristics

### 3.3.1 Pin characteristics

Γ <sub>A</sub> = -40 to +105°C,	2.4 V ≤	$V_{DD} \leq 5.5 \text{ V}, \text{ Vss} = 0 \text{ V})$					(1/4)
Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, high <sup>Note 1</sup>	Іон1	20-, 24-pin products: Per pin for P00 to P03 <sup>Note 4</sup> , P10 to P14, P40 to P42 30-pin products: Per pin for P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147				-3.0 Note 2	mA
		20-, 24-pin products:	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$			-9.0	mA
		Total of P40 to P42	$2.7~V \leq V_{\text{DD}} < 4.0~V$			-6.0	mA
		30-pin products: Total of P00, P01, P40, P120 (When duty $\leq$ 70% <sup>Note 3</sup> )	$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2.7 \text{ V}$			-4.5	mA
		20-, 24-pin products:	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$			-27.0	mA
		Total of P00 to P03 <sup>Note 4</sup> , P10 to P14	$2.7~V \leq V_{\text{DD}} < 4.0~V$			-18.0	mA
		30-pin products: Total of P10 to P17, P30, P31, P50, P51, P147 (When duty $\leq$ 70% <sup>Note 3</sup> )	$2.4 \text{ V} \le \text{V}_{\text{DD}} \le 2.7 \text{ V}$			-10.0	mA
		Total of all pins (When duty $\leq 70\%^{Note 3}$ )				-36.0	mA
	Іон2	Per pin for P20 to P23				-0.1	mA
		Total of all pins				-0.4	mA

Notes 1. value of current at which the device operation is guaranteed even if the current flows from the VDD pin to an output pin.

- 2. However, do not exceed the total current value.
- 3. The output current value under conditions where the duty factor  $\leq$  70%. If duty factor > 70%: The output current value can be calculated with the following expression (where n represents the duty factor as a percentage).
  - Total output current of pins =  $(I_{OH} \times 0.7)/(n \times 0.01)$ <Example> Where n = 80% and IoH = -10.0 mA

Total output current of pins =  $(-10.0 \times 0.7)/(80 \times 0.01) \approx -8.7$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

- 4. 24-pin products only.
- Caution P10 to P12 and P41 for 20-pin products, P01, P10 to P12, and P41 for 24-pin products, and P00, P10 to P15, P17, and P50 for 30-pin products do not output high level in N-ch open-drain mode.
- Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



	1	$V_{DD} \leq 5.5 \text{ V}, \text{ Vss} = 0 \text{ V})$			1		(2/4
Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low <sup>Note 1</sup>	Iol1	20-, 24-pin products: Per pin for P00 to P03 <sup>Note 4</sup> , P10 to P14, P40 to P42 30-pin products: Per pin for P00, P01, P10 to P17, P30,		MIN. TYP.	8.5 Note 2	mA	
		P31, P40, P50, P51, P120, P147					
		Per pin for P60, P61				15.0 Note 2	mA
		20-, 24-pin products:	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$			25.5	mA
		Total of P40 to P42	$2.7~V \leq V_{\text{DD}} < 4.0~V$			9.0	mA
		30-pin products: Total of P00, P01, P40, P120 (When duty $\leq$ 70% <sup>Note 3</sup> )	$2.4~V \leq V_{DD} < 2.7~V$			1.8	mA
		20-, 24-pin products:	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$			40.0	mA
		Total of P00 to P03 <sup>Note 4</sup> , P10 to P14, P60, P61	$2.7~V \leq V_{\text{DD}} < 4.0~V$			27.0	mA
		P 10 to P 14, P60, P61 30-pin products: Total of P10 to P17, P30, P31, P50, P51, P60, P61, P147 (When duty ≤ 70% <sup>Note 3</sup> )	$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2.7 \text{ V}$			5.4	mA
		Total of all pins (When duty $\leq 70\%^{Note 3}$ )				65.5	mA
	IOL2	Per pin for P20 to P23				0.4	mA
		Total of all pins				1.6	mA

#### 40500 0 4 14 4 14 \_ \_ . . . . **~** \ \ \ . .

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the Vss pin.

2. However, do not exceed the total current value.

3. The output current value under conditions where the duty factor  $\leq$  70%.

If duty factor > 70%: The output current value can be calculated with the following expression (where n represents the duty factor as a percentage).

• Total output current of pins =  $(I_{OL} \times 0.7)/(n \times 0.01)$ 

<Example> Where n = 80% and IoL = 10.0 mA

Total output current of pins =  $(10.0 \times 0.7)/(80 \times 0.01) \cong 8.7$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

- 4. 24-pin products only.
- Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Parameter	Symbol	Condition	S	MIN.	TYP.	MAX.	Unit
Input voltage, high	VIH1	Normal input buffer		0.8Vdd		Vdd	V
		20-, 24-pin products: P00 to P0 P40 to P42	)3 <sup>№te 2</sup> , P10 to P14,				
		30-pin products: P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147					
	VIH2	TTL input buffer	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	2.2		VDD	V
		20-, 24-pin products: P10, P11	$3.3~V \leq V_{\text{DD}} < 4.0~V$	2.0		Vdd	V
		30-pin products: P01, P10, P11, P13 to P17	$2.4~V \leq V_{\text{DD}} < 3.3~V$	1.5		Vdd	V
	Vінз	Normal input buffer		0.7Vdd		Vdd	V
		P20 to P23					
	VIH4	P60, P61				6.0	V
	VIH5	P121, P122, P125 <sup>Note 1</sup> , P137, EXCLK, RESET		0.8VDD		Vdd	V
Input voltage, low	VIL1	Normal input buffer		0		0.2V <sub>DD</sub>	V
		20-, 24-pin products: P00 to P0 P40 to P42	)3 <sup>Note 2</sup> , P10 to P14,				
		30-pin products: P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147					
	VIL2	TTL input buffer	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	0		0.8	V
		20-, 24-pin products: P10, P11	$3.3 \text{ V} \le \text{V}_{\text{DD}} < 4.0 \text{ V}$	0		0.5	V
		30-pin products: P01, P10, P11, P13 to P17	$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 3.3 \text{ V}$	0		0.32	V
	VIL3	P20 to P23		0		0.3VDD	V
	VIL4	P60, P61		0		0.3VDD	V
	VIL5	P121, P122, P125 <sup>Note 1</sup> , P137,	EXCLK, RESET	0		0.2V <sub>DD</sub>	V
Output voltage, high	Vон1	20-, 24-pin products: P00 to P03 <sup>Note 2</sup> , P10 to P14,	$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -3.0 \ \text{mA} \end{array}$	V <sub>DD</sub> -0.7			V
		P40 to P42 30-pin products:	$2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V},$ IOH1 = -2.0 mA	V <sub>DD</sub> -0.6			V
		P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147	$2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OH1}} = -1.5 \text{ mA}$	VDD-0.5			V
	Vон2	P20 to P23	Іон2 <b>=</b> –100 <i>µ</i> А	VDD-0.5			V

### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Notes 1. 20, 24-pin products only.

2. 24-pin products only.

Caution The maximum value of V<sub>I</sub> of pins P10 to P12 and P41 for 20-pin products, P01, P10 to P12, and P41 for 24-pin products, and P00, P10 to P15, P17, and P50 for 30-pin products is VDD even in N-ch opendrain mode.

High level is not output in the N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

(4/4)

Parameter	Symbol		Conditio	ns MIN. T			TYP. MAX.		
Output voltage, low	V <sub>OL1</sub>	20-, 24-pin products: P00 to P03 <sup>Note</sup> , P10 to P14, P40 to P42 30-pin products: P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147		$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 8.5 \ mA \end{array} \end{array} \label{eq:eq:electropy}$			0.7	V	
				$\begin{array}{l} 2.7 \ \text{V} \leq \text{V}_{\text{DD}} \leq 5.5 \ \text{V}, \\ I_{\text{OL1}} = 3.0 \ \text{mA} \end{array}$			0.6	V	
				$2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V},$ lol1 = 1.5 mA			0.4	V	
				$\begin{array}{l} 2.4 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 0.6 \ \text{mA} \end{array} \end{array} \label{eq:eq:electropy}$			0.4	V	
	Vol2	P20 to P23		lol2 = 400 μA			0.4	V	
	Vols	P60, P61		$4.0 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V},$ Iol1 = 15.0 mA			2.0	V	
				$\begin{array}{l} 4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 5.0 \ \text{mA} \end{array} \end{array} \label{eq:VDD}$			0.4	V	
				$\begin{array}{l} 2.7 \ \text{V} \leq \text{V}_{\text{DD}} \leq 5.5 \ \text{V}, \\ \text{I}_{\text{OL1}} = 3.0 \ \text{mA} \end{array}$			0.4	V	
				$\begin{array}{l} 2.4 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 2.0 \ \text{mA} \end{array} \end{array} \label{eq:VDD}$			0.4	V	
Input leakage current, high	Ілні	Other than P121, P122	VI = VDD				1	μA	
	Ілна	P121, P122 (X1, X2/EXCLK)	VI = VDD	Input port or external clock input			1	μA	
				When resonator connected			10	μA	
Input leakage current, low	Ilil1	Other than P121, P122	VI = VSS				-1	μA	
	Ilil2	P121, P122 (X1, X2/EXCLK)	VI = VSS	Input port or external clock input			-1	μA	
			When resonator connected			-10	μA		
On-chip pull-up resistance	Ru         20-, 24-pin products: P00 to P03 <sup>Note</sup> , P10 to P14, P40 to P42, P125, RESET           30-pin products: P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147		0 to P14,	VI = VSS, input port	10	20	100	kΩ	
			P31, P40,						

Note 24-pin products only.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



(1/2)

### 3.3.2 Supply current characteristics

### (1) 20-, 24-pin products

(1A = 4010	$\pm 100 O_{2}$	2.4 4 3 4	JD ≤ <b>3.3 v</b> , vss -	••••						(1/4)
Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply IDD1 current <sup>Note 1</sup>		Operating	HS (High-speed	f⊩ = 24 MHz <sup>Note 3</sup>	Basic	V <sub>DD</sub> = 5.0 V		1.5		mA
	mode	main) mode <sup>Note 4</sup>	ain) mode Note 4 operation $V_{DD} = 3.0 V$		1.5					
			1		Normal operation	V <sub>DD</sub> = 5.0 V		3.3	5.3	mA
						V <sub>DD</sub> = 3.0 V		3.3	5.3	
				$\begin{split} f_{IH} &= 16 \; MHz^{\text{Note 3}} \\ f_{MX} &= 20 \; MHz^{\text{Note 2}}, \\ V_{DD} &= 5.0 \; V \\ f_{MX} &= 20 \; MHz^{\text{Note 2}}, \end{split}$		V <sub>DD</sub> = 5.0 V		2.5	3.9	mA
						V <sub>DD</sub> = 3.0 V		2.5	3.9	
					,	Square wave input		2.8	4.7	mA
						Resonator connection		3.0	4.8	
						Square wave input		2.8	4.7	mA
			V <sub>DD</sub> = 3.0 V		Resonator connection		3.0	4.8		
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.8	2.8	mA
			$V_{DD} = 5.0 V$ f <sub>MX</sub> = 10 MHz <sup>Note 2</sup> ,	Resonator connection		1.8	2.8			
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.8	2.8	mA
				V <sub>DD</sub> = 3.0 V		Resonator connection		1.8	2.8	

**Notes 1.** Total current flowing into V<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub> or V<sub>SS</sub>. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

- 2. When high-speed on-chip oscillator clock is stopped.
- **3.** When high-speed system clock is stopped
- 4. Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS(High speed main) mode:  $V_{DD}$  = 2.7 V to 5.5 V @1 MHz to 24 MHz V<sub>DD</sub> = 2.4 V to 5.5 V @1 MHz to 16 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fil: high-speed on-chip oscillator clock frequency
  - **3.** Temperature condition of the TYP. value is  $T_A = 25^{\circ}C$ .



(0/0)

### (1) 20-, 24-pin products

(T∧ = –40 to	+105°C, 2	2.4 V ≤ `	$V$ DD $\leq$ 5.5 V, Vss	= 0 V)					(2/2)
Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	DD2 Note 2	HALT	HS (High-speed main) mode <sup>Note 6</sup>	f <sub>IH</sub> = 24 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		440	2230	μA
current <sup>Note 1</sup>		mode			V <sub>DD</sub> = 3.0 V		440	2230	
				f⊪ = 16 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		400	1650	μA
					V <sub>DD</sub> = 3.0 V		400	1650	
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1900	μA
				V <sub>DD</sub> = 5.0 V	Resonator connection		450	2000	
				$f_{MX} = 20 \text{ MHz}^{\text{Note 3}},$ $V_{\text{DD}} = 3.0 \text{ V}$	Square wave input		280	1900	μA
					Resonator connection		450	2000	
					Square wave input		190	1010	μA
					Resonator connection		260	1090	
					Square wave input		190	1010	
					Resonator connection		260	1090	
	DD3 Note 5	STOP	T <sub>A</sub> = -40°C				0.19	0.50	μA
		mode	T <sub>A</sub> = +25°C				0.24	0.50	
			T <sub>A</sub> = +50°C				0.32	0.80	
			T <sub>A</sub> = +70°C				0.48	1.20	
			T <sub>A</sub> = +85°C				0.74	2.20	
			T <sub>A</sub> = +105°C				1.50	10.20	

Notes 1. Total current flowing into VDD, including the input leakage current flowing when the level of the input pin is fixed to VDD or VSS. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

- 2. During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator clock is stopped.
- 4. When high-speed system clock is stopped.
- 5. Not including the current flowing into the 12-bit interval timer and watchdog timer.
- 6. Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS (High speed main) mode: VDD = 2.7 V to 5.5 V @1 MHz to 24 MHz VDD = 2.4 V to 5.5 V @1 MHz to 16 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Except temperature condition of the TYP. value is T<sub>A</sub> = 25°C, other than STOP mode



### (2) 30-pin products

$(T_{A} = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ V}_{\text{SS}} = 0 \text{ V}) $ (1)										(1/2)
Parameter	Symbol	Conditions					MIN.	TYP.	MAX.	Unit
Supply		Operating	HS (High-speed	f⊩ = 24 MHz <sup>Note 3</sup>	4 MHz <sup>Note 3</sup> Basic	V <sub>DD</sub> = 5.0 V		1.5		mA
current <sup>Note 1</sup>	fir	-	operation	V <sub>DD</sub> = 3.0 V		1.5				
			Normal	V <sub>DD</sub> = 5.0 V		3.7	5.8	mA		
			operation	V <sub>DD</sub> = 3.0 V		3.7	5.8			
		$f_{\text{IH}} = 16 \text{ MHz}^{\text{Note 3}}$ $f_{\text{MX}} = 20 \text{ MHz}^{\text{Note 2}},$		V <sub>DD</sub> = 5.0 V		2.7	4.2	mA		
				V <sub>DD</sub> = 3.0 V		2.7	4.2			
				Square wave input		3.0	4.9	mA		
				$V_{DD} = 5.0 V$ f <sub>MX</sub> = 20 MHz <sup>Note 2</sup> , V <sub>DD</sub> = 3.0 V		Resonator connection		3.2	5.0	
						Square wave input		3.0	4.9	mA
						Resonator connection		3.2	5.0	
			$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.9	2.9	mA	
		V <sub>DD</sub> = 5.0 V		Resonator connection		1.9	2.9			
			$f_{MX}$ = 10 MHz <sup>Note 2</sup> ,		Square wave input		1.9	2.9	mA	
	V <sub>DD</sub> = 3.0 V		Resonator connection		1.9	2.9				

Notes 1. Total current flowing into VDD, including the input leakage current flowing when the level of the input pin is fixed to VDD or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

- 2. When high-speed on-chip oscillator clock is stopped.
- 3. When high-speed system clock is stopped
- 4. Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS(High speed main) mode: VDD = 2.7 V to 5.5 V @1 MHz to 24 MHz VDD = 2.4 V to 5.5 V @1 MHz to 16 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - **3.** Temperature condition of the TYP. value is  $T_A = 25^{\circ}C$ .



(2/2)

### (2) 30-pin products

$(T_A = -40 \text{ to } +105^{\circ}\text{C}.$	$2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ V}_{\text{SS}} = 0 \text{ V}$
(	

(1 = -40  to)	+105°C,	2.4 V ≤ Vi	oo ≤ 5.5 V, Vss =	= U V)					(2/2)
Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	IDD2 Note 2	HALT	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 4</sup>	MHz <sup>Note 4</sup> V <sub>DD</sub> = 5.0 V		440	2300	μA
current <sup>Note 1</sup>		mode	main) mode <sup>Note 6</sup>		V <sub>DD</sub> = 3.0 V		440	2300	
				f <sub>IH</sub> = 16 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		400	1700	μA
					V <sub>DD</sub> = 3.0 V		400	1700	
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1900	μA
				V <sub>DD</sub> = 5.0 V	Resonator connection		450	2000	
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> , V <sub>DD</sub> = 3.0 V	Square wave input		280	1900	μA
					Resonator connection		450	2000	
				$f_{MX} = 10 \text{ MHz}^{Note 3},$ $V_{DD} = 5.0 \text{ V}$ $f_{MX} = 10 \text{ MHz}^{Note 3},$ $V_{DD} = 3.0 \text{ V}$	Square wave input		190	1020	μA
					Resonator connection		260	1100	
					Square wave input		190	1020	μA
					Resonator connection		260	1100	
	IDD3 Note 5	STOP	$P \qquad T_A = -40^{\circ}C$			0.18	0.50	μA	
		mode	$T_A = +25^{\circ}C$ $T_A = +50^{\circ}C$ $T_A = +70^{\circ}C$				0.23	0.50	
							0.30	1.10	
							0.46	1.90	
			T <sub>A</sub> = +85°C				0.75	3.30	
			T <sub>A</sub> = +105°C				2.94	15.30	

**Notes 1.** Total current flowing into V<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub> or V<sub>SS</sub>. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

- **2.** During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator clock is stopped.
- 4. When high-speed system clock is stopped.
- 5. Not including the current flowing into the 12-bit interval timer and watchdog timer.
- 6. Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS (High speed main) mode:  $V_{DD} = 2.7 V$  to 5.5 V @1 MHz to 24 MHz  $V_{DD} = 2.4 V$  to 5.5 V @1 MHz to 16 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Except STOP mode, temperature condition of the TYP. value is  $T_A = 25^{\circ}C$ .



### (3) Peripheral functions (Common to all products)

### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Low-speed onchip oscillator operating current	IFIL Note 1				0.20		μA
12-bit interval timer operating current	ТМКА Notes 1, 2, 3				0.02		μA
Watchdog timer operating current	IWDT Notes 1, 2, 4	fı∟ = 15 kHz			0.22		μA
A/D converter	IADC	When conversion	Normal mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 5.0 V		1.30	1.70	mA
operating current	Notes 1, 5	at maximum speed	Low voltage mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 3.0 V		0.50	0.70	mA
A/D converter reference voltage operating current	IADREF Note 1				75.0		μA
Temperature sensor operating current	ITMPS Note 1				75.0		μA
LVD operating current	ILVD Notes 1, 6				0.08		μA
Self-programming operating current	IFSP Notes 1, 8				2.00	12.20	mA
BGO operating current	IBGO Notes 1, 7				2.00	12.20	mA
SNOOZE operating	Isnoz	ADC operation	The mode is performed Note 9		0.50	1.10	mA
current	current Note 1		The A/D conversion operations are performed, Low voltage mode, $AV_{REFP}$ = $V_{DD}$ = 3.0 V		1.20	2.04	mA
		CSI/UART operation	1		0.70	1.54	mA

Notes 1. Current flowing to the VDD.

- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3, and IFIL and ITMKA when the 12-bit interval timer operates.
- 4. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer operates.
- 5. Current flowing only to the A/D converter. The current value of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- 6. Current flowing only to the LVD circuit. The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit operates.
- 7. Current flowing only during data flash rewrite.
- **8.** Current flowing only during self programming.
- 9. For shift time to the SNOOZE mode, see 17.3.3 SNOOZE mode in the RL78/G12 User's Manual Hardware.

Remarks 1. fil: Low-speed on-chip oscillator clock frequency

**2.** Temperature condition of the TYP. value is  $T_A = 25^{\circ}C$ 



## 3.4 AC Characteristics

## $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

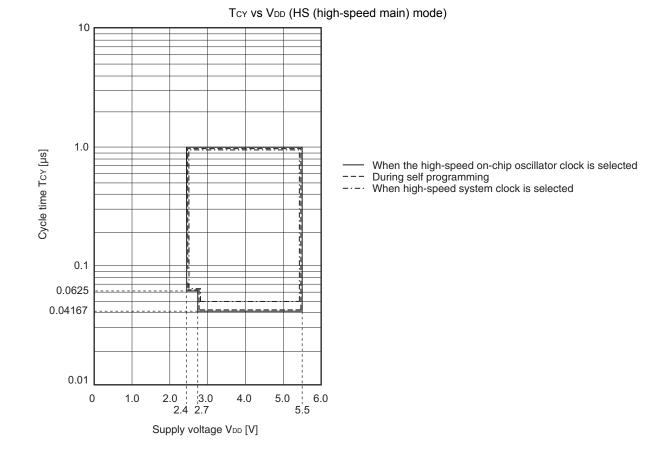
Items	Symbol		Condition	S	MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Тсч	Main system	HS (High-	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	0.04167		1	μs
instruction execution time)		clock (fmain) operation	speed main) mode	$2.4~\text{V} \leq \text{V}_\text{DD} < 2.7~\text{V}$	0.0625		1	μs
		During self	HS (High-	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	0.04167		1	μs
		programming	speed main) mode	$2.4~V \leq V_{\text{DD}} < 2.7~V$	0.0625		1	μs
External main system clock	fEX	$2.7 V \le V_{DD} \le 5.$	.5 V		1.0		20.0	MHz
frequency		$2.4~V \leq V_{\text{DD}} < 2$	.7 V		1.0		16.0	MHz
External main system clock	texh, texl	$2.7~V \leq V_{\text{DD}} \leq 5$	.5 V		24			ns
input high-level width, low- level width		$2.4 V \le V_{DD} < 2.4$	$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2.7 \text{ V}$					ns
TI00 to TI07 input high-level width, low-level width	t⊓н, t⊤∟				1/fмск + 10			ns
TO00 to TO07 output	fто	$4.0~V \le V_{\text{DD}} \le 5$	.5 V				12	MHz
frequency		$2.7 V \leq V_{DD} < 4.$	.0 V				8	MHz
		$2.4~V \leq V_{\text{DD}} < 2$	.7 V				4	MHz
PCLBUZ0, or PCLBUZ1	<b>f</b> PCL	$4.0~V \le V_{\text{DD}} \le 5$	.5 V				16	MHz
output frequency		$2.7~V \leq V_{\text{DD}} < 4$	.0 V				8	MHz
		$2.4~V \leq V_{\text{DD}} < 2$	.7 V				4	MHz
INTP0 to INTP5 input high- level width, low-level width	tinth, tintl				1			μs
KR0 to KR9 input available width	<b>t</b> ĸĸ				250			ns
RESET low-level width	<b>t</b> RSL				10			μs

Remark fmck: Timer array unit operation clock frequency

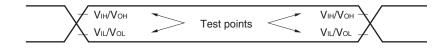
(Operation clock to be set by the timer clock select register 0 (TPS0) and the CKS0n bit of timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))



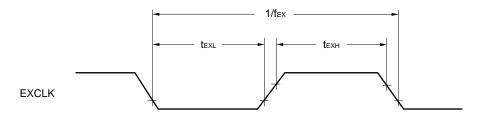
#### Minimum Instruction Execution Time during Main System Clock Operation



### **AC Timing Test Point**

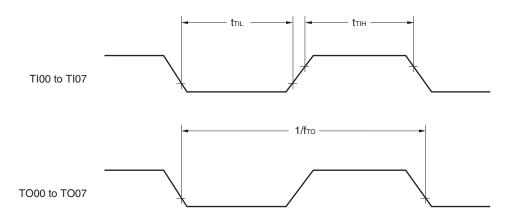


#### **External Main System Clock Timing**

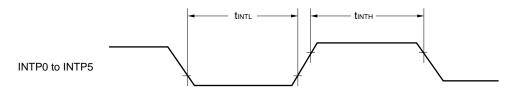




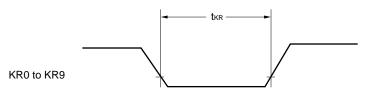
#### **TI/TO Timing**



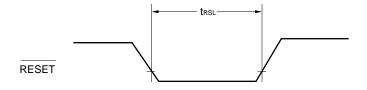
#### Interrupt Request Input Timing



#### Key Interrupt Input Timing



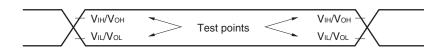
#### **RESET** Input Timing





## 3.5 Peripheral Functions Characteristics

#### **AC Timing Test Point**



### 3.5.1 Serial array unit

#### (1) During communication at same potential (UART mode) (T<sub>A</sub> = -40 to $+105^{\circ}$ C, 2.4 V $\leq$ V<sub>DD</sub> $\leq$ 5.5 V, V<sub>SS</sub> = 0 V)

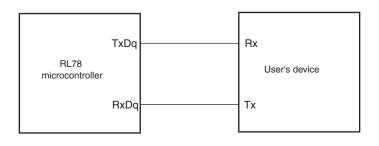
Parameter	Symbol	Conditions		ed main) Mode	Unit
			MIN.	MAX.	
Transfer rate				fмск/12	bps
Note 1		Theoretical value of the maximum transfer rate $f_{CLK} = f_{MCK}^{Note2}$		2.0	Mbps

- **Notes 1.** Transfer rate in the SNOOZE mode is 4800 bps only.
  - 2. The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are:

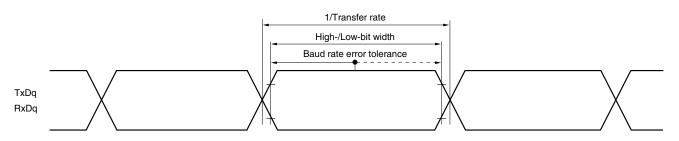
HS (high-speed main) mode: 24 MHz (2.7 V 
$$\leq$$
 V<sub>DD</sub>  $\leq$  5.5 V)

- 16 MHz (2.4 V  $\leq$  VDD  $\leq$  5.5 V)
- Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

#### UART mode connection diagram (during communication at same potential)



#### UART mode bit width (during communication at same potential) (reference)



**Remarks 1.** q: UART number (q = 0 to 2), g: PIM, POM number (g = 0, 1)

- 2. fMCK: Serial array unit operation clock frequency
  - (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))



Parameter	Symbol	Conditions		HS (high-spee	d main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time	tkCY1	tксү1 ≥ 4/fclк	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	334		ns
			$2.4~V \le V_{\text{DD}} \le 5.5~V$	500		ns
SCKp high-/low-level width	tкнı,	$4.0 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5$	ν	tксү1/2–24		ns
	tĸ∟1	$2.7~V \le V_{\text{DD}} \le 5.5~V$		tксү1/2–36		ns
		$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5$	ν	tксү1/2–76		ns
SIp setup time (to SCKp↑) Note 1	tsiĸ1	$4.0 \text{ V} \le \text{V}_{\text{DD}} \le 5.5$	ν	66		ns
		$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5$	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$			ns
		$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5$	ν	113		ns
SIp hold time (from SCKp $\uparrow$ ) <sup>Note 2</sup>	tksi1			38		ns
Delay time from SCKp↓ to SOp output <sup>Note 3</sup>	tkso1	C = 30 pF <sup>Note4</sup>			50	ns

(2) During communication at same potential (CSI mode) (master mode, SCKp internal clock output)
(T <sub>A</sub> = −40 to +105°C, 2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V, V <sub>SS</sub> = 0 V)

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SCKp and SOp output lines.
- Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp and SCKp pins by using port input mode register 1 (PIM1) and port output mode registers 0, 1, 4 (POM0, POM1, POM4).
- **Remarks 1.** p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3)
  - 2. fMCK: Serial array unit operation clock frequency
    - (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3))

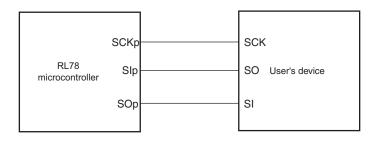


Parameter	Symbol	Con	ditions	HS (high-speed	l main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time Note4	tксү2	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	20 MHz < fмск	<b>16/f</b> мск		ns
			fмск ≤ 20 MHz	12/fмск		ns
		$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	16 MHz < fмск	16/fмск		ns
			fмск ≤ 16 MHz	12/fмск		ns
		$2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$		12/fмск		ns
				and 1000		
SCKp high-/low-level width	<b>t</b> кн2,	$4.0~V \leq V_{\text{DD}} \leq 5.5~V$	tксү2/2–14		ns	
	tĸ∟2	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	tксү2/2–16		ns	
		$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	tксү2/2–36		ns	
SIp setup time (to SCKp $\uparrow$ )	tsik2	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$		1/fмск + 40		ns
Note 1		$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	1/fмск + 60		ns	
SIp hold time (from SCKp↑) <sup>Note 2</sup>	tksi2			1/fмск + 62		ns
Delay time from SCKp $\downarrow$ to	tkso2	C = 30 pF <sup>Note4</sup>	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$		2/fмск + 66	ns
SOp output Note 3			$2.4~V \leq V_{\text{DD}} \leq 5.5~V$		2/fмск + 113	ns

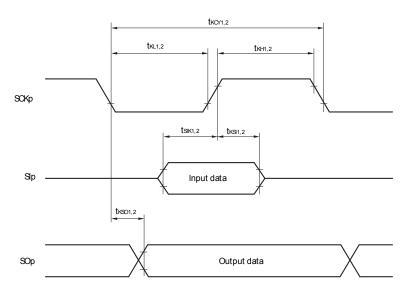
## (3) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input) (T<sub>A</sub> = -40 to +105°C, 2.4 V $\leq$ V<sub>DD</sub> $\leq$ 5.5 V, V<sub>SS</sub> = 0 V)

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp<sup>↑</sup>" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SOp output lines.
  - 5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
- Caution Select the normal input buffer for the SIp and SCKp pins and the normal output mode for the SOp pin by using port input mode register 1 (PIM1) and port output mode registers 0, 1, 4 (POM0, POM1, POM4).

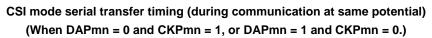
#### CSI mode connection diagram (during communication at same potential)

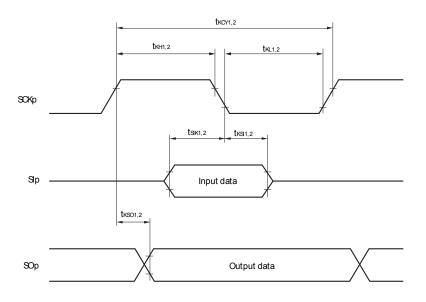






## CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)





- Remarks 1. p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3)
   2. fMCK: Serial array unit operation clock frequency
  - (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0,1), n: Channel number (n = 0, 1, 3))



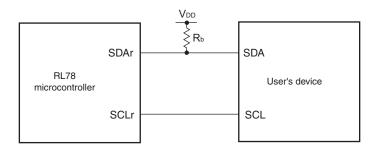
$(T_A = -40 \text{ to } +105^{\circ}C, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$									
Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit				
			MIN.	MAX.					
SCLr clock frequency	fscl	$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$		100 Note 1	kHz				
Hold time when SCLr = "L"	tLow	$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$	4600		ns				
Hold time when SCLr = "H"	tніgн	$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$	4600		ns				
Data setup time (reception)	tsu:dat	$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$	1/f <sub>MCK</sub> + 580 <sup>Note 2</sup>		ns				
Data hold time (transmission)	thd:dat	$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$	0	1420	ns				

## (4) During communication at same potential (simplified I<sup>2</sup>C mode)

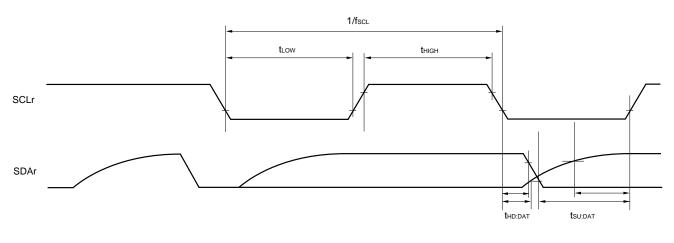
**Notes 1.** The value must also be equal to or less than fmck/4.

- 2. Set tsu:DAT so that it will not exceed the hold time when SCLr = "L" or SCLr = "H".
- Caution Select the N-ch open drain output (VDD tolerance) mode for SDAr by using port output mode register h (POMh).

Simplified I<sup>2</sup>C mode connection diagram (during communication at same potential)



Simplified I<sup>2</sup>C mode serial transfer timing (during communication at same potential)



- **Remarks 1.** R<sub>b</sub> [Ω]:Communication line (SDAr) pull-up resistance C<sub>b</sub> [F]: Communication line (SCLr, SDAr) load capacitance
  - **2.** r: IIC number (r = 00, 01, 11, 20), h: = POM number (h = 0, 1, 4, 5)

 fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number (m = 0, 1), n: Channel number (0, 1, 3))



Parameter	Symbol		Conditions		HS (high-speed main) Mode	
				MIN.	MAX.	
Transfer rate Note4		Reception	4.0 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V, 2.7 V $\leq$ V <sub>b</sub> $\leq$ 4.0 V		fмск/12 Note 1	bps
			Theoretical value of the maximum transfer rate for Note 2 for for the form		2.0	Mbps
			$\begin{array}{c} 2.7 \ V \leq V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_{b} \leq 2.7 \ V \end{array}$		fмск/12 Note 1	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 2}$		2.0	Mbps
			$\begin{array}{c} 2.4 \ V \leq V_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V \end{array}$		fмск/12 Note 1	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2		2.0	Mbps
		Transmission	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \\ 2.7 \; V \leq V_{b} \leq 4.0 \; V \end{array}$		Note 3	bps
			Theoretical value of the maximum transfer rate $C_b$ = 50 pF, $R_b$ = 1.4 kΩ, $V_b$ = 2.7 V		2.0 Note 4	Mbps
			$\begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_{b} \leq 2.7 \ V, \end{array}$		Note 5	bps
			Theoretical value of the maximum transfer rate $C_b$ = 50 pF, $R_b$ = 2.7 k $\Omega$ , $V_b$ = 2.3 V		1.2 Note 6	Mbps
			$2.4 V \le V_{DD} < 3.3 V,$ $1.6 V \le V_b \le 2.0 V$		Notes 2, 7	bps
			Theoretical value of the maximum transfer rate $C_b$ = 50 pF, $R_b$ = 5.5 k $\Omega$ , V <sub>b</sub> = 1.6 V		0.43 Note 8	Mbps

## (5) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The maximum operating frequencies of the CPU/peripheral hardware clock (f<sub>CLK</sub>) are: HS (high-speed main) mode: 24 MHz (2.7 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

16 MHz (2.4 V 
$$\leq$$
 V<sub>DD</sub>  $\leq$  5.5 V)

**3.** The smaller maximum transfer rate derived by using fMCK/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V  $\leq$  V\_{DD}  $\leq$  5.5 V and 2.7 V  $\leq$  V\_b  $\leq$  4.0 V

Maximum transfer rate =

$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =  $\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.2}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$ 

\* This value is the theoretical value of the relative difference between the transmission and reception sides.



- 4. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to **Note 3** above to calculate the maximum transfer rate under conditions of the customer.
- 5. The smaller maximum transfer rate derived by using fMCK/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V  $\leq$  V<sub>DD</sub> < 4.0 V and 2.3 V  $\leq$  V<sub>b</sub>  $\leq$  2.7 V

Maximum transfer rate =  $\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$  [bps]

Baud rate error (theoretical value) =

$$\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\}$$

$$(\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits} \times 100 [\%]$$

\* This value is the theoretical value of the relative difference between the transmission and reception sides.

- 6. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 5 above to calculate the maximum transfer rate under conditions of the customer.
- **7.** The smaller maximum transfer rate derived by using fMCK/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.4 V  $\leq$  V\_DD < 3.3 V, 1.6 V  $\leq$  V\_b  $\leq$  2.0 V

Maximum transfer rate =

$$\frac{1}{[-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})] \times 3}$$
 [bps]

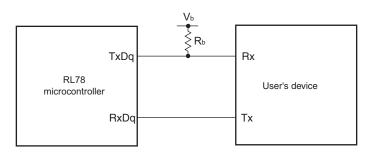
Baud rate error (theoretical value) =  $\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$ 

\* This value is the theoretical value of the relative difference between the transmission and reception sides.

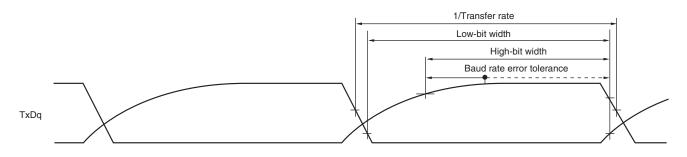
- This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 7 above to calculate the maximum transfer rate under conditions of the customer.
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.

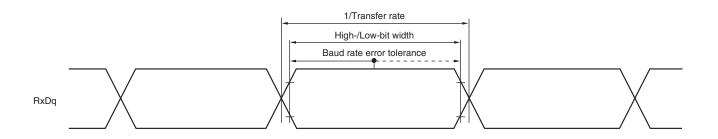


### UART mode connection diagram (during communication at different potential)



#### UART mode bit width (during communication at different potential) (reference)





- **Remarks 1.** R<sub>b</sub>[Ω]: Communication line (TxDq) pull-up resistance, C<sub>b</sub>[F]: Communication line (TxDq) load capacitance, V<sub>b</sub>[V]: Communication line voltage
  - 2. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
  - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
    - m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))
  - **4.** UART0 of the 20- and 24-pin products supports communication at different potential only when the peripheral I/O redirection function is not used.



# (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (1/3)

Parameter	Symbol		Conditions	HS (high-speed	d main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time	tkCY1	tксү1 ≥ 4/fclк	$4.0~V \leq V_{\text{DD}} \leq 5.5~V,$	600		ns
			$2.7~V \leq V_b \leq 4.0~V,$			
			$C_b$ = 30 pF, $R_b$ = 1.4 k $\Omega$			
			$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.0 \text{ V},$	1000		ns
			$2.3 V \le V_b \le 2.7 V$ ,			
			$C_b$ = 30 pF, $R_b$ = 2.7 k $\Omega$			
			$2.4 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V},$	2300		ns
			$1.6 V \le V_b \le 2.0 V$ ,			
			$C_b$ = 30 pF, $R_b$ = 5.5 k $\Omega$			
SCKp high-level width tkH1		$4.0 \ V \leq V_{\text{DD}} \leq 5.5 \ V, \ 2.7 \ V \leq V_{\text{b}} \leq 4.0 \ V,$		tксү1/2 –150		ns
		$C_b$ = 30 pF, $R_b$ = 1.4 k $\Omega$				
		$2.7 \text{ V} \le \text{V}_{\text{DD}}$ < 4.0 V, 2.3 V $\le \text{V}_{\text{b}} \le$ 2.7 V,		tксү1/2 –340		ns
		C <sub>b</sub> = 30 pF, Rt	$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
		$2.4 \text{ V} \leq \text{V}_{\text{DD}}$ <	3.3 V, 1.6 V ≤ V <sub>b</sub> ≤ 2.0 V,	tксү1/2 –916		ns
		C <sub>b</sub> = 30 pF, Rt	<sub>b</sub> = 5.5 kΩ			
SCKp low-level width	<b>t</b> ĸ∟1	$4.0 V \le V_{DD} \le$	5.5 V, 2.7 V $\leq$ V <sub>b</sub> $\leq$ 4.0 V,	tксү1/2 –24		ns
		C <sub>b</sub> = 30 pF, Rt	<sub>b</sub> = 1.4 kΩ			
		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V},$		tксү1/2 –36		ns
		C <sub>b</sub> = 30 pF, Rt	b = 2.7 kΩ			
		2.4 V ≤ V <sub>DD</sub> < 1	$3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	tkcy1/2 –100		ns
		C₀ = 30 pF, Rt				

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$ 

- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SOp pin and SCKp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For V<sub>H</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.
- **Remarks 1.** R<sub>b</sub> [Ω]: Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - **2.** p: CSI number (p = 00, 20)



(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (2/3)

Parameter	Symbol	Conditions	HS (high-spe	ed main) Mode	Unit
			MIN.	MAX.	
SIp setup time (to SCKp↑) Note	tsik1		162		ns
		$\label{eq:VDD} \begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	354		ns
		$\label{eq:VD} \begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	958		ns
SIp hold time (from SCKp↑) <sup>Note</sup>	tksii	$\label{eq:VDD} \begin{split} 4.0 \; V \leq V_{\text{DD}} \leq 5.5 \; V, \; 2.7 \; V \leq V_{\text{b}} \leq 4.0 \; V, \\ C_{\text{b}} = 30 \; pF, \; R_{\text{b}} = 1.4 \; k\Omega \end{split}$	38		ns
		$\label{eq:VDD} \begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	38		ns
		$\label{eq:VDD} \begin{array}{l} 2.4 \ V \leq V_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V, \\ C_{\text{b}} = 30 \ p\text{F}, \ R_{\text{b}} = 5.5 \ k\Omega \end{array}$	38		ns
Delay time from SCKp↓ to SOp output <sup>Note</sup>	tkso1	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$		200	ns
		$\label{eq:VDD} \begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$		390	ns
		$\label{eq:VDD} \begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$		966	ns

## $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$

Note When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

(Cautions and Remarks are listed on the next page.)



## (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (3/3)

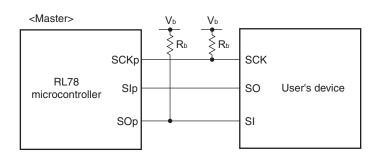
Parameter	Symbol	Conditions	HS (high-speed main) Mode	Unit
			MIN. MAX.	
SIp setup time (to SCKp $\downarrow$ ) Note	tsik1		88	ns
		$\label{eq:VDD} \begin{split} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{split}$	88	ns
		$\label{eq:VDD} \begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	220	ns
Slp hold time (from SCKp↓) <sup>Note</sup>	tksii		38	ns
		$\label{eq:VDD} \begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	38	ns
		$\label{eq:VDD} \begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	38	ns
Delay time from SCKp↑ to SOp output <sup>Note</sup>	tkso1	$\begin{array}{l} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	50	ns
		$\label{eq:VD} \begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	50	ns
		$\label{eq:VDD} \begin{split} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	50	ns

## $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$

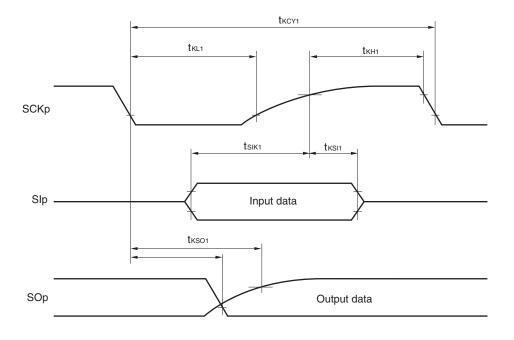
**Note** When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.
- **Remarks 1.** R<sub>b</sub> [Ω]: Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - **2.** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)

#### CSI mode connection diagram (during communication at different potential)

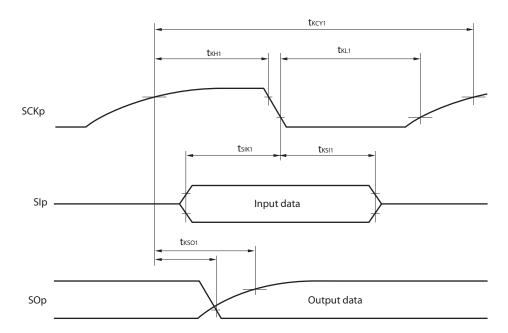


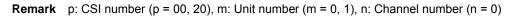




CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1)

CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)







## (7) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (slave mode, SCKp... external clock input) $(T_A = -40 \text{ to } \pm 105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{ Vss} = 0.\text{ V})$

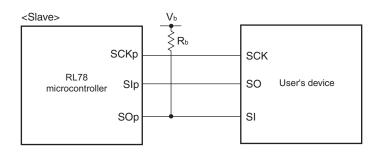
Parameter	Symbol		Conditions	HS (high-spe Mod		Unit
				MIN.	MAX.	
SCKp cycle time Note 1	<b>t</b> ксү2	$4.0~V \leq V_{\text{DD}} \leq 5.5~V,$	20 MHz < fмск ≤ 24 MHz	<b>24/f</b> мск		ns
		$2.7~V \leq V_b \leq 4.0~V$	$8 \text{ MHz} < f_{MCK} \le 20 \text{ MHz}$	<b>20/f</b> мск		ns
			$4 \text{ MHz} < f_{\text{MCK}} \le 8 \text{ MHz}$	<b>16/f</b> мск		ns
			fмск ≤4 MHz	<b>12/f</b> мск		ns
		$2.7 \text{ V} \le \text{V}_{\text{DD}} < 4.0 \text{ V},$	20 MHz < $f_{MCK} \le$ 24 MHz	<b>32/f</b> мск		ns
		$2.3~V \leq V_b \leq 2.7~V$	16 MHz < fмск ≤ 20 MHz	<b>28/f</b> мск		ns
			8 MHz < $f_{MCK} \le 16$ MHz	<b>24/f</b> мск		ns
			$4 \text{ MHz} < f_{\text{MCK}} \le 8 \text{ MHz}$	<b>16/f</b> мск		ns
			fмск ≤4 MHz	<b>12/f</b> мск		ns
		$2.4 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V},$	20 MHz < fмск ≤ 24 MHz	<b>72/f</b> мск		ns
		$1.6~V \leq V_b \leq 2.0~V$	16 MHz < fмск ≤ 20 MHz	<b>64/f</b> мск		ns
			8 MHz < $f_{MCK} \le 16$ MHz	<b>52/f</b> мск		ns
			4 MHz < $f_{MCK} \le 8$ MHz	<b>32/f</b> мск		ns
			fмск ≤4 MHz	<b>20/f</b> мск		ns
SCKp high-/low-level	tкн2,	$4.0~V \leq V_{\text{DD}} \leq 5.5~V,~2$	$7~V \leq V_b \leq 4.0~V$	tkcy2/2 – 24		ns
width	tĸ∟2	$2.7 \text{ V} \le \text{V}_{\text{DD}} \le 4.0 \text{ V}, 2$	$.3~V \leq V_b \leq 2.7~V$	tkcy2/2 – 36		ns
		$2.4 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V}, 1$	$.6~V \leq V_b \leq 2.0~V$	tkcy2/2 - 100		ns
SIp setup time	tsik2	$4.0~V \leq V_{\text{DD}} \leq 5.5~V,~2.$	$7~V \leq V_{\text{DD}} \leq 4.0~V$	1/fмск + 40		ns
(to SCKp↑) Note 2		$2.7 \text{ V} \le \text{V}_{\text{DD}}$ < 4.0 V, 2	$.3~V \leq V_b \leq 2.7~V$	1/fмск + 40		ns
		$2.4 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V}, 1$	$.6 \text{ V} \leq \text{V}_{\text{DD}} \leq 2.0 \text{ V}$	1/fмск + 60		ns
SIp hold time (from SCKp↑) <sup>Note 3</sup>	tksi2			1/fмск + 62		ns
Delay time from SCKp↓ to	tĸso2	$4.0 \text{ V} \le V_{\text{DD}} \le 5.5 \text{ V}, 2.00 \text{ V}$	$7 \text{ V} \leq V_b \leq 4.0 \text{ V},$		2/fмск +	ns
SOp output Note 4		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 1.4 k	Ω		240	
		$2.7 \text{ V} \le \text{V}_{\text{DD}}$ < 4.0 V, 2	$.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V},$		2/fмск +	ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 2.7 k	Ω		428	
		$2.4 \text{ V} \le \text{V}_{\text{DD}} < 3.3 \text{ V}, 1$	$.6 V \le V_b \le 2.0 V,$		2/fмск +	ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 5.5 kΩ			1146	

**Notes 1.** Transfer rate in the SNOOZE mode: MAX. 1 Mbps

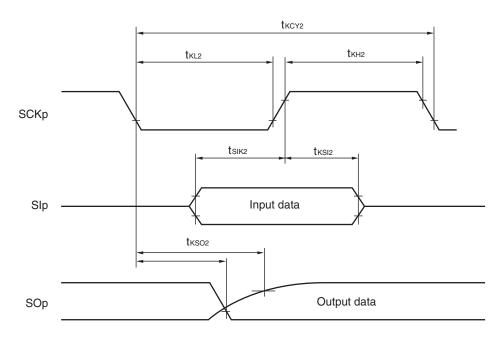
- 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp<sup>↑</sup>" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Cautions 1. Select the TTL input buffer for the SIp and SCKp pins and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SOp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.



#### CSI mode connection diagram (during communication at different potential)



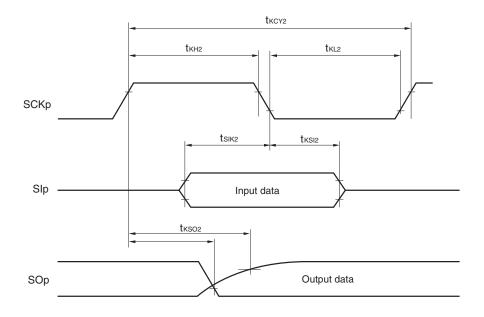
CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



- Remarks 1.
   Rb [Ω]: Communication line (SOp) pull-up resistance, Cb [F]: Communication line (SOp) load capacitance,

   Vb [V]: Communication line voltage
  - **2.** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)
  - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn))





## CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)

**Remark** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)



## (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I<sup>2</sup>C mode)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		
			MIN.	MAX.		
SCLr clock frequency	fsc∟	$\begin{array}{l} \mbox{4.0 V} \le V_{\text{DD}} \le 5.5 \ \text{V}, \ 2.7 \ \text{V} \le V_{b} \le 4.0 \ \text{V}, \\ \mbox{C}_{b} = 100 \ \text{pF}, \ R_{b} = 2.8 \ \text{k}\Omega \end{array}$		100 <sup>Note1</sup>	kHz	
		$\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		100 <sup>Note1</sup>	kHz	
		$\begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$		100 <sup>Note1</sup>	kHz	
Hold time when SCLr = "L"	tLOW	$\begin{array}{l} \mbox{4.0 V} \le V_{\text{DD}} \le 5.5 \ \text{V}, \ 2.7 \ \text{V} \le V_{\text{b}} \le 4.0 \ \text{V}, \\ \mbox{C}_{\text{b}} = 100 \ \text{pF}, \ \text{R}_{\text{b}} = 2.8 \ \text{k}\Omega \end{array}$	4600		ns	
		$\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	4600		ns	
		$\begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	4650		ns	
Hold time when SCLr = "H"	tніgн	$\begin{array}{l} \mbox{4.0 V} \leq V_{\text{DD}} \leq 5.5 \mbox{ V}, \mbox{2.7 V} \leq V_{b} \leq 4.0 \mbox{ V}, \\ \mbox{C}_{b} = 100 \mbox{ pF}, \mbox{ R}_{b} = 2.8 \mbox{ k} \Omega \end{array}$	2700		ns	
		$\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	2400		ns	
		$\begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	1830		ns	
Data setup time (reception)	tsu:dat	$\begin{array}{l} \mbox{4.0 V} \leq V_{\text{DD}} \leq 5.5 \mbox{ V}, \mbox{2.7 V} \leq V_{b} \leq 4.0 \mbox{ V}, \\ \mbox{C}_{b} = 100 \mbox{ pF}, \mbox{ R}_{b} = 2.8 \mbox{ k} \Omega \end{array}$	1/fмск + 760 <sup>Note3</sup>		ns	
		$\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1/fмск + 760 <sup>Note3</sup>		ns	
		$\label{eq:VDD} \begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	1/fмск + 570 <sup>Note3</sup>		ns	
Data hold time (transmission)	thd:dat	$\begin{array}{l} \label{eq:VDD} 4.0 \; V \leq V_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 100 \; pF, \; R_b = 2.8 \; k\Omega \end{array}$	0	1420	ns	
		$\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{\text{b}} \leq 2.7 \ V, \\ C_{\text{b}} = 100 \ p\text{F}, \ R_{\text{b}} = 2.7 \ k\Omega \end{array}$	0	1420	ns	
		$\begin{array}{l} 2.4 \ V \leq V_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	0	1215	ns	

**Notes 1.** The value must also be equal to or less than  $f_{MCK}/4$ .

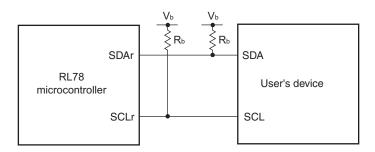
2. Set tsu:DAT so that it will not exceed the hold time when SCLr = "L" or SCLr = "H".

- Cautions 1. Select the TTL input buffer and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SDAr pin and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SCLr pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.
  - 2. IIC01 and IIC11 cannot communicate at different potential.

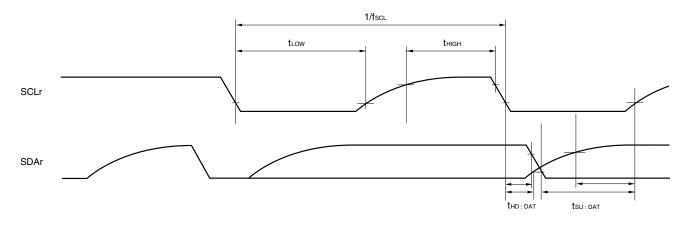
(Remarks are listed on the next page.)



## Simplified I<sup>2</sup>C mode connection diagram (during communication at different potential)



### Simplified I<sup>2</sup>C mode serial transfer timing (during communication at different potential)



- Remarks 1. Rb [Ω]: Communication line (SDAr, SCLr) pull-up resistance, Cb [F]: Communication line (SDAr, SCLr) load capacitance, Vb [V]: Communication line voltage
  - **2.** r: IIC Number (r = 00, 20)
  - 3. fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number (m = 0,1), n: Channel number (n = 0))



## 3.5.2 Serial interface IICA

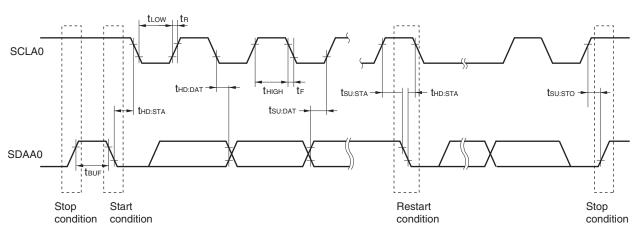
Parameter	Symbol	Conditions	HS	HS (high-speed main) mode			
			Standa	rd Mode	Fast Mode		
			MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fsc∟	Fast mode: fcLk≥ 3.5 MHz			0	400	kHz
		Normal mode: fcLk≥ 1 MHz	0	100			kHz
Setup time of restart condition	tsu:sta		4.7		0.6		μs
Hold time <sup>Note 1</sup>	thd:sta		4.0		0.6		μs
Hold time when SCLA0 = "L"	<b>t</b> LOW		4.7		1.3		μs
Hold time when SCLA0 = "H"	<b>t</b> high		4.0		0.6		μs
Data setup time (reception)	tsu:dat		250		100		ns
Data hold time (transmission) <sup>Note 2</sup>	thd:dat		0	3.45	0	0.9	μs
Setup time of stop condition	tsu:sto		4.0		0.6		μs
Bus-free time	<b>t</b> BUF		4.7		1.3		μs

### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

- 2. The maximum value (MAX.) of the during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.
- Caution Only in the 30-pin products, the values in the above table are applied even when bit 2 (PIOR2) in the peripheral I/O redirection register (PIOR) is 1. At this time, the pin characteristics (IOH1, IOL1, VOH1, VOL1) must satisfy the values in the redirect destination.
- **Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Normal mode: $C_b$  = 400 pF, Rb = 2.7 k $\Omega$ Fast mode: $C_b$  = 320 pF, Rb = 1.1 k $\Omega$ 



IICA serial transfer timing



## 3.6 Analog Characteristics

### 3.6.1 A/D converter characteristics

Classification of A/D converter characteristics

Input channel	Reference Voltage							
	Reference voltage (+) = AVREFP Reference voltage (-) = AVREFM	Reference voltage (+) = V <sub>DD</sub> Reference voltage (-) = Vss	Reference voltage (+) = V <sub>BGR</sub> Reference voltage (-) = AV <sub>REFM</sub>					
ANI0 to ANI3	Refer to 3.6.1 (1).	Refer to 3.6.1 (3).	Refer to 3.6.1 (4).					
ANI16 to ANI22	Refer to 3.6.1 (2).							
Internal reference voltage	Refer to 3.6.1 (1).		-					
Temperature sensor output voltage								

(1) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI2, ANI3, internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{REFP} \le \text{VDD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{REFP}, \text{Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$ 

Parameter	Symbol	Cor	MIN.	TYP.	MAX.	Unit	
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution AV <sub>REFP</sub> = $V_{DD}^{Note 3}$			1.2	±3.5	LSB
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V\text{DD} \leq 5.5~V$	2.125		39	μs
		Target pin: ANI2, ANI3	$2.7~V \leq V\text{DD} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
		10-bit resolution	$3.6~V \leq V\text{DD} \leq 5.5~V$	2.375		39	μs
		Target pin: Internal	$2.7~V \leq V\text{DD} \leq 5.5~V$	3.5625		39	μs
		reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±0.25	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±0.25	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±2.5	LSB
Differential linearity error	DLE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>			±1.5	LSB	
Analog input voltage	VAIN	ANI2, ANI3	0		AVREFP	V	
		Ŭ	nternal reference voltage (HS (high-speed main) mode)		V <sub>BGR</sub> Note 4		
		Temperature sensor output voltage (HS (high-speed main) mode)		VTMPS25 Note 4			V

(Notes are listed on the next page.)



- **Notes 1.** Excludes quantization error (±1/2 LSB).
  - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
  - 3. When AV<sub>REFP</sub> < V<sub>DD</sub>, the MAX. values are as follows. Overall error: Add ±1.0 LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>. Zero-scale error/Full-scale error: Add ±0.05%FSR to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>. Integral linearity error/ Differential linearity error: Add ±0.5 LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.
  - 4. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.
- (2) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI16 to ANI22

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{\text{REFP}}, \text{Reference voltage (-)} = 10^{\circ}\text{C}, $	
AVREFM = 0 V)	

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error Note 1	AINL	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>			1.2	±5.0	LSB
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.125		39	μs
		Target ANI pin: ANI16 to ANI22	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V \text{DD} \leq 5.5~V$	17		39	μs
Zero-scale error Notes 1, 2	EZS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±0.35	%FSR
Full-scale error Notes 1, 2	EFS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±0.35	%FSR
Integral linearity error Note 1	ILE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±3.5	LSB
Differential linearity error <sup>Note 1</sup>	DLE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> <sup>Note 3</sup>				±2.0	LSB
Analog input voltage	VAIN	ANI16 to ANI22		0		AVREFP and VDD	V

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

- **2.** This value is indicated as a ratio (%FSR) to the full-scale value.
- **3.** When  $AV_{REFP} \leq V_{DD}$ , the MAX. values are as follows.

Overall error: Add  $\pm 4.0$  LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Zero-scale error/Full-scale error: Add  $\pm 0.20\%$ FSR to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Integral linearity error/ Differential linearity error: Add  $\pm 2.0$  LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.



# (3) When reference voltage (+) = V<sub>DD</sub> (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V<sub>ss</sub> (ADREFM = 0), target pin: ANI0 to ANI3, ANI16 to ANI22, internal reference voltage, and temperature sensor output voltage

Parameter	Symbol	Conditio	MIN.	TYP.	MAX.	Unit	
Resolution	Res			8		10	bit
Overall errorNote 1	AINL	10-bit resolution			1.2	±7.0	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \le V \text{DD} \le 5.5~V$	2.125		39	μs
		Target pin: ANI0 to ANI3,	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.1875		39	μs
		ANI16 to ANI22	$2.4~V \leq V \text{DD} \leq 5.5~V$	17		39	μs
Conversion time	tconv	Target pin: internal reference 2 voltage, and temperature	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.375		39	μs
			$2.7~V \le V \text{DD} \le 5.5~V$	3.5625		39	μs
			$2.4 \text{ V} \leq \text{VDD} \leq 5.5 \text{ V}$	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution	10-bit resolution			±0.60	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution				±0.60	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution				±4.0	LSB
Differential linearity error Note 1	DLE	10-bit resolution				±2.0	LSB
Analog input voltage	VAIN	ANI0 to ANI3, ANI16 to ANI2	2	0		VDD	V
		Internal reference voltage (HS (high-speed main) mode)		V <sub>BGR</sub> Note 3			V
		Temperature sensor output voltage (HS (high-speed main) mode)		,	VTMPS25 Note 3	3	V

#### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{V}_{DD}, \text{ Reference voltage (-)} = \text{V}_{SS})$

Notes 1. Excludes quantization error ( $\pm 1/2$  LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.



# (4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AV<sub>REFM</sub> (ADREFM = 1), target pin: ANI0, ANI2, ANI3, and ANI16 to ANI22

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{V}_{BGR}^{Note 3}, \text{ Reference voltage (-)} = 100 \text{ V}_{SS} = 100 \text{ V}, \text$
AVREFM <sup>Note 4</sup> = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		bit
Conversion time	t <sub>CONV</sub>	8-bit resolution	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	8-bit resolution			±0.60	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	8-bit resolution			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution			±1.0	LSB
Analog input voltage	VAIN		0		$V_{\text{BGR}}^{\text{ Note 3}}$	V

Notes 1. Excludes quantization error (±1/2 LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.

4. When reference voltage (-) = Vss, the MAX. values are as follows.

Zero-scale error: Add  $\pm 0.35\%$ FSR to the MAX. value when reference voltage (–) = AV<sub>REFM</sub>. Integral linearity error: Add  $\pm 0.5$  LSB to the MAX. value when reference voltage (–) = AV<sub>REFM</sub>. Differential linearity error: Add  $\pm 0.2$  LSB to the MAX. value when reference voltage (–) = AV<sub>REFM</sub>.



## 3.6.2 Temperature sensor/internal reference voltage characteristics

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	VTMPS25	Setting ADS register = 80H, TA = +25°C		1.05		V
Internal reference voltage	Vbgr	Setting ADS register = 81H	1.38	1.45	1.50	V
Temperature coefficient	Fvtmps	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		5			μs

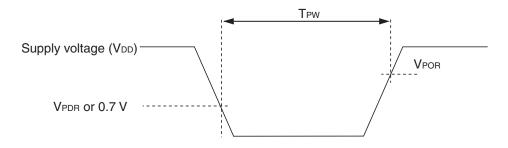
## (T<sub>A</sub> = -40 to $+105^{\circ}$ C, 2.4 V $\leq$ V<sub>DD</sub> $\leq$ 5.5 V, V<sub>SS</sub> = 0 V, HS (high-speed main) mode

## 3.6.3 POR circuit characteristics

#### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{ Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	V <sub>POR</sub> Power supply rise time		1.45	1.51	1.57	V
	VPDR	Power supply fall time	1.44	1.50	1.56	V
Minimum pulse width Note	Tpw		300			μs

**Note** Minimum time required for a POR reset when V<sub>DD</sub> exceeds below V<sub>PDR</sub>. This is also the minimum time required for a POR reset from when V<sub>DD</sub> exceeds below 0.7 V to when V<sub>DD</sub> exceeds V<sub>POR</sub> while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).





## 3.6.4 LVD circuit characteristics

## LVD Detection Voltage of Reset Mode and Interrupt Mode (T<sub>A</sub> = -40 to +105°C, V<sub>PDR</sub> $\leq$ V<sub>DD</sub> $\leq$ 5.5 V, V<sub>SS</sub> = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection supply voltage	VLVD0	Power supply rise time	3.90	4.06	4.22	V
		Power supply fall time	3.83	3.98	4.13	V
	VLVD1	Power supply rise time	3.60	3.75	3.90	V
		Power supply fall time	3.53	3.67	3.81	V
	VLVD2	Power supply rise time	3.01	3.13	3.25	V
		Power supply fall time	2.94	3.06	3.18	V
	VLVD3	Power supply rise time	2.90	3.02	3.14	V
		Power supply fall time	2.85	2.96	3.07	V
	VLVD4	Power supply rise time	2.81	2.92	3.03	V
		Power supply fall time	2.75	2.86	2.97	V
	VLVD5	Power supply rise time	2.70	2.81	2.92	V
		Power supply fall time	2.64	2.75	2.86	V
	VLVD6	Power supply rise time	2.61	2.71	2.81	V
		Power supply fall time	2.55	2.65	2.75	V
	VLVD7	Power supply rise time	2.51	2.61	2.71	V
		Power supply fall time	2.45	2.55	2.65	V
Minimum pulse width	t∟w		300			μs
Detection delay time					300	μs



## LVD detection voltage of interrupt & reset mode

Parameter	Symbol		Conditions			TYP.	MAX.	Unit
Interrupt and reset	VLVDD0	VPOC2,	VPOC1, VPOC1 = 0, 1, 1, fall	ng reset voltage	2.64	2.75	2.86	V
mode	VLVDD1		LVIS1, LVIS0 = 1, 0	Rising reset release voltage	2.81	2.92	3.03	V
				Falling interrupt voltage	2.75	2.86	2.97	V
	VLVDD2		LVIS1, LVIS0 = 0, 1	Rising reset release voltage	2.90	3.02	3.14	V
				Falling interrupt voltage	2.85	2.96	3.07	V
	VLVDD3		LVIS1, LVIS0 = 0, 0	Rising reset release voltage	3.90	4.06	4.22	V
				Falling interrupt voltage	3.83	3.98	4.13	V

### 3.6.5 Power supply voltage rising slope characteristics

### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{ Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V<sub>DD</sub> reaches the operating voltage range shown in 3.4 AC Characteristics.

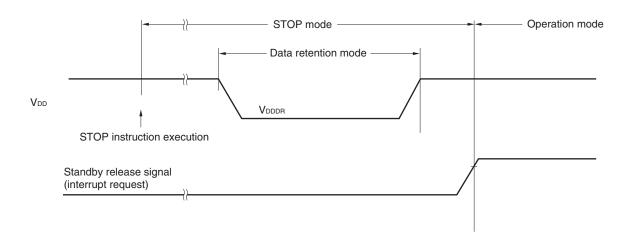


## 3.7 Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics

$(T_A = -40 \text{ to } +1)$	05°C, Vss = 0 V)
------------------------------	------------------

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.44 <sup>Note</sup>		5.5	V

**Note** The value depends on the POR detection voltage. When the voltage drops, the data is retained before a POR reset is affected, but data is not retained when a POR reset is affected.



## 3.8 Flash Memory Programming Characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C})$	$2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$	$V_{\rm SS} = 0 V$
(1A = 10.00 1100 0)		,

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
System clock frequency	fclk			1		24	MHz
Code flash memory rewritable times Notes 1, 2, 3	Cerwr	Retained for 20 years	T <sub>A</sub> = 85°C	1,000			Times
Data flash memory rewritable times		Retained for 1 year	T <sub>A</sub> = 25°C		1,000,000		
Notes 1, 2, 3		Retained for 5 years	T <sub>A</sub> = 85°C	100,000			
		Retained for 20 years	T <sub>A</sub> = 85°C	10,000			

**Notes 1.** 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library
- **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.



## 3.9 Dedicated Flash Memory Programmer Communication (UART)

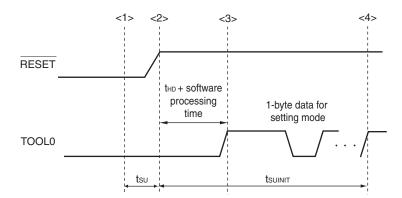
11.4 40 10 1100 0, 2.4 1 3		•, • • • • • • • • • • • • • • • • • •				
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps

## $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

## 3.10 Timing of Entry to Flash Memory Programming Modes

## $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset are released before external release			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	<b>t</b> su	POR and LVD reset are released before external release	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to	tнd	POR and LVD reset are released before external release	1			ms
control the flash memory)						



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.
- **Remark** tsuinit: Communication for the initial setting must be completed within 100 ms after the external reset is released during this period.
  - $t_{\text{SU:}}$  Time to release the external reset after the TOOL0 pin is set to the low level
  - the: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)



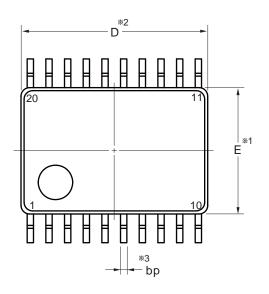
## 4. PACKAGE DRAWINGS

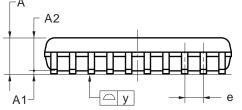
#### 4.1 20-pin products

R5F1026AASP, R5F10269ASP, R5F10268ASP, R5F10267ASP, R5F10266ASP R5F1036AASP, R5F10369ASP, R5F10368ASP, R5F10367ASP, R5F10366ASP R5F1026ADSP, R5F10269DSP, R5F10268DSP, R5F10267DSP, R5F10266DSP R5F1036ADSP, R5F10369DSP, R5F10368DSP, R5F10367DSP, R5F10366DSP R5F1026AGSP, R5F10269GSP, R5F10268GSP, R5F10267GSP, R5F10266GSP R5F1036AGSP, R5F10369GSP, R5F10368GSP, R5F10367GSP, R5F10366GSP

<R> <R>

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LSSOP20-4.4x6.5-0.65	PLSP0020JB-A	P20MA-65-NAA-1	0.1

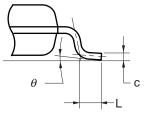


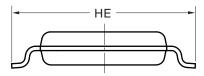


1.Dimensions "%1" and "%2" do not include mold flash.

2.Dimension "3" does not include trim offset.

detail of lead end





	(UNIT:mm)
ITEM	DIMENSIONS
D	6.50±0.10
Е	4.40±0.10
HE	6.40±0.20
А	1.45 MAX.
A1	0.10±0.10
A2	1.15
е	0.65±0.12
bp	0.22 + 0.10 - 0.05
С	$0.15 \pm 0.05 \\ -0.02$
L	0.50±0.20
У	0.10
θ	0° to 10°

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## 5-10264450 R5F10260450 D

NOTE

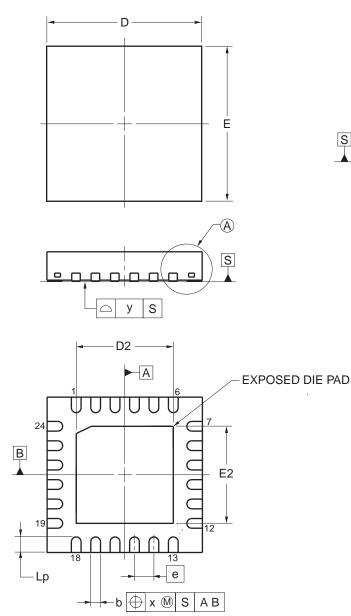


#### 4.2 24-pin products

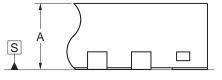
R5F1027AANA, R5F10279ANA, R5F10278ANA, R5F10277ANA R5F1037AANA, R5F10379ANA, R5F10378ANA, R5F10377ANA R5F1027ADNA, R5F10279DNA, R5F10278DNA, R5F10277DNA R5F1037ADNA, R5F10379DNA, R5F10378DNA, R5F10377DNA R5F1027AGNA, R5F10279GNA, R5F10278GNA, R5F10277GNA R5F1037AGNA, R5F10379GNA, R5F10378GNA, R5F10377GNA

<R> <R>

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-HWQFN24-4x4-0.50	PWQN0024KE-A	P24K8-50-CAB-1	0.04



DETAIL OF (A) PART



	(UNIT:mm)
ITEM	DIMENSIONS
D	$4.00 \pm 0.05$
Е	$4.00\pm\!0.05$
Α	0.75±0.05
b	0.25 + 0.05 - 0.07
е	0.50
Lp	$0.40\pm\!0.10$
х	0.05
У	0.05

ſ	ITEM		D2			E2		
			MIN	NOM	MAX	MIN	NOM	MAX
	EXPOSED DIE PAD VARIATIONS	A	2.45	2.50	2.55	2.45	2.50	2.55

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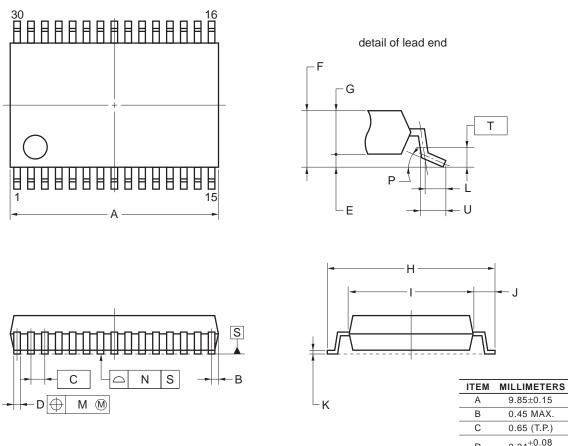


#### 4.3 30-pin products

R5F102AAASP, R5F102A9ASP, R5F102A8ASP, R5F102A7ASP R5F103AAASP, R5F103A9ASP, R5F103A8ASP, R5F103A7ASP R5F102AADSP, R5F102A9DSP, R5F102A8DSP, R5F102A7DSP R5F103AADSP, R5F103A9DSP, R5F103A8DSP, R5F103A7DSP R5F102AAGSP, R5F102A9GSP, R5F102A8GSP, R5F102A7GSP R5F103AAGSP, R5F103A9GSP, R5F103A8GSP, R5F103A7GSP

<R> <R>

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LSSOP30-0300-0.65	PLSP0030JB-B	S30MC-65-5A4-3	0.18



#### NOTE

Each lead centerline is located within 0.13 mm of its true position (T.P.) at maximum material condition.

С	0.65 (T.P.)
D	$0.24\substack{+0.08\\-0.07}$
Е	0.1±0.05
F	1.3±0.1
G	1.2
Н	8.1±0.2
Ι	6.1±0.2
J	1.0±0.2
К	0.17±0.03
L	0.5
М	0.13
Ν	0.10
Р	$3^{\circ}^{+5^{\circ}}_{-3^{\circ}}$
Т	0.25
U	0.6±0.15

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**Revision History** 

## RL78/G12 Data Sheet

			Description			
Rev.	Date	Page	Summary			
1.00	Dec 10, 2012	-	First Edition issued			
2.00	Sep 06, 2013	1	Modification of 1.1 Features			
		3	Modification of 1.2 List of Part Numbers			
		4	Modification of Table 1-1. List of Ordering Part Numbers, Note, and Caution			
		7 to 9	Modification of package name in 1.4.1 to 1.4.3			
		14	Modification of tables in 1.7 Outline of Functions			
		17	Modification of description of table in 2.1 Absolute Maximum Ratings (Ta = 25°C)			
		18	Modification of table, Note, and Caution in 2.2.1 X1 oscillator characteristics			
		18	Modification of table in 2.2.2 On-chip oscillator characteristics			
		19	Modification of Note 3 in 2.3.1 Pin characteristics (1/4)			
		20	Modification of Note 3 in 2.3.1 Pin characteristics (2/4)			
		23	Modification of Notes 1 and 2 in (1) 20-, 24-pin products (1/2)			
		24	Modification of Notes 1 and 3 in (1) 20-, 24-pin products (2/2)			
		25	Modification of Notes 1 and 2 in (2) 30-pin products (1/2)			
		26	Modification of Notes 1 and 3 in (2) 30-pin products (2/2)			
		27	Modification of (3) Peripheral functions (Common to all products)			
		28	Modification of table in 2.4 AC Characteristics			
		29	Addition of Minimum Instruction Execution Time during Main System Clock Operation			
		30	Modification of figures of AC Timing Test Point and External Main System Clock Timing			
		31	Modification of figure of AC Timing Test Point			
		31	Modification of description and Note 2 in (1) During communication at same			
			potential (UART mode)			
		32	Modification of description in (2) During communication at same potential (CSI mode)			
		33	Modification of description in (3) During communication at same potential (CSI mode)			
		34	Modification of description in (4) During communication at same potential (CSI mode)			
		36	Modification of table and Note 2 in (5) During communication at same potential			
			(simplified I <sup>2</sup> C mode)			
		38, 39	Modification of table and Notes 1 to 9 in (6) Communication at different potential			
		,	(1.8 V, 2.5 V, 3 V) (UART mode)			
		40	Modification of Remarks 1 to 3 in (6) Communication at different potential (1.8 V,			
			2.5 V, 3 V) (UART mode)			
		41	Modification of table in (7) Communication at different potential (2.5 V, 3 V) (CSI mode)			
		42	Modification of Caution in (7) Communication at different potential (2.5 V, 3 V) (CSI mode)			
		43	Modification of table in (8) Communication at different potential (1.8 V, 2.5 V, 3 V)			
		10	(CSI mode) (1/3)			
		44	Modification of table and Notes 1 and 2 in (8) Communication at different potential			
			(1.8 V, 2.5 V, 3 V) (CSI mode) (2/3)			
		45	Modification of table, Note 1, and Caution 1 in (8) Communication at different			
		45	potential (1.8 V, 2.5 V, 3 V) (CSI mode) (3/3)			
		47	Modification of table in (9) Communication at different potential (1.8 V, 2.5 V, 3 V)			
		47	(CSI mode)			
		50	Modification of table, Note 1, and Caution 1 in (10) Communication at different			
		50	potential (1.8 V, 2.5 V, 3 V) (simplified I <sup>2</sup> C mode)			
		E0	Modification of Remark in 2.5.2 Serial interface IICA			
		52				
		53	Addition of table to 2.6.1 A/D converter characteristics			
		53	Modification of description in <b>2.6.1 (1)</b>			
		54	Modification of Notes 3 to 5 in 2.6.1 (1)			
		54	Modification of description and Notes 2 to 4 in 2.6.1 (2)			

		Description		
Rev.	Date	Page	Summary	
2.00	Sep 06, 2013	55	Modification of description and Notes 3 and 4 in 2.6.1 (3)	
		56	Modification of description and Notes 3 and 4 in 2.6.1 (4)	
		57	Modification of table in 2.6.2 Temperature sensor/internal reference voltage characteristics	
		57	Modification of table and Note in 2.6.3 POR circuit characteristics	
		58	Modification of table in 2.6.4 LVD circuit characteristics	
		59	Modification of table of LVD detection voltage of interrupt & reset mode	
		59	Modification of number and title to 2.6.5 Power supply voltage rising slope characteristics	
		61	Modification of table, figure, and Remark in 2.10 Timing of Entry to Flash Memory	
			Programming Modes	
		62 to 103	Addition of products of industrial applications (G: TA = -40 to +105°C)	
		104 to 106	Addition of products of industrial applications (G: TA = -40 to +105°C)	

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#### NOTES FOR CMOS DEVICES

- (1) VOLTAGE APPLICATION WAVEFORM AT INPUT PIN: Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between VIL (MAX) and VIH (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between VIL (MAX) and VIH (MIN).
- (2) HANDLING OF UNUSED INPUT PINS: Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.
- (3) PRECAUTION AGAINST ESD: A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.
- (4) STATUS BEFORE INITIALIZATION: Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.
- (5) POWER ON/OFF SEQUENCE: In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current. The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.
- (6) INPUT OF SIGNAL DURING POWER OFF STATE : Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

#### Notice

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